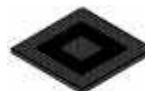




MPC5676R



TEPBGA-416
27 mm x 27 mm



TEPBGA-516
27mm x 27mm

MPC5676R Microcontroller Data Sheet

On-chip modules available within the family include the following features:

- Two identical dual issue,32-bit CPU core complexes (e200z7), each with
 - Power Architecture embedded specification compliance
 - Instruction set enhancement allowing variable length encoding (VLE), optional encoding of mixed 16-bit and 32-bit instructions, for code size footprint reduction
 - Signal processing extension (SPE) instruction support for digital signal processing (DSP)
 - Single-precision floating point operations (FPU)
 - 16 KB I-Cache and 16 KB D-Cache
 - Hardware cache coherency between cores
- 16 Hardware semaphores
- 3 channel CRC module
- 6MB on-chip flash
 - Supports read during program and erase operations, and multiple blocks allowing EEPROM emulation
- 384KB on-chip general-purpose SRAM including 48KB of standby RAM
- Two multi-channel directmemory access controllers (eDMA)
 - 64 channels per eDMA
- Dual core Interrupt controller (INTC)
- Phase-locked loop with FM modulation (FMPLL)
- Crossbar switch architecture for concurrent access to peripherals, flash, or RAM from multiple bus masters
- External Bus Interface (EBI) for calibration and application development
- System integration unit (SIU) with error correction status module (ECSM)
- Four protected port output pins (PPO)
- Boot assist module (BAM) supports serial bootload via CAN or SCI
- Three second-generation enhanced time processor units (eTPU2)

- Up to 96 eTPU2 channels (32 channels per eTPU2)
- total of 36 KB code RAM
- total of 9 KB parameter RAM
- Enhanced modular input output system supporting 32 unified channels (eMIOS) with each channel capable of single action, double action, pulse width modulation (PWM) and modulus counter operation
- Two enhanced queued analog-to-digital converter (eQADC) modules with
 - two separate analog converters per eQADC module
 - support for a total of 64 analog input pins, expandable to 176 inputs with off-chip multiplexers
 - one absolute reference ADC channel
 - interface to twelve hardware decimation filters
 - enhanced ‘Tap’ command to route any conversion to two separate decimation filters
 - Temperature sensor
- Five deserial serial peripheral interface (DSPI) modules
- Three enhanced serial communication interface (eSCI) modules
- Four controller area network (FlexCAN) modules
- Dual-channel FlexRay controller
- Nexus development interface (NDI) per IEEE-ISTO 5001-2003 standard, with some support for 2010 standard.
- Device and board test support per Joint Test Action Group (JTAG) (IEEE 1149.1)
- On-chip voltage regulator controller regulates supply voltage down to 1.2 V for core logic
- Self Test capability

This document contains information on a product under development. Freescale reserves the right to change or discontinue this product without notice.

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Preliminary—Subject to Change Without Notice

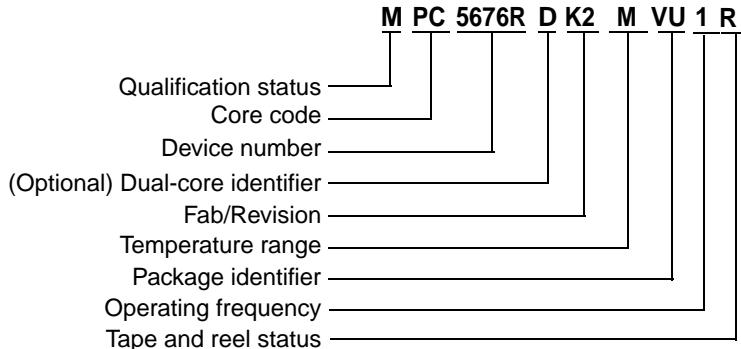
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1 Ordering Information

1.1 Orderable Parts

Figure 1 and Table 1 describe and list the orderable part numbers for the MPC5676R.



Temperature Range
M = -40 °C to 125 °C

Package Identifier
VU = 416 TEPBGA
Pb-Free
VY = 516 TEPBGA
Pb-Free

Operating Frequency
1 = 2 x 180 MHz

Tape and Reel Status
R = Tape and reel
(blank) = Trays

Qualification Status

P = Pre qualification

M = Fully spec. qualified, general market flow

S = Fully spec. qualified, automotive flow

Note: Not all options are available on all devices. Refer to Table 1.

Figure 1. MPC5676R Orderable Part Number Description

Table 1. Orderable Part Numbers

Freescale Part Number ¹	Package Description	Speed (MHz) ²		Operating Temperature ³	
		Nominal	Max ⁴ (f _{MAX})	Min (T _L)	Max (T _H)
SPC5676RDK2MVU1R	MPC5676R 416 package Lead-free (Pb-free)	180	184	-40 °C	125 °C
SPC5676RDK2MVY1R	MPC5676R 516 package Lead-free (Pb-free)	180	184	-40 °C	125 °C

¹ All packaged devices are PPC5676R, rather than MPC5676R or SPC5676R, until product qualifications are complete. The unpackaged device prefix is PCC, rather than SCC, until product qualification is complete.
Not all configurations are available in the PPC parts.

² For the operating mode frequency of various blocks on the device, see Table 27.

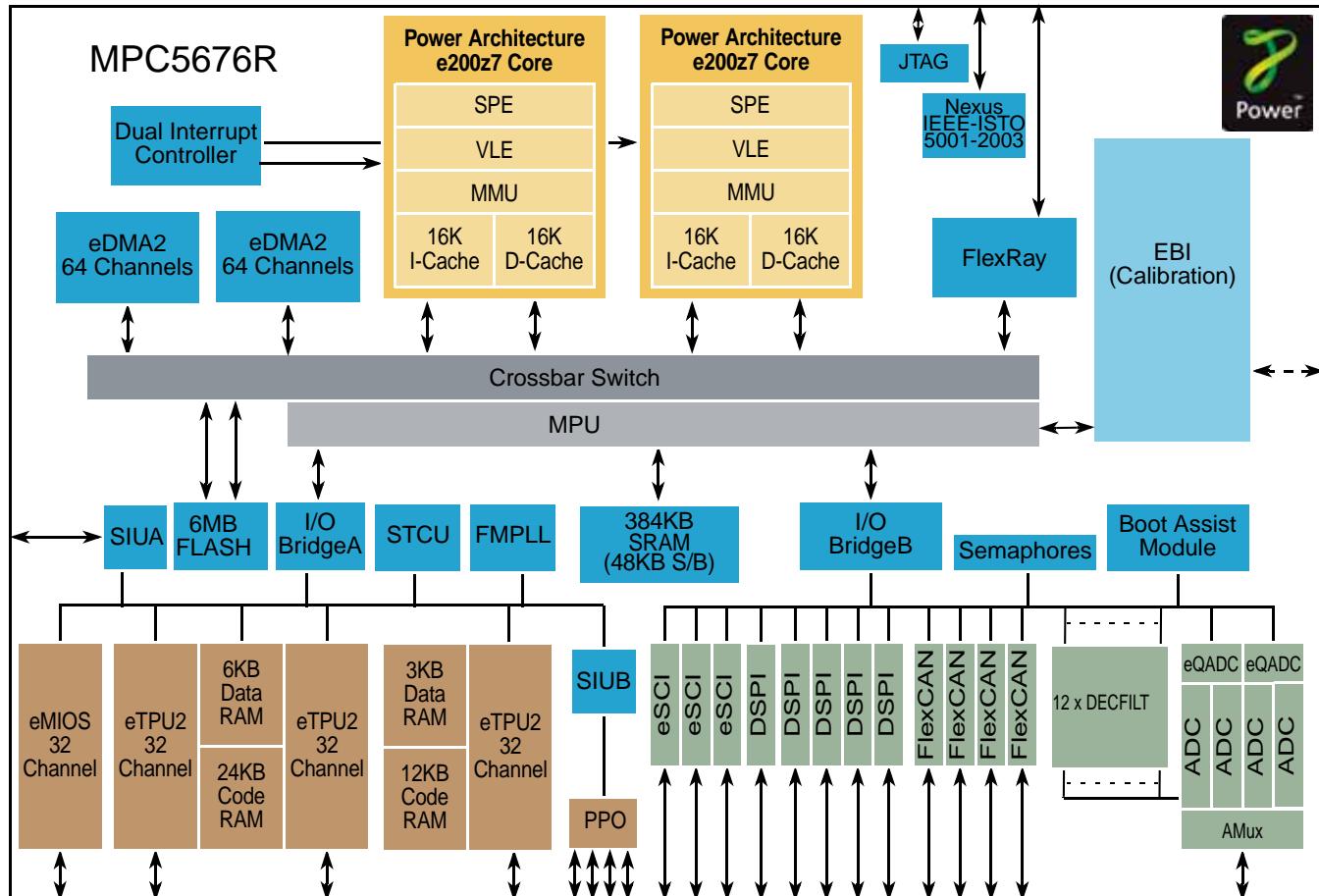
³ The lowest ambient operating temperature is referenced by T_L; the highest ambient operating temperature is referenced by T_H.

⁴ Speed is the nominal maximum frequency. Max speed is the maximum speed allowed including frequency modulation (FM). 180 MHz parts allow for 180 MHz system clock + 2% FM.

2 MPC5676R Blocks

2.1 Block Diagram

The following figure shows a top-level block diagram of the MPC5676R. The purpose of the block diagram is to show the general interconnection of functional modules through the crossbar switch and from the Dual Interrupt Controller, and provide an indication of the modules that connect to external pins. For clarity, the following modules are omitted from the diagram: PMU, SWT, STM, PIT, ECSV, DTS, and CRC.



LEGEND

ADC	- Analog to Digital Converter
AMux	- Analog Pin Multiplexer
D-Cache	- Data Cache
DECFLIT	- Decimation Filter
DSPI	- Deserial/Serial Peripheral Interface
EBI	- External Bus Interface
eDMA2	- Enhanced Direct Memory Access controller version 2
eMIOS	- Enhanced Modular I/O System
eQADC	- Enhanced Queued Analog to Digital Converter
eSCI	- Enhanced Serial Communications Interface
eTPU2	- Enhanced Time Processing Unit version 2
FlexCAN	- Flexible Controller Area Network controller
FMPLL	- Frequency Modulated Phase Lock Loop clock generator
I-Cache	- Instruction Cache
IRC	- Internal RC Oscillator
JTAG	- Joint Test Action Group controller
MMU	- Memory Management Unit
MPU	- Memory Protection Unit
PPO	- Protected Port Output
S/B	- Stand-by
SIUA	- System Integration Unit A
SIUB	- System Integration Unit B
SPE	- Signal Processing Engine
SRAM	- Static RAM
STCU	- Self Test Control Unit
VLE	- Variable Length instruction Encoding

Figure 2. MPC5676R Block Diagram

3 Pin Assignments

3.1 416-ball TEPBGA Pin Assignments

Figure 3 shows the 416-ball TEPBGA pin assignments.

CAUTION

This ball map is preliminary and subject to change. Do not use it for board design.

	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	21	22	23	24	25	26											
A	VSS	VDD	RSTOUT	ANA0	ANA4	ANA8	ANA11	ANA15	VDDA_A0	REF-BYPC1	VRL_A	VRH_A	AN28	AN32	AN36	VDDA_B0	REF-BYPC1	VRL_B	VRH_B	ANB7	ANB11	ANB14	ANB17	ANB21	ANB23	VSS	A										
B	VDDEH1	VSS	VDD	TEST	ANA1	ANA5	ANA10	ANA14	VDDA_A1	VSSA_A1	REF-BYPC1	AN24	AN27	AN29	AN33	VDDA_B1	VSSA_B0	REF-BYPC1	ANB6	ANB8	ANB10	ANB15	ANB18	ANB22	VSS	TCRCLK_B											
C	ETPUA30	ETPUA31	VSS	VDD	ANA2	ANA6	ANA9	ANA13	ANA17	ANA19	ANA21	ANA23	AN26	AN30	AN34	AN37	AN38	ANB0	ANB4	ANB5	ANB12	ANB16	ANB19	VSS	ETPUC0	ETPUC1_C											
D	ETPUA27	ETPUA28	ETPUA29	VSS	VDD	ANA3	ANA7	ANA12	ANA16	ANA18	ANA20	ANA22	AN25	AN31	AN35	AN39	ANB1	ANB2	ANB3	ANB9	ANB13	ANB20	VSS	VDDEH7	ETPUC2	ETPUC3_D											
E	ETPUA23	ETPUA24	ETPUA25	ETPUA26																						VDDEH7	ETPUC4	ETPUC5	ETPUC6_E								
F	ETPUA19	ETPUA20	ETPUA21	ETPUA22																						ETPUC7	ETPUC8	ETPUC9	ETPUC10_F								
G	ETPUA15	ETPUA16	ETPUA17	ETPUA18																						ETPUC11	ETPUC12	ETPUC13	ETPUC14_G								
H	ETPUA11	ETPUA12	ETPUA14	ETPUA13																						ETPUC15	ETPUC16	ETPUC17	ETPUC18_H								
J	ETPUA7	ETPUA8	ETPUA9	ETPUA10																						ETPUC19	ETPUC20	ETPUC21	ETPUC22_J								
K	ETPUA3	ETPUA4	ETPUA5	ETPUA6						VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS							
L	TCRCLK_A	ETPUA0	ETPUA1	ETPUA2						VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS						
M	VDD33_1	TXDA	RXDA	VSTBY						VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS						
N	RXDB	BOOT-CFG1	WKPCFG	VDD						VDDE2	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS						
P	TXDB	PLLCFG1	PLLCFG2	VDDEH1						VDDE2	VDDE2	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS						
R	JCOMP	RESET	PLLCFG0	RDY						VDDE2	VDDE2	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS						
T	VDDE2	MCK0	MSE01	EVTI						VDDE2	VDDE2	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS					
U	EVTO	MSE00	MDO0	MDO1						VDDE2	VDDE2	VDDE2	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS					
V	MDO2	MDO3	MDO4	MDO5						VDDE2	VDDE2	VDDE2	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS					
W	MDO6	MDO7	MDO8	VDDE2						REGSEL	ETPUB25	ETPUB24	ETPUB23_W																								
Y	MDO9	MDO10	MDO11	MDO15						ETPUB29	ETPUB28	ETPUB27	REGCTL_Y																								
AA	MDO12	MDO13	MDO14	VDD33_2						VDD33_3	ETPUB30	VDDREG	VSSSYN_AA																								
AB	TDO	TCK	TMS	VDD						VDD	ETPUB31	VSSFL	EXTAL_AB																								
AC	VDDE2	TDI	VDD	VSS	VDDE2	PCSA1	PCSA2	PCSB4	PCSB1	VDDEH3	VDDEH4	VDD	EMIOS8	EMIOS14	EMIOS18	EMIOS22	EMIOS27	EMIOS31	CNRXB	CNRXD	VDDEH5	PCSC1	VSS	VDD	VDDEH6	XTAL_AC											
AD	ENGCLK	VDD	VSS	FR_A-TX	FR_B-TX	PCSA5	SOUTA	SCKA	PCSB0	PCSB3	EMIOS2	EMIOS3	EMIOS9	EMIOS15	EMIOS19	EMIOS23	EMIOS26	EMIOS30	CNTXB	SCKC	RXDC	PCSC3	VSS	VDD	VDDSYN	AD											
AE	VDD	VSS	FR_A-RX	FR_B-RX	PCSA4	PCSA0	PCSA3	SCKB	SINB	EMIOS0	EMIOS3	EMIOS6	EMIOS10	EMIOS13	EMIOS17	EMIOS21	EMIOS25	EMIOS29	CNRXA	CNRXC	PCSC0	SINC	PCSC2	PCSC5	VSS	VDD	AE										
AF	VSS	VDDE2	FR_A-TX_EN	FR_B-TX_EN	VDDEH3	PCSB5	SINA	PCSB2	SOUTB	EMIOS1	EMIOS4	EMIOS7	EMIOS11	EMIOS12	EMIOS16	EMIOS20	EMIOS24	EMIOS28	CNTXA	CNTXC	SOUTC	VDDEH4	TXDC	PCSC4	VDDEH5	VSS	AF										
	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	21	22	23	24	25	26											

Figure 3. MPC5676R 416-ball TEPBGA (full diagram)

Pin Assignments

3.2 516-ball TEPBGA Pin Assignments

Figure 4 shows the 516-ball TEPBGA pin assignments.

	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	21	22	23	24	25	26		
A	VDD	RSTOUT	ANA0	ANA4	ANA9	ANA11	ANA15	VDDA_A0	REF-BYPC1	VRL_A	VRH_LA	AN28	AN29	AN36	VDDA_B0	REF-BYPC1	VRL_B	VRH_B	ANB5	ANB9	ANB12	ANB18	ANB21	VSS		A		
B	VDDEH1	VSS	VDD	TEST	ANA1	ANA5	ANA10	ANA14	VDDA_A1	VSSA_A1	REF-BYPC1	AN24	AN27	AN30	AN32	VDDA_B1	VSSA_B1	REF-BYPC1	ANB4	ANB8	ANB10	ANB13	ANB19	ANB22	VSS	VSS	B	
C	ETPUA30	ETPUA31	VSS	VDD	ANA2	ANA6	ANA7	ANA13	ANA17	ANA19	ANA21	ANA22	AN25	AN31	AN34	AN39	AN37	ANB6	ANB7	ANB8	ANB11	ANB15	ANB20	VSS	ETPUC0	ETPUC1	C	
D	ETPUA27	ETPUA28	ETPUA29	VSS	VDD	ANA3	ANA8	ANA12	ANA16	ANA18	ANA20	ANA23	AN26	AN33	AN35	AN38	ANB1	ANB2	ANB3	ANB4	ANB16	ANB17	VSS	VDDEH7	ETPUC2	ETPUC3	D	
E	ETPUA23	ETPUA24	ETPUA25	ETPUA26	VSS	VDD	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	E	
F	ETPUA19	ETPUA20	ETPUA21	ETPUA22	VSS	VDDE8		VDDE8		VDDE8	VDDE8		VSS	VSS		VDDE10	VDDE10		VDDE10		VDDE10	TCRCLKC	ETPUC7	ETPUC8	ETPUC9	ETPUC10	F	
G	ETPUA11	ETPUA13	ETPUA15	ETPUA17	ETPUA18																						G	
H	ETPUA5	ETPUA7	ETPUA8	ETPUA3	ETPUA4	ETPUA14	ETPUA16																					H
J	ETPUA1	ETPUA2	ETPUA9	ETPUA4	ETPUA12																							J
K	TXDB	TXDA	RXDA	TCRCLKA	ETPUA6	ETPUA10																						K
L	PLLCFG1	PLLCFG2	BOOT-CFG1	BOOT-CFG0	RXDB	ETPUA0																						L
M	VDD33_1	D_BDIP	PLLCFG0	VSTBY	WKPCFG																							M
N	D_WE0	D_WE2	D_WE3	VDD	RESET	VDDE8																						N
P	D_ADD9	D_ADD10	D_ADD11	VDDEH1	D_WE1	VDD33_1																						P
R	D_ADD12	D_ADD13	D_ADD14	D_ADD15	D_ADD16																							R
T	VDDE2	D_ADD18	D_ADD19	D_ADD20	D_ADD17	D_CS3																						T
U	D_CS2	JCOMP	RDY	MCK0	MSE01	MSE00																						U
V	EVTI	EVTO	MDO0	MDO2	MDO3																							V
W	MDO4	MDO5	MDO6	VDDE2	MDO8	MDO1																						W
Y	MDO7	MDO9	MDO10	MDO11	MDO12																							Y
AA	MDO13	MDO14	MDO15	VDD33_1	VDDE8	VSS			PCSA5		SOUTB	VDD33_4		VDDE9	VDD33_4		EMIOS23	EMIOS31		CNRXB		VSS	VDDE10	VDD33_3	ETPUB28	VDDREG	VSSYN	AA
AB	TDO	TCK	TMS	VDD	VSS	VDDE9	VDDE9	SCKA	SINB	D_CS1	D_ADD21	D_ADD28	EMIOS1	EMIOS11	EMIOS17	EMIOS19	EMIOS29	VDDE9	VDDE9	VDDE9	VSS	VDD	ETPUB30	VSSFL	EXTAL	AB		
AC	VDDE2	TDI	VDD	VSS	VDDE2	PCSA1	SOUTA	SCKB	PCSB3	VDDEH3	VDDEH4	VDD	EMIOS0	EMIOS8	EMIOS13	EMIOS22	EMIOS24	EMIOS28	CNTXB	CNRXD	VDDEH5	PCSC1	VSS	VDD	VDDEH6	XTAL	AC	
AD	ENGCLK	VDD	VSS	FR_A_TX	FR_B_TX	PCSA0	PCSA3	PCSB2	D_CS0	D_ADD22	D_ADD25	D_ADD28	EMIOS2	EMIOS7	EMIOS12	EMIOS16	EMIOS18	EMIOS27	CNRXA	CNTXD	SCKC	RXDC	PCSC3	VSS	VDD	VDDSYN	AD	
AE	VDD	VSS	FR_A_RX	FR_B_RX	PCSA4	PCSB5	SINA	PCSB1	D_TS	D_ADD23	D_ADD26	D_ADD30	EMIOS3	EMIOS6	EMIOS10	EMIOS15	EMIOS21	EMIOS26	CNTXA	CNRXC	PCSC0	SINC	PCSC2	PCSC5	VSS	VDD	AE	
AF	VDDE2	FR_A_TX_EN	FR_B_TX_EN	VDDEH3	PCSA2	PCSB4	PCSB0	D_TA	D_ADD24	D_ADD27	D_CLKOUT	EMIOS4	EMIOS5	EMIOS9	EMIOS20	EMIOS14	EMIOS25	EMIOS30	CNTXC	SOUTC	VDDEH4	TXDC	PCSC4	VDDEH5			AF	
	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	21	22	23	24	25	26		

Figure 4. MPC5676R 516-ball TEPBGA (full diagram)

3.3 Pin Muxing and Reset States

See [Appendix A, Signal Properties and Muxing](#), for a listing and description of the pin functions and properties.

4 Electrical Characteristics

This section contains detailed information on power considerations, DC/AC electrical characteristics, and AC timing specifications for the MPC5676R.

The electrical specifications are preliminary and are from previous designs, design simulations, or initial evaluation. These specifications may not be fully tested or guaranteed at this early stage of the product life cycle, however for production silicon these specifications will be met. Finalized specifications will be published after complete characterization and device qualifications have been completed.

4.1 Maximum Ratings

Table 2. Absolute Maximum Ratings¹

Spec	Characteristic	Symbol	Min	Max ²	Unit
1	1.2 V Core Supply Voltage ³	V _{DD}	-0.3	1.65 ⁴	V
2	SRAM Standby Voltage	V _{STBY}	-0.3	5.5 ^{5,6}	V
3	Clock Synthesizer Voltage	V _{DDSYN}	-0.3	4.5 ^{6,7}	V
4	I/O Supply Voltage (I/O buffers and predrivers)	V _{DD33}	-0.3	4.5 ^{6,7}	V
5	Analog Supply Voltage (reference to V _{SSA} ⁸)	V _{DDA} ⁹	-0.3	5.5 ^{5,6}	V
6	I/O Supply Voltage (fast I/O pads)	V _{DDE}	-0.3	4.5 ⁶	V
7	I/O Supply Voltage (medium I/O pads)	V _{DDEH}	-0.3	5.5 ^{5,6}	V
8	Voltage Regulator Input Supply Voltage	V _{DDREG}	-0.3	5.5 ^{5,6}	V
9	Analog Reference High Voltage (reference to V _{RL} ¹⁰)	V _{RH} ¹¹	-0.3	5.5 ^{5,6}	V
10	V _{SS} to V _{SSA} ⁸ Differential Voltage	V _{SS} - V _{SSA}	-0.1	0.1	V
11	V _{REF} Differential Voltage	V _{RH} - V _{RL}	-0.3	5.5 ^{5,6}	V
12	V _{RL} to V _{SSA} Differential Voltage	V _{RL} - V _{SSA}	-0.3	0.3	V
13	V _{DD33} to V _{DDSYN} Differential Voltage	V _{DD33} - V _{DDSYN}	-0.1	0.1	V
14	V _{SSSYN} to V _{SS} Differential Voltage	V _{SSSYN} - V _{SS}	-0.1	0.1	V
15	Maximum Digital Input Current ¹² (per pin, applies to all digital pins)	I _{MAXD}	-3 ¹³	3 ¹³	mA
16	Maximum Analog Input Current ¹⁴ (per pin, applies to all analog pins)	I _{MAXA}	-3 ^{9,13}	3 ^{9,13}	mA

Electrical Characteristics

Table 2. Absolute Maximum Ratings¹ (continued)

Spec	Characteristic	Symbol	Min	Max ²	Unit
17	Maximum Operating Temperature Range ¹⁵ – Die Junction Temperature	T _J	-40.0	150.0	°C
18	Storage Temperature Range	T _{stg}	-55.0	150.0	°C
19	Maximum Solder Temperature ¹⁶ Pb-free package SnPb package	T _{sdr}	— —	260.0 245.0	°C
20	Moisture Sensitivity Level ¹⁷	MSL	—	3	—

¹ Functional operating conditions are given in the DC electrical specifications. Absolute maximum ratings are stress ratings only, and functional operation at the maxima is not guaranteed. Stress beyond the listed maxima may affect device reliability or cause permanent damage to the device.

² Absolute maximum voltages are currently maximum burn-in voltages. Absolute maximum specifications for device stress have not yet been determined.

³ 1.2 V ±10% for proper operation. This parameter is specified at a maximum junction temperature of 150 °C.

⁴ 2.0 V for 10 hours cumulative time, 1.2 V +10% for time remaining.

⁵ 6.4 V for 10 hours cumulative time, 5.0 V +10% for time remaining.

⁶ Voltage overshoots during a high-to-low or low-to-high transition must not exceed 10 seconds per instance.

⁷ 4.5 V for 10 hours cumulative time, 3.3 V +10% for time remaining.

⁸ MPC5676R has two analog power supply pins on the pinout: VDDA_A and VDDA_B.

⁹ MPC5676R has two analog ground supply pins on the pinout: VSSA_A and VSSA_B.

¹⁰ MPC5676R has two analog low reference voltage pins on the pinout: VRL_A and VRL_B.

¹¹ MPC5676R has two analog high reference voltage pins on the pinout: VRH_A and VRH_B.

¹² Total injection current for all pins must not exceed 25 mA at maximum operating voltage.

¹³ Injection current of ±5 mA allowed for limited duration for analog (ADC) pads and digital 5 V pads. The maximum accumulated time at this current shall be 60 hours. This includes an assumption of a 5.25 V maximum analog or V_{DDEH} supply when under this stress condition.

¹⁴ Total injection current for all analog input pins must not exceed 15 mA.

¹⁵ Lifetime operation at these specification limits is not guaranteed.

¹⁶ Solder profile per CDF-AEC-Q100.

¹⁷ Moisture sensitivity per JEDEC test method A112.

4.2 Thermal Characteristics

Table 3. Thermal Characteristics, 416-pin TEPBGA Package¹

Characteristic	Symbol	Value	Unit
Junction to Ambient ^{2,3} Natural Convection (Single layer board)	R _{θJA}	24	°C/W
Junction to Ambient ^{2,4} Natural Convection (Four layer board 2s2p)	R _{θJA}	16	°C/W
Junction to Ambient (@200 ft./min., Single layer board)	R _{θJMA}	18	°C/W

Table 3. Thermal Characteristics, 416-pin TEPBGA Package¹ (continued)

Characteristic	Symbol	Value	Unit
Junction to Ambient (@200 ft./min., Four layer board 2s2p)	$R_{\theta JMA}$	13	°C/W
Junction to Board ⁵	$R_{\theta JB}$	8	°C/W
Junction to Case ⁶	$R_{\theta JC}$	4	°C/W
Junction to Package Top ⁷ Natural Convection	Ψ_{JT}	3	°C/W

¹ Thermal characteristics are targets based on simulation that are subject to change per device characterization.

² Junction temperature is a function of on-chip power dissipation, package thermal resistance, mounting site (board) temperature, ambient temperature, air flow, power dissipation of other components on the board, and board thermal resistance.

³ Per JEDEC JESD51-2 with the single layer board horizontal. Board meets JESD51-9 specification.

⁴ Per JEDEC JESD51-6 with the board horizontal.

⁵ Thermal resistance between the die and the printed circuit board per JEDEC JESD51-8. Board temperature is measured on the top surface of the board near the package.

⁶ Indicates the average thermal resistance between the die and the case top surface as measured by the cold plate method (MIL SPEC-883 Method 1012.1) with the cold plate temperature used for the case temperature.

⁷ Thermal characterization parameter indicating the temperature difference between package top and the junction temperature per JEDEC JESD51-2.

Table 4. Thermal Characteristics, 516-pin TEPBGA Package¹

Characteristic	Symbol	Value	Unit
Junction to Ambient ^{2,3} Natural Convection (Single layer board)	$R_{\theta JA}$	24	°C/W
Junction to Ambient ^{2,4} Natural Convection (Four layer board 2s2p)	$R_{\theta JA}$	17	°C/W
Junction to Ambient (@200 ft./min., Single layer board)	$R_{\theta JMA}$	19	°C/W
Junction to Ambient (@200 ft./min., Four layer board 2s2p)	$R_{\theta JMA}$	14	°C/W
Junction to Board ⁵	$R_{\theta JB}$	9	°C/W
Junction to Case ⁶	$R_{\theta JC}$	5	°C/W
Junction to Package Top ⁷ Natural Convection	Ψ_{JT}	2	°C/W

¹ Thermal characteristics are targets based on simulation that are subject to change per device characterization.

² Junction temperature is a function of on-chip power dissipation, package thermal resistance, mounting site (board) temperature, ambient temperature, air flow, power dissipation of other components on the board, and board thermal resistance.

³ Per JEDEC JESD51-2 with the single layer board horizontal. Board meets JESD51-9 specification.

⁴ Per JEDEC JESD51-6 with the board horizontal.

⁵ Thermal resistance between the die and the printed circuit board per JEDEC JESD51-8. Board temperature is measured on the top surface of the board near the package.

⁶ Indicates the average thermal resistance between the die and the case top surface as measured by the cold plate method (MIL SPEC-883 Method 1012.1) with the cold plate temperature used for the case temperature.

Electrical Characteristics

- ⁷ Thermal characterization parameter indicating the temperature difference between package top and the junction temperature per JEDEC JESD51-2.

4.2.1 General Notes for Specifications at Maximum Junction Temperature

An estimation of the chip junction temperature, T_J , can be obtained from the equation:

$$T_J = T_A + (R_{\theta JA} * P_D) \quad Eqn. 1$$

where:

T_A = ambient temperature for the package ($^{\circ}\text{C}$)

$R_{\theta JA}$ = junction to ambient thermal resistance ($^{\circ}\text{C/W}$)

P_D = power dissipation in the package (W)

The junction to ambient thermal resistance is an industry standard value that provides a quick and easy estimation of thermal performance. Unfortunately, there are two values in common usage: the value determined on a single layer board and the value obtained on a board with two planes. For packages such as the TEPBGA, these values can be different by a factor of two. Which value is closer to the application depends on the power dissipated by other components on the board. The value obtained on a single layer board is appropriate for the tightly packed printed circuit board. The value obtained on the board with the internal planes is usually appropriate if the board has low power dissipation and the components are well separated.

When a heat sink is used, the thermal resistance is expressed as the sum of a junction to case thermal resistance and a case to ambient thermal resistance:

$$R_{\theta JA} = R_{\theta JC} + R_{\theta CA} \quad Eqn. 2$$

where:

$R_{\theta JA}$ = junction to ambient thermal resistance ($^{\circ}\text{C/W}$)

$R_{\theta JC}$ = junction to case thermal resistance ($^{\circ}\text{C/W}$)

$R_{\theta CA}$ = case to ambient thermal resistance ($^{\circ}\text{C/W}$)

$R_{\theta JC}$ is device related and cannot be influenced by the user. The user controls the thermal environment to change the case to ambient thermal resistance, $R_{\theta CA}$. For instance, the user can change the size of the heat sink, the air flow around the device, the interface material, the mounting arrangement on printed circuit board, or change the thermal dissipation on the printed circuit board surrounding the device.

To determine the junction temperature of the device in the application when heat sinks are not used, the Thermal Characterization Parameter (Ψ_{JT}) can be used to determine the junction temperature with a measurement of the temperature at the top center of the package case using the following equation:

$$T_J = T_T + (\Psi_{JT} * P_D) \quad Eqn. 3$$

where:

T_T = thermocouple temperature on top of the package ($^{\circ}\text{C}$)

Ψ_{JT} = thermal characterization parameter ($^{\circ}\text{C/W}$)

P_D = power dissipation in the package (W)

The thermal characterization parameter is measured per JESD51-2 specification using a 40 gauge type T thermocouple epoxied to the top center of the package case. The thermocouple should be positioned so that the thermocouple junction rests on the package. A small amount of epoxy is placed over the thermocouple junction and over about 1 mm. of wire extending from the junction. The thermocouple wire is placed flat against the package case to avoid measurement errors caused by cooling effects of the thermocouple wire.

References:

Semiconductor Equipment and Materials International
3081 Zanker Road
San Jose, CA 95134
(408) 943-6900

MIL-SPEC and EIA/JESD (JEDEC) specifications are available from Global Engineering Documents at 800-854-7179 or 303-397-7956.

JEDEC specifications are available on the WEB at <http://www.jedec.org>.

- C.E. Triplett and B. Joiner, "An Experimental Characterization of a 272 PBGA Within an Automotive Engine Controller Module," Proceedings of SemiTherm, San Diego, 1998, pp. 47-54.
- G. Kromann, S. Shidore, and S. Addison, "Thermal Modeling of a PBGA for Air-Cooled Applications," Electronic Packaging and Production, pp. 53-58, March 1998.
- B. Joiner and V. Adams, "Measurement and Simulation of Junction to Board Thermal Resistance and Its Application in Thermal Modeling," Proceedings of SemiTherm, San Diego, 1999, pp. 212-220.

4.3 EMI (Electromagnetic Interference) Characteristics

To find application notes that provide guidance on designing your system to minimize interference from radiated emissions, go to www.freescale.com and perform a keyword search for "radiated emissions." The following tables list the values of the device's radiated emissions operating behaviors.

Table 5. EMC Radiated Emissions Operating Behaviors: 416 BGA

Symbol	Description	Conditions	f _{osc} f _{sys}	Frequency band (MHz)	Level (max.)	Unit	Notes
V _{RE_TEM}	Radiated emissions, electric field and magnetic field	V _{DD} = 1.2 V V _{DDE} = 3.3 V V _{DDEH} = 5 V T _A = 25 °C 416 BGA EBI off CLK off FM off	40 MHz crystal 180 MHz (f _{EBI_CAL} = 46 MHz)	0.15–50	26	dB μ V	1
				50–150	30		
				150–500	34		
				500–1000	30		
				IEC and SAE level	I ²	—	1, 3
V _{RE_TEM}	Radiated emissions, electric field and magnetic field	V _{DD} = 1.2 V V _{DDE} = 3.3 V V _{DDEH} = 5 V T _A = 25 °C 416 BGA EBI off CLK off FM on ⁴	40 MHz crystal 180 MHz (f _{EBI_CAL} = 46 MHz)	0.15–50	24	dB μ V	1
				50–150	25		
				150–500	25		
				500–1000	21		
				IEC and SAE level	K ⁵	—	1, 3

¹ Determined according to IEC Standard 61967-2, Measurement of Radiated Emissions—TEM Cell and Wideband TEM Cell Method, and SAE Standard J1752-3, Measurement of Radiated Emissions from Integrated Circuits—TEM/Wideband TEM (GTEM) Cell Method.

² I = 36 dB μ V

³ Specified according to Annex D of IEC Standard 61967-2, Measurement of Radiated Emissions—TEM Cell and Wideband TEM Cell Method, and Appendix D of SAE Standard J1752-3, Measurement of Radiated Emissions from Integrated Circuits—TEM/Wideband TEM (GTEM) Cell Method.

⁴ "FM on" = FM depth of ±2%

⁵ K = 30 dB μ V

4.4 ESD Characteristics

Table 6. ESD Ratings^{1,2}

Spec	Characteristic	Symbol	Value	Unit
1	ESD for Human Body Model (HBM)	V_{HBM}	2000	V
2	ESD for Charged Device Model (CDM)	V_{CDM}	750 (corners) 500 (other)	V

¹ All ESD testing is in conformity with CDF-AEC-Q100 Stress Test Qualification for Automotive Grade Integrated Circuits.

² A device will be defined as a failure if after exposure to ESD pulses the device no longer meets the device specification requirements. Complete DC parametric and functional testing shall be performed per applicable device specification at room temperature followed by hot temperature, unless specified otherwise in the device specification.

4.5 PMC/POR/LVI Electrical Specifications

Table 7. PMC Operating conditions

Spec	Name	Parameter	Condition	Min	Typ	Max	Unit
1	V_{DDREG}	Supply voltage VDDREG 5V nominal ¹	LDO5V / SMPS5V mode	4.5	5	5.5	V
2	V_{DDREG}	Supply voltage VDDREG 3V nominal ¹	LDO3V mode	3.0	3.3	3.6	V
3	V_{DD33}	Supply voltage VDDSYN / V_{DD33} 3.3V nominal ²	LDO3V mode	3.0	3.3	3.6	V
4	V_{DD}	Supply voltage VDD 1.2V nominal ³	—	1.14	1.2	1.32	V

¹ Voltage should be higher than maximum V_{LVDREG} to avoid LVD event

² Applies to both V_{DD33} (flash supply) and VDDSYN (PLL supply) pads. Voltage should be higher than maximum V_{LVD33} to avoid LVD event

³ Voltage should be higher than maximum V_{LVD12} to avoid LVD event

NOTE

In the following table, “untrimmed” means “at reset” and “trimmed” means “after reset”.

Table 8. PMC Electrical Specifications

Spec	Name	Symbol	Condition	Min	Typ	Max	Unit
1	Nominal bandgap reference voltage	V_{BG}	—	—	0.620	—	V
1a	Bandgap reference voltage during power on reset	—	—	$V_{BG} - 5\%$	V_{BG}	$V_{BG} + 5\%$	V
1b	Bandgap reference voltage at nominal voltage / nominal temperature after power on reset	—	—	$V_{BG} - 2\%$	V_{BG}	$V_{BG} + 2\%$	V

Table 8. PMC Electrical Specifications

Spec	Name	Symbol	Condition	Min	Typ	Max	Unit
1c	Bandgap reference voltage / temperature dependence after power on reset	—	—	—	300	—	ppm/C
1d	Bandgap reference voltage / voltage dependence (V_{DDREG}) after power on reset	—	—	—	1500	—	
2	Nominal VRC regulated 1.2V output VDD ¹	$V_{DD12OUT}$	—	—	1.2	—	V
2a	VRC 1.2V output variation at reset (unloaded) ²	—	At POR	$V_{DD12OUT} - 8\%$	$V_{DD12OUT}$	$V_{DD12OUT} + 10\%$	
2b	VRC 1.2V output variation after reset(REGCTL load max. 20mA, VDD load max. 1A)	—	After POR	$V_{DD12OUT} - 5\%$	$V_{DD12OUT}$	$V_{DD12OUT} + 10\%$	
2c	Trimming step Vdd1p2	$V_{STEPV12}$	—	—	10	—	mV
3	POR rising VDD 1.2V	V_{PORC}	—	-	0.7	—	V
3a	POR VDD 1.2V variation	—	—	$V_{PORC} - 30\%$	V_{PORC}	$V_{PORC} + 30\%$	
3b	POR 1.2V hysteresis	—	—	—	75	—	mV
4	Nominal rising LVD 1.2V ³	V_{LVD12}	—	—	1.100	—	V
4a	LVD 1.2V variation before band gap trim ⁴	—	At POR	$V_{LVD12} - 6\%$	V_{LVD12}	$V_{LVD12} + 6\%$	
4b	LVD 1.2V variation after band gap trim ⁴	—	After POR	$V_{LVD12} - 3\%$	V_{LVD12}	$V_{LVD12} + 3\%$	
4c	LVD 1.2V Hysteresis	—	—	15	20	25	mV
4d	Trimming step LVD 1.2V	$V_{LVDSTEP12}$	—	—	10	—	mV
5	VRC 1.2V max DC output current	I_{REGCTL}	—	—	—	20	mA
6	Voltage regulator 1.2V current consumption VDDREG	—	—	—	3	—	mA
7	Nominal Vreg 3.3V output ⁵	$V_{DD33OUT}$	—	—	3.3	—	V
7a	Vreg 3.3V output variation at reset (unloaded) ⁶	—	At POR	$V_{DD33OUT} - 6\%$	$V_{DD33OUT}$	$V_{DD33OUT} + 10\%$	
7b	Vreg 3.3V output variation after reset (max. load 60mA)	—	After POR	$V_{DD33OUT} - 5\%$	$V_{DD33OUT}$	$V_{DD33OUT} + 10\%$	
7c	Trimming step VDDSYN	$V_{STEPV33}$	—	—	30	—	mV
8	Nominal rising LVD 3.3V ⁷	V_{LVD33}	—	—	2.950	—	V
8a	LVD 3.3V variation before band gap trim ⁶	—	At POR	$V_{LVD33} - 5\%$	V_{LVD33}	$V_{LVD33} + 5\%$	
8b	LVD 3.3V variation after bad gap trim ⁶	—	After POR	$V_{LVD33} - 3\%$	V_{LVD33}	$V_{LVD33} + 3\%$	

Electrical Characteristics

Table 8. PMC Electrical Specifications

Spec	Name	Symbol	Condition	Min	Typ	Max	Unit
8c	LVD 3.3V Hysteresis	—	—	—	30	—	mV
8d	Trimming step LVD 3.3V	$V_{LVDSTEP33}$	—	—	30	—	mV
9	Vreg 3.3V minimum peak DC output current supplied by regulator without causing V_{LVD33}^8	I_{DD33}	—	60	—	—	mA
10	Voltage regulator 3.3V current consumption VDDREG ⁹	—	—	—	2	—	mA
11	POR rising on VDDREG	V_{PORREG}	—	—	2.00	—	V
11a	POR VDDREG variation	—	—	$V_{PORREG} - 30\%$	V_{PORREG}	$V_{PORREG} + 30\%$	
11b	POR VDDREG hysteresis	—	—	—	250	—	mV
12	Nominal rising LVD VDDREG	V_{LVDREG}	LDO3V / LDO5V mode	—	2.950	—	V
12a	LVD VDDREG variation at reset ¹⁰	—	At POR	$V_{LVDREG} - 5\%$	V_{LVDREG}	$V_{LVDREG} + 5\%$	
12b	LVD VDDREG variation after reset ¹⁰	—	After POR	$V_{LVDREG} - 3\%$	V_{LVDREG}	$V_{LVDREG} + 3\%$	
12c	LVD VDDREG Hysteresis	—	LDO3V / LDO5V mode	—	30	—	mV
12d	Trimming step LVD VDDREG	$V_{LVDSTEPREG}$	LDO3V / LDO5V mode	—	30	—	mV
13	Nominal rising LVD VDDREG	V_{LVDREG}	SMPS5V mode	—	4.360	—	V
13a	LVD VDDREG variation at reset ¹⁰	—	At POR	$V_{LVDREG} - 5\%$	V_{LVDREG}	$V_{LVDREG} + 5\%$	
13b	LVD VDDREG variation after reset ¹⁰	—	After POR	$V_{LVDREG} - 3\%$	V_{LVDREG}	$V_{LVDREG} + 3\%$	
14	SMPS regulator output resistance ¹¹	—	—	—	15	25	Ohm
15	SMPS regulator clock frequency	—	After POR	1.0	1.5	—	MHz
16	SMPS regulator overshoot at start-up ¹²	—	GBD/GBC ¹³	—	1.32	1.4	V
17	SMPS maximum output current, as required by SoC ¹⁴	—	—	—	1.0	—	A
18	Voltage variation on current step (20% to 80% of maximum current with 4 usec constant time) ¹⁴	—	GBD/GBC ¹³	—	—	0.1	V

- ¹ Nominal internal regulator output voltage is 1.27V
- ² Voltage should be higher than maximum VLVD12 to avoid LVD event
- ³ ~VDD12OUT *0.87
- ⁴ Rising VDD
- ⁵ Nominal internal regulator output voltage is 3.4V
- ⁶ Rising VDDSYN
- ⁷ ~VDD33OUT *0.872
- ⁸ VDDSYN
- ⁹ Except IDD33
- ¹⁰ Rising VDDREG
- ¹¹ Pull up to VDDREG when high, pull down to VSSREG when low.
- ¹² Depends on external device, can be as high as 1.6V for short time (<100 usec each start-up)
- ¹³ GBD — Guaranteed By Design; GBC — Guaranteed by Characterization
- ¹⁴ Proper external devices required

4.5.1 Regulator Example

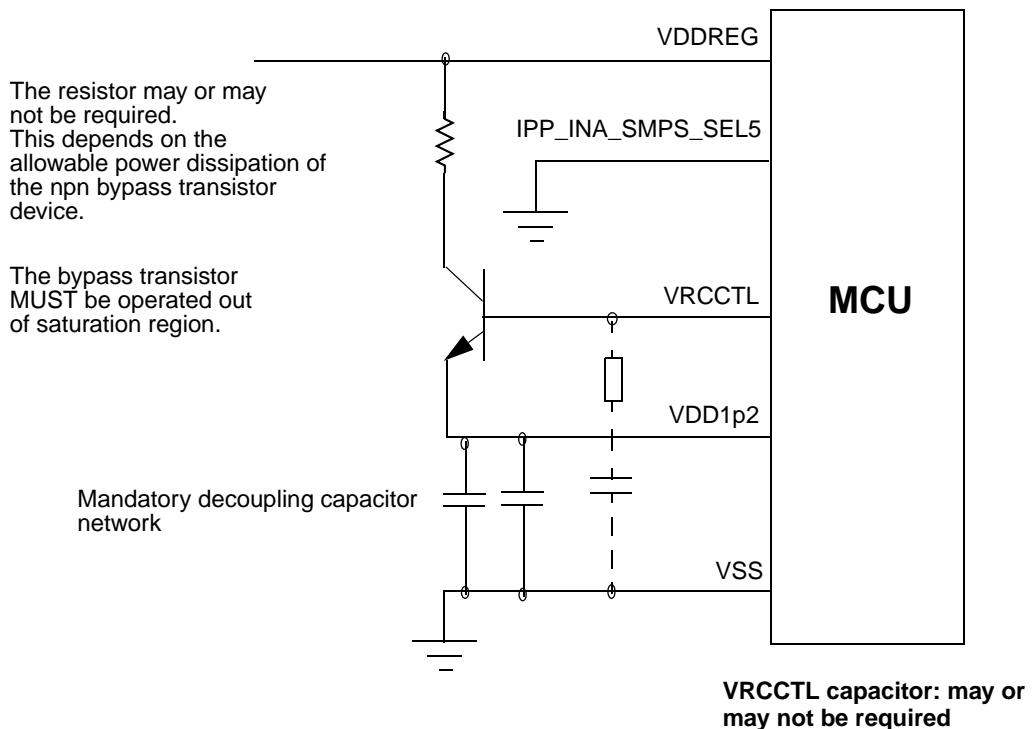


Figure 5. VRC 1.2 V LDO configuration with external bipolar

Electrical Characteristics

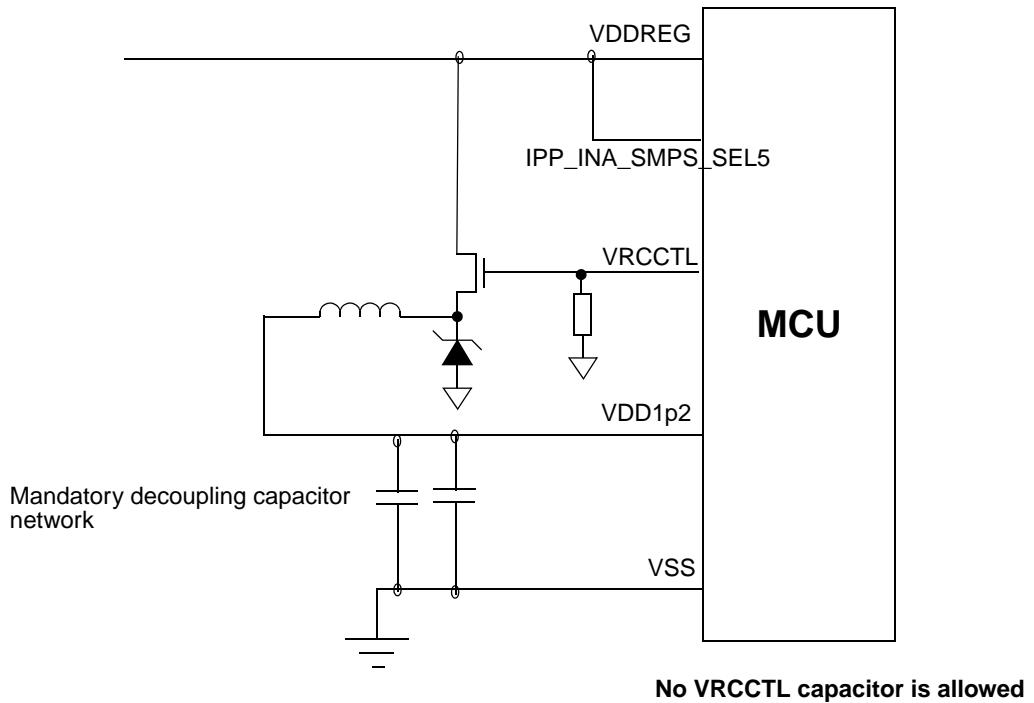


Figure 6. VRC 1.2V buck SMPS LDO configuration with external MOS - Schottky diode

Table 9. VRC LDO recommended external devices

Part Name	Part Type	Nominal	Description
NJD2873 Beta (Bf)	NPN		ON Semiconductor TM From 60 to 550
Vbe			From 0.4 V to 1.0 V
Vce	Capacitor	6 x 4.7uF - 20V	From 0.2 V to 0.6 V depends on package / power Ceramic low ESR—One for each VDD pin
	Capacitor	6 x 0.1uF - 20V	Ceramic —One capacitor for each VDD pin
	Capacitor	20uF	Supply decoupling cap (close to bipolar collector)
	Capacitor	2.2uF	Snubber cap, required with NJD2873 (on bipolar base)
	Resistor	12 Ohm	Optional ESR for snubber cap

Table 10. VRC SMPS recommended external devices

Part Name	Part Type	Nominal	Description
IR7353	HS nMOS + Schottky		Low threshold n-MOS/Low Vf Schottky diode
SS8P3L	Schottky		Low Vf Schottky diode
Vf			From 0.4V to 0.6V
SI3460 or equivalent	nMOS		Low threshold n-MOS
Vth			Less than 2V
Ids			More than 1.5A
Vds			More than 12V
Rdson			Less than 100 Ohms
Cg			Less than 5 nF
Turn on / off delay			Less than 50 ns
Rise time			Less than 90 ns
LQH66SN2R2M03	inductor	2.2 uH—3.2 A	muRata TM shielded coil, preferred $f_{max} > 40$ MHz
C3225X7R1E106M	capacitor	22 uF — 25V	TDK high capacitance ceramic SMD (on VDD close to coil)
C3225X7R1E225K	capacitor	2 to 6 x 2.2 uF — 25V	TDK ceramic SMD (on VDD close to MCU)
	capacitor	6 x 0.1 uF — 20V	Ceramic -One capacitor for each VDD pin
C3225X7R1E106M	capacitor	22 uF — 25 V	Supply decoupling cap—close to n-MOS drain
	resistor	20 K	Pull down for power n—MOS gate

4.6 Power Up/Down Sequencing

There is no power sequencing required among power sources during power up and power down in order to operate within specification as long as the following two rules are met:

- When VDDREG is tied to a nominal 3.3V supply, VDD33 and VDDSYN must be both shorted to VDDREG.
- When VDDREG is tied to a 5V supply, VDD33 and VDDSYN must be tied together and shall be powered by the internal 3.3V regulator.

The recommended power supply behavior is as follows: Use 25 V/millisecond or slower rise time for all supplies. Power up each V_{DDE}/V_{DDEH} first and then power up V_{DD} . For power down, drop V_{DD} to 0 V first, and then drop all V_{DDE}/V_{DDEH} supplies. There is no limit on the fall time for the power supplies.

Although there are no power up/down sequencing requirements to prevent issues like latch-up, excessive current spikes, etc., the state of the I/O pins during power up/down varies according to [Table 11](#) and [Table 12](#).

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Table 11. Power Sequence Pin States for MH and AE pads

VDD	VDD33	VDDE	MH Pad	MH+LVDS Pads ¹	AE/up-down Pads
High	High	High	Normal operation	Normal operation	Normal operation
—	Low	High	Pin is tri-stated (output buffer, input buffer, and weak pulls disabled)	Outputs driven high	Pull-ups enabled, pull-downs disabled
Low	High	Low	Output low, pin unpowered	Outputs disabled	Output low, pin unpowered
Low	High	High	Pin is tri-stated (output buffer, input buffer, and weak pulls disabled)	Outputs disabled	Pull-ups enabled, pull-downs disabled

¹ MH+LVDS pads are output-only.

Table 12. Power Sequence Pin States for F and FS pads

VDD	VDD33	VDDE	F and FS pads
low	low	high	Outputs drive high
low	high	—	Outputs Disabled
high	low	low	Outputs Disabled
high	low	high	Outputs drive high
high	high	low	Normal operation - except no drive current and input buffer output is unknown. ¹
high	high	high	Normal Operation

¹ The pad pre-drive circuitry will function normally but since VDDE is unpowered the outputs will not drive high even though the output pmos can be enabled.

4.6.1 Power-Up

If V_{DDE}/V_{DDEH} is powered up first, then a threshold detector tristates all drivers connected to V_{DDE}/V_{DDEH} . There is no limit to how long after V_{DDE}/V_{DDEH} powers up before V_{DD} must power up. If there are multiple V_{DDE}/V_{DDEH} supplies, they can be powered up in any order. For each V_{DDE}/V_{DDEH} supply not powered up, the drivers in that V_{DDE}/V_{DDEH} segment exhibit the characteristics described in the next paragraph.

If V_{DD} is powered up first, then all pads are loaded through the drain diodes to V_{DDE}/V_{DDEH} . This presents a heavy load that pulls the pad down to a diode above V_{SS} . Current injected by external devices connected to the pads must meet the current injection specification. There is no limit to how long after V_{DD} powers up before V_{DDE}/V_{DDEH} must power up.

The rise times on the power supplies are to be no faster than 25 V/millisecond.

4.6.2 Power-Down

If V_{DD} is powered down first, then all drivers are tristated. There is no limit to how long after V_{DD} powers down before V_{DDE}/V_{DDEH} must power down.

If V_{DDE}/V_{DDEH} is powered down first, then all pads are loaded through the drain diodes to V_{DDE}/V_{DDEH} . This presents a heavy load that pulls the pad down to a diode above V_{SS} . Current injected by external devices connected to the pads must meet the current injection specification. There is no limit to how long after V_{DDE}/V_{DDEH} powers down before V_{DD} must power down.

There are no limits on the fall times for the power supplies.

4.6.3 Power Sequencing and POR Dependent on V_{DDA}

During power up or down, V_{DDA} can lag other supplies (of magnitude greater than $V_{DDEH}/2$) within 1 V to prevent any forward-biasing of device diodes that causes leakage current and/or POR. If the voltage difference between V_{DDA} and V_{DDEH} is more than 1 V, the following will result:

- Triggers POR (ADC monitors on V_{DDEH1} segment which powers the RESET pin) if the leakage current path created, when V_{DDA} is sufficiently low, causes sufficient voltage drop on V_{DDEH1} node monitored crosses low-voltage detect level.
- If V_{DDA} is between 0–2 V, powering all the other segments (especially V_{DDEH1}) will not be sufficient to get the part out of reset.
- Each V_{DDEH} will have a leakage current to V_{DDA} of a magnitude of $((V_{DDEH} - V_{DDA} - 1\text{ V(diode drop)})/200\text{ KOhms})$ up to $(V_{DDEH}/2 = V_{DDA} + 1\text{ V})$.
- Each V_{DD} has the same behavior; however, the leakage will be small even though there is no current limiting resistor since $V_{DD} = 1.32\text{ V max.}$

4.7 DC Electrical Specifications

Table 13. DC Electrical Specifications¹

Spec	Characteristic	Symbol	Min	Max	Unit
1	Core Supply Voltage (External Regulation)	V_{DD}	1.14	1.32 ^{2, 3}	V
1a	Core Supply Voltage (Internal Regulation) ⁴	V_{DD}	1.08	1.32	V
2	I/O Supply Voltage (fast I/O pads)	V_{DDE}	3.0	3.6 ²	V
3	I/O Supply Voltage (medium I/O pads)	V_{DDEH}	3.0	5.25 ²	V
4	3.3 V I/O Buffer Voltage	V_{DD33}	3.0	3.6 ²	V
5	Analog Supply Voltage	V_{DDA}	4.75	5.25 ²	V
6a	SRAM Standby Voltage low range	V_{STBY_LOW}	0.95 ⁵	1.2	V
6b	SRAM Standby Voltage high range	V_{STBY_HIGH}	2	6	V
7	Voltage Regulator Control Input Voltage ⁶	V_{DDREG}	2.7 ⁷	5.5 ²	V
8	Clock Synthesizer Operating Voltage ⁸	V_{DDSYN}	3.0	3.6 ²	V
9	Fast I/O Input High Voltage Hysteresis enabled Hysteresis disabled	V_{IH_F}	0.65 × V_{DDE} 0.55 × V_{DDE}	$V_{DDE} + 0.3$	V
10	Fast I/O Input Low Voltage Hysteresis enabled Hysteresis disabled	V_{IL_F}	$V_{SS} - 0.3$	0.35 × V_{DDE} 0.40 × V_{DDE}	V
11	Medium I/O Input High Voltage Hysteresis enabled Hysteresis disabled	V_{IH_S}	0.65 × V_{DDEH} 0.55 × V_{DDEH}	$V_{DDEH} + 0.3$	V

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Table 13. DC Electrical Specifications¹ (continued)

Spec	Characteristic	Symbol	Min	Max	Unit
12	Medium I/O Input Low Voltage Hysteresis enabled Hysteresis disabled	V _{IL_S}	V _{SS} – 0.3	0.35 × V _{DDEH} 0.40 × V _{DDEH}	V
13	Fast I/O Input Hysteresis	V _{HYS_F}	0.1 × V _{DDE}	—	V
14	Medium I/O Input Hysteresis	V _{HYS_S}	0.1 × V _{DDEH}	—	V
15	Analog Input Voltage	V _{INDC}	V _{SSA} – 0.1	V _{DDA} + 0.1	V
16	Fast I/O Output High Voltage ⁹	V _{OH_F}	0.8 × V _{DDE}	—	V
17	Medium I/O Output High Voltage ¹⁰	V _{OH_S}	0.8 × V _{DDEH}	—	V
18	Fast I/O Output Low Voltage ⁹	V _{OL_F}	—	0.2 × V _{DDE}	V
19	Medium I/O Output Low Voltage ¹⁰	V _{OL_S}	—	0.2 × V _{DDEH}	V
20	Load Capacitance (Fast I/O) ¹¹ DSC(PCR[8:9]) = 0b00 DSC(PCR[8:9]) = 0b01 DSC(PCR[8:9]) = 0b10 DSC(PCR[8:9]) = 0b11	C _L	— — — —	10 20 30 50	pF pF pF pF
21	Input Capacitance (Digital Pins)	C _{IN}	—	7	pF
22	Input Capacitance (Analog Pins)	C _{IN_A}	—	10	pF
23	Input Capacitance (Digital and Analog Pins ¹²)	C _{IN_M}	—	12	pF
24	Operating Current 1.2 V Supplies @ f _{sys} = 180 MHz V _{DD} (including V _{DDF} current) @ 1.32 V V _{STBY} ¹³ @ 1.2 V and 85°C V _{STBY} @ 6.0 V and 85°C V _{DDF} ¹⁴ (P/E) V _{DDF} ¹⁴ (Read) V _{DDF} ¹⁴ (RWW) V _{DDF} ¹⁴ (Standby) V _{DDF} ¹⁴ (Disabled)	I _{DD} I _{DDSTBY} I _{DDSTBY6} I _{DDFPE} I _{DDFREAD} I _{DDFRWW} I _{DDpTSTANDBY} I _{DDFDISABLED}	— — — — — — — —	1.0 ¹⁵ 0.10 0.15 36 ¹⁶ 50 ¹⁶ 90 ¹⁶ 0.20 ¹⁶ 0.10 ¹⁶	A mA mA mA mA mA mA mA
25	Operating Current 3.3 V Supplies @ f _{sys} = 180 MHz V _{DD33} ¹⁷ V _{DDSYN} ¹⁸ (P/E) V _{FLASH} ¹⁸ (Read) V _{FLASH} ¹⁸ (RWW) V _{FLASH} ¹⁸ (Standby) V _{FLASH} ¹⁸ (Disabled)	I _{DD33} I _{DDSYN} I _{DDFLASHPE} I _{DDFLASHREADS} I _{DDFLASHRW} I _{DDFLASHSTANDBY} I _{DDFLASHDISABLED}	— — — — — — —	note ¹⁷ 7 ¹⁹ 32 ²⁰ 6.4 ²⁰ 40 ²⁰ 3.4 ²⁰ 0.10 ²⁰	mA mA mA mA mA mA mA
26	Operating Current 5.0 V Supplies @ f _{sys} = 180 MHz V _{DDA} Analog Reference Supply Current (Transient) V _{DDREG}	I _{DDA} I _{REF} I _{REG}	— — —	50 ²¹ 1.0 22	mA mA mA

Table 13. DC Electrical Specifications¹ (continued)

Spec	Characteristic	Symbol	Min	Max	Unit
27	Operating Current V_{DDE}/V_{DDEH} ²² Supplies V_{DDE2} V_{DDEH1} V_{DDEH3} V_{DDEH4} V_{DDEH5} V_{DDEH6} V_{DDEH7}	I_{DD2} I_{DD1} I_{DD3} I_{DD4} I_{DD5} I_{DD6} I_{DD7}	— — — — — — —	note ²²	mA mA mA mA mA mA mA
28	Fast I/O Weak Pull Up/Down Current ²³ 3.0 V–3.6 V	I_{ACT_F}	42	158	μA
29	Medium I/O Weak Pull Up/Down Current ²⁴ 3.0 V–3.6 V 4.5 V–5.5 V	I_{ACT_S}	15 35	95 200	μA μA
30	I/O Input Leakage Current ²⁵	I_{INACT_D}	-2.5	2.5	μA
31	DC Injection Current (per pin)	I_{IC}	-1.0	1.0	mA
32	Analog Input Current, Channel Off ²⁶ , AN[0:7], AN38, AN39 Analog Input Current, Channel Off, all other analog inputs AN[x] = -/+ 150nA	I_{INACT_A}	-250 -150	250 150	nA nA
33	V_{SS} Differential Voltage	$V_{SS} - V_{SSA}$	-100	100	mV
34	Analog Reference Low Voltage	V_{RL}	V_{SSA}	$V_{SSA} + 100$	mV
35	V_{RL} Differential Voltage	$V_{RL} - V_{SSA}$	-100	100	mV
36	Analog Reference High Voltage	V_{RH}	$V_{DDA} - 100$	V_{DDA}	mV
37	V_{REF} Differential Voltage	$V_{RH} - V_{RL}$	4.75	5.25	V
38	V_{SSSYN} to V_{SS} Differential Voltage	$V_{SSSYN} - V_{SS}$	-100	100	mV
39	Operating Temperature Range—Ambient (Packaged)	T_A (T_L to T_H)	-40.0	125.0	°C
40	Slew rate on power supply pins	—	—	25	V/ms
41	Weak Pull-Up/Down Resistance ^{27,28} 200 kΩ Option	$R_{PUPD200K}$	130	280	kΩ
42	Weak Pull-Up/Down Resistance ^{27,28} 100 kΩ Option	$R_{PUPD100K}$	65	140	kΩ
43	Weak Pull-Up/Down Resistance ²⁷ (5 kΩ Option) 5 V ± 10% supply 3.3 V ± 10% supply	R_{PUPD5K}	1.4 1.7	5.2 7.7	kΩ
44	Pull-Up/Down Resistance Matching Ratios (100K/200K) (Pull-up and pull-down resistances both enabled and settings are equal)	$R_{PUPDMATCH}$	-2.5	2.5	%

¹ These specifications are design targets and subject to change per device characterization.² Voltage overshoots during a high-to-low or low-to-high transition must not exceed 10 seconds per instance.³ 2.0 V for 10 hours cumulative time, 1.2 V +10% for time remaining.

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- 4 Assumed with DC load.
- 5 V_{STBY} below 0.95 V the RAM will not retain states, but will be operational. V_{STBY} can be 0 V when bypass standby mode.
- 6 Regulator is functional with derated performance, with supply voltage down to 4.0 V for system with $V_{DDREG} = 4.5$ V (min).
- 7 2.7 V minimum operating voltage allowed during vehicle crank for system with $V_{DDREG} = 3.0$ V (min). Normal operating voltage should be either $V_{DDREG} = 3.0$ V (min) or 4.5 V (min) depending on the user regulation voltage system selected.
- 8 Required to be supplied when 3.3 V regulator is disabled. See [Section 4.5, “PMC/POR/LVI Electrical Specifications.”](#)
- 9 $I_{OH_F} = \{12, 20, 30, 40\}$ mA and $I_{OL_F} = \{24, 40, 50, 65\}$ mA for {00, 01, 10, 11} drive mode with $V_{DDE} = 3.0$ V;
 $I_{OH_F} = \{7, 13, 18, 25\}$ mA and $I_{OL_F} = \{18, 30, 35, 50\}$ mA for {00, 01, 10, 11} drive mode with $V_{DDE} = 2.25$ V;
 $I_{OH_F} = \{3, 7, 10, 16\}$ mA and $I_{OL_F} = \{12, 20, 27, 35\}$ mA for {00, 01, 10, 11} drive mode with $V_{DDE} = 1.62$ V
- 10 $I_{OH_S} = \{11.6\}$ mA and $I_{OL_S} = \{17.7\}$ mA for {medium} I/O with $V_{DDEH} = 4.5$ V;
 $I_{OH_S} = \{5.4\}$ mA and $I_{OL_S} = \{8.1\}$ mA for {medium} I/O with $V_{DDEH} = 3.0$ V
- 11 Applies to D_CLKOUT, external bus pins, and Nexus pins.
- 12 Applies to the FCK, SDI, SDO, and SDS_B pins.
- 13 V_{STBY} current specified at 1.0 V at a junction temperature of 85 °C. V_{STBY} current is 700 µA maximum at a junction temperature of 150 °C.
- 14 VDDF pin is shorted to V_{DD} on the package substrate.
- 15 Preliminary. Specification pending typical and/or high-use Runid pattern simulation as well as final silicon characterization.
1.0 A based on transistor count estimate at Worst Case (wcs) process and temperature condition.
- 16 Typical values from the simulation.
- 17 Power requirements for the V_{DD33} supply depend on the frequency of operation and load of all I/O pins, and the voltages on the I/O segments. See [Section 4.7.2, “I/O Pad \$V_{DD33}\$ Current Specifications,”](#) for information on both fast (F, FS) and medium (MH) pads. Also refer to [Table 15](#) for values to calculate power dissipation for specific operation.
- 18 VFLSH pin is shorted to V_{DD33} on the package substrate.
- 19 This value is a target that is subject to change.
- 20 Typical values from the simulation.
- 21 These value allows a 5 V 20 mA reference to supply ADC + REF.
- 22 Power requirements for each I/O segment depend on the frequency of operation and load of the I/O pins on a particular I/O segment, and the voltage of the I/O segment. See [Section 4.7.1, “I/O Pad Current Specifications,”](#) for information on I/O pad power. Also refer to [Table 14](#) for values to calculate power dissipation for specific operation. The total power consumption of an I/O segment is the sum of the individual power consumptions for each pin on the segment.
- 23 Absolute value of current, measured at V_{IL} and V_{IH} .
- 24 Absolute value of current, measured at V_{IL} and V_{IH} .
- 25 Weak pull up/down inactive. Measured at $V_{DDE} = 3.6$ V and $V_{DDEH} = 5.25$ V. Applies to pad types F and MH.
- 26 Maximum leakage occurs at maximum operating temperature. Leakage current decreases by approximately one-half for each 8 to 12 °C, in the ambient temperature range of 50 to 125 °C. Applies to pad types AE and AE/up-down.
- 27 This programmable option applies only to eQADC differential input channels and is used for biasing and sensor diagnostics.
- 28 When the pull-up and pull-down of the same nominal 200 kΩ or 100 kΩ value are both enabled, assuming no interference from external devices, the resulting pad voltage will be $0.5^*V_{DDEH} \pm 2.5\%$.

4.7.1 I/O Pad Current Specifications

The power consumption of an I/O segment is dependent on the usage of the pins on a particular segment. The power consumption is the sum of all output pin currents for a particular segment. The output pin current can be calculated from [Table 14](#) based on the voltage, frequency, and load on the pin. Use linear scaling to calculate pin currents for voltage, frequency, and load parameters that fall outside the values given in [Table 14](#).

The AC timing of these pads are described in the [Section 4.11.2, “Pad AC Specifications.”](#)

Table 14. V_{DDE}/V_{DDEH} I/O Pad Average DC Current¹

Spec	Pad Type	Symbol	Frequency (MHz)	Load ² (pF)	Voltage (V)	Drive/Slew Rate Select	Current (mA)
1	Medium	I_{DRV_MH}	50	50	5.25	11	16.0
2			20	50	5.25	01	6.3
3			3.0	50	5.25	00	1.1
4			2.0	200	5.25	00	2.4
5	Fast	I_{DRV_FC}	66	10	3.6	00	6.5
6			66	20	3.6	01	9.4
7			66	30	3.6	10	10.8
8			66	50	3.6	11	33.3
9			66	10	1.98	00	2.0
10			66	20	1.98	01	3.0
11			66	30	1.98	10	4.4
12			66	50	1.98	11	15.1
13	Fast w/ Slew Control	I_{DRV_FSR}	66	50	3.6	11	12.0
14			50	50	3.6	10	6.2
15			33.33	50	3.6	01	4.0
16			20	50	3.6	00	2.4
17			20	200	3.6	00	8.9

¹ These are average IDDE numbers for worst case PVT from simulation. Currents apply to output pins only.

² All loads are lumped.

4.7.2 I/O Pad V_{DD33} Current Specifications

The power consumption of the V_{DD33} supply is dependent on the usage of the pins on all I/O segments. The power consumption is the sum of all input and output pin V_{DD33} currents for all I/O segments. The V_{DD33} current draw on fast speed pads can be calculated from [Table 15](#) dependent on the voltage, frequency, and load on all F type pins. The V_{DD33} current draw on medium pads can be calculated from [Table 15](#) dependent on voltage and independent on the frequency and load on all MH type pins. Use linear scaling to calculate pin currents for voltage, frequency, and load parameters that fall outside the values given in [Table 15](#).

The AC timing of these pads are described in the [Section 4.11.2, “Pad AC Specifications.”](#)

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Table 15. V_{DD33} Pad Average DC Current¹

Spec	Pad Type	Symbol	Frequency (MHz)	Load ² (pF)	V _{DD33} (V)	V _{DDE} (V)	Drive/Slew Rate Select	Current (mA)
1	Medium	I _{33_MH}	—	—	3.6	5.5	—	0.0007
2	Fast	I _{33_FC}	66	10	3.6	3.6	00	0.92
3			66	20	3.6	3.6	01	1.14
4			66	30	3.6	3.6	10	1.50
5			66	50	3.6	3.6	11	2.19
6			66	10	3.6	1.98	00	0.70
7			66	20	3.6	1.98	01	0.90
8			66	30	3.6	1.98	10	1.08
9			66	50	3.6	1.98	11	1.52
10	Fast w/ Slew Control	I _{33_FSR}	66	50	3.6	3.6	11	0.74
11			50	50	3.6	3.6	10	0.52
12			33.33	50	3.6	3.6	01	0.36
13			20	50	3.6	3.6	00	0.19
14			20	200	3.6	3.6	00	0.19

¹ These are average IDD33 for worst case PVT from simulation. Currents apply to output pins only for the fast pads and to input pins only for the medium pads.

² All loads are lumped.

4.7.3 LVDS Pad Specifications

LVDS pads are implemented to support the MSC (Microsecond Channel) protocol, which is an enhanced feature of the DSPI module.

Table 16. DSPI LVDS Pad Specification^{1, 2}
(V_{DD33} = 3.0 V to 3.6 V, V_{DDEH} = 4.75 V to 5.25 V, T_A = T_L to T_H)

Spec	Characteristic	Symbol	Min	Typical	Max	Unit
Data Rate						
1	Data Frequency	f _{LVDSCLK}	—	—	40	MHz
Driver Specs						
2	Differential Output Voltage SRC=0b00 or 0b11 SRC=0b01 SRC=0b10	V _{OD}	150 90 160	—	400 320 480	mV
3	Common Mode Voltage (LVDS), V _{OS}	V _{OS}	1.075	1.2	1.325	V
4	Rise/Fall Time	t _R or t _F	—	—	2.5	ns
5	Delay, Z to Normal (High/Low)	t _{DZ}	—	—	100	ns

Table 16. DSPI LVDS Pad Specification^{1, 2} (continued)
 $(V_{DD33} = 3.0 \text{ V to } 3.6 \text{ V}, V_{DDEH} = 4.75 \text{ V to } 5.25 \text{ V}, T_A = T_L \text{ to } T_H)$

6	Differential Skew between Positive and Negative LVDS Pair $ t_{phla} - t_{plhb} $ or $ t_{plhb} - t_{phla} $	t_{Skew}	—	—	0.5	ns
Termination						
7	Transmission Line (Differential)	Z_O	95	100	105	ohm
8	Load	—	—	—	25	pF

¹ These are typical values that are estimated from simulation.

² These specifications are subject to change per device characterization.

Table 17. Power Management Control (PMC) Specification

Spec	Characteristic	Symbol	Min	Typical	Max	Unit
PMC Normal Mode						
1	Bandgap 0.62 V ADC0 channel 145	V_{ADC145}	—	0.62	—	V
2	Bandgap 1.2 V ADC0 channel 146	V_{ADC146}	—	1.22	—	V
3	Vreg1p2 Feedback ADC0 channel 147	V_{ADC147}	—	$V_{DD} / 2.045$	—	V
4	LVD 1.2 V ADC0 channel 180	V_{ADC180}	—	$V_{DD} / 1.774$	—	V
5	Vreg3p3 Feedback ADC0 channel 181	V_{ADC181}	—	Vreg3p3 / 5.460	—	V
6	LVD 3.3 V ADC0 channel 182	V_{ADC182}	—	Vreg3p3 / 4.758	—	V
7	LVD 5.0 V ADC0 channel 183 — LDO mode — SMPS mode	V_{ADC183}	—	$V_{DDREG} / 4.758$ $V_{DDREG}/7.032$	—	V

Table 18. Standby RAM Regulator Electrical Specifications

Spec	Characteristic	Symbol	Min	Typ	Max	Unit
Normal Mode						
1	Standby Regulator Output ADC1 channel 194	V_{ADC194}	—	1.2	—	V
2	Standby Source Bias ADC1 channel 195	V_{ADC195}	150	—	360	mV

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Table 19. ADC Band Gap Reference / LVI Electrical Specifications

Spec	Characteristic	Symbol	Min	Typ	Max	Unit
1	4.75 LVD (from V _{DDA}) ADC1 channel 196	V _{ADC196}	—	4.75	—	V
2	ADC Bandgap ADC0 channel 45 ADC1 channel 45	V _{ADC45}	—	1.220	—	V

Table 20. Temperature Sensor Electrical Specifications

Spec	Characteristic	Symbol	Min	Typ	Max	Unit
1	Slope –40 °C to 100 °C ±1.0 °C 100 °C to 150 °C ±1.6 °C ADC0 channel 128 ADC1 channel 128	V _{SADC128} ¹	—	5.8	—	mV/ °C
2	Accuracy –40 °C to 100 °C 100 °C to 150 °C ADC0 channel 128 ADC1 channel 128	—	—	±1.0 ±1.6	—	°C

¹ Slope is the measured voltage change per °C.

4.8 Oscillator and FMPLL Electrical Characteristics

Table 21. FMPLL Electrical Specifications¹

(V_{DDSYN} = 3.0 V to 3.6 V, V_{SS} = V_{SSSYN} = 0 V, T_A = T_L to T_H)

Spec	Characteristic	Symbol	Min	Max	Unit
1	PLL Reference Frequency Range ² (Normal Mode) Crystal Reference (PLLCFG2 = 0b0) Crystal Reference (PLLCFG2 = 0b1) External Reference (PLLCFG2 = 0b0) External Reference(PLLCFG2 = 0b1)	f _{ref_crystal} f _{ref_crystal} f _{ref_ext} f _{ref_ext}	8 40 8 40	20 40 ³ 20 40	MHz
2	PLL Frequency ⁴ Enhanced Mode	f _{PLL}	f _{vco(min)} ÷ 64	f _{max}	MHz
3	Loss of Reference Frequency ⁵	f _{LOR}	100	1000	kHz
4	Self Clocked Mode Frequency ⁶	f _{SCM}	4	16	MHz
5	PLL Lock Time ⁷	t _{LPLL}	—	<750	μs
6	Duty Cycle of Reference ^{8, 9}	t _{DC}	40	60	%
7	Frequency un-LOCK Range	f _{UL}	–4.0	4.0	% f _{sys}
8	Frequency LOCK Range	f _{LCK}	–2.0	2.0	% f _{sys}

Table 21. FMPLL Electrical Specifications¹ (continued)
 $(V_{DDSYN} = 3.0 \text{ V to } 3.6 \text{ V}, V_{SS} = V_{SSSYN} = 0 \text{ V}, T_A = T_L \text{ to } T_H)$

Spec	Characteristic	Symbol	Min	Max	Unit
9	D_CLKOUT Period Jitter ^{10, 11} Measured at f_{SYS} Max Cycle-to-cycle Jitter	C_{jitter}	-5	5	% f_{clock} ut
10	Peak-to-Peak Frequency Modulation Range Limit ^{12, 13} (f_{sys} Max must not be exceeded)	C_{mod}	0	4	% f_{sys}
11	FM Depth Tolerance ¹⁴	C_{mod_err}	-0.25	0.25	% f_{sys}
12	VCO Frequency	f_{VCO}	192	600	MHz
13	Modulation Rate Limits ¹⁵	f_{mod}	0.400	1	MHz
14	Predivider Operating Frequency	f_{prediv}	4	10	MHz

¹ All values given are initial design targets and subject to change.

² Crystal and External reference frequency limits depend on device relying on PLL to lock prior to release of reset, default PREDIV/EPREDIV, MFD/EMFD default settings, and VCO frequency range. Absolute minimum loop frequency is 4 MHz.

³ Upper tolerance of less than 1% is allowed on 40MHz crystal.

⁴ All internal registers retain data at 0 Hz.

⁵ "Loss of Reference Frequency" is the reference frequency detected internally, which transitions the PLL into self clocked mode.

⁶ Self clocked mode frequency is the frequency that the PLL operates at when the reference frequency falls below f_{LOR} . This frequency is measured at D_CLKOUT with the divider set to divide-by-2 of the system clock. NOTE: in SCM, the PLL is running open loop at a centercode 0x4. The MFD has no effect and the RFD is bypassed.

⁷ This specification applies to the period required for the PLL to re-lock after changing the MFD frequency control bits in the synthesizer control register (SYNCR). From power up with crystal oscillator reference, lock time will be additive with crystal startup time.

⁸ For FlexRay operation, duty cycle requirements are higher.

⁹ Duty cycle can be 20–80% when PLL is used with a pre-divider greater than 1.

¹⁰ Jitter is the average deviation from the programmed frequency measured over the specified interval at maximum f_{sys} . Measurements are made with the device powered by filtered supplies and clocked by a stable external clock signal. Noise injected into the PLL circuitry via V_{DDSYN} and V_{SSSYN} and variation in crystal oscillator frequency increase the C_{jitter} percentage for a given interval. D_CLKOUT divider set to divide-by-2.

¹¹ Values are with frequency modulation disabled. If frequency modulation is enabled, jitter is the sum of $C_{jitter} + C_{mod}$.

¹² Modulation depth selected must not result in f_{PLL} value greater than the f_{PLL} maximum specified value.

¹³ Maximum and minimum variation from programmed modulation depth is pending characterization. Depth settings available in control register are: 1%, 2%, 3%, and 4% peak-to-peak.

¹⁴ Depth tolerance is the programmed modulation depth $\pm 0.25\%$ of F_{sys} . Initial design target pending silicon evaluation.

¹⁵ Modulation rates less than 400 kHz will result in exceedingly long FM calibration durations. Modulation rates greater than 1 MHz will result in reduced calibration accuracy.

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Table 22. Oscillator Electrical Specifications¹
 $(V_{DDSYN} = 3.0 \text{ V to } 3.6 \text{ V}, V_{SS} = V_{SSSYN} = 0 \text{ V}, T_A = T_L \text{ to } T_H)$

Spec	Characteristic	Symbol	Min	Max	Unit
1	Crystal Mode Differential Amplitude ² (Min differential voltage between EXTAL and XTAL)	$V_{\text{crystal_diff_amp}}$	$ V_{\text{extal}} - V_{\text{xtal}} > 0.4 \text{ V}$	—	V
2	Crystal Mode: Internal Differential Amplifier Noise Rejection	$V_{\text{crystal_diff_amp_nr}}$	—	$ V_{\text{extal}} - V_{\text{xtal}} < 0.2 \text{ V}$	V
3	EXTAL Input High Voltage Bypass mode, External Reference	$V_{I\text{HEXT}}$	$((V_{DD33}/2) + 0.4 \text{ V})$	—	V
4	EXTAL Input Low Voltage Bypass mode, External Reference	$V_{I\text{LEXT}}$	—	$(V_{DD33}/2) - 0.4 \text{ V}$	V
5	XTAL Current ³	I_{XTAL}	1	3	mA
6	Total On-chip stray capacitance on XTAL	C_{S_XTAL}	—	1.5	pF
7	Total On-chip stray capacitance on EXTAL	C_{S_EXTAL}	—	1.5	pF
8	Crystal manufacturer's recommended capacitive load	C_L	See crystal spec	See crystal spec	pF
9	Discrete load capacitance to be connected to EXTAL	C_{L_EXTAL}	—	$(2 \times C_L - C_{S_EXTAL})$	pF
10	Discrete load capacitance to be connected to XTAL	C_{L_XTAL}	—	$(2 \times C_L - C_{S_XTAL} - C_{PCB_XTAL})$	pF

¹ All values given are initial design targets and subject to change.

² This parameter is meant for those who do not use quartz crystals or resonators, but instead use CAN oscillators in crystal mode. In that case, $V_{\text{extal}} - V_{\text{xtal}} \geq 400 \text{ mV}$ criterion has to be met for oscillator's comparator to produce output clock.

³ I_{xtal} is the oscillator bias current out of the XTAL pin with both EXTAL and XTAL pins grounded.

⁴ C_{PCB_EXTAL} and C_{PCB_XTAL} are the measured PCB stray capacitances on EXTAL and XTAL, respectively.

4.9 eQADC Electrical Characteristics

Table 23. eQADC Conversion Specifications (Operating)

Spec	Characteristic	Symbol	Min	Max	Unit
1	ADC Clock (ADCLK) Frequency	f_{ADCLK}	2	16	MHz
2	Conversion Cycles	CC	$2 + 13$	$128 + 14$	ADCLK cycles
3	Stop Mode Recovery Time ¹	T_{SR}	10	—	μs
4	Resolution ²	—	1.25	—	mV
5	INL: 8 MHz ADC Clock ³	INL8	-4^4	4^4	LSB ⁵
6	INL: 16 MHz ADC Clock ³	INL16	-8^4	8^4	LSB
7	DNL: 8 MHz ADC Clock ³	DNL8	-3^4	3^4	LSB
8	DNL: 16 MHz ADC Clock ³	DNL16	-3^4	3^4	LSB

Table 23. eQADC Conversion Specifications (Operating) (continued)

Spec	Characteristic	Symbol	Min	Max	Unit
9	Offset Error without Calibration	OFFNC	0 ⁴	100 ⁴	LSB
10	Offset Error with Calibration	OFFWC	-4 ⁴	4 ⁴	LSB
11	Full Scale Gain Error without Calibration	GAINNC	-120 ⁴	0 ⁴	LSB
12	Full Scale Gain Error with Calibration	GAINWC	-4 ^{4,6}	4 ^{4,6}	LSB
13	Disruptive Input Injection Current ^{7, 8, 9, 10}	I _{INJ}	-1	1	mA
14	Incremental Error due to injection current ^{11, 12}	E _{INJ}	—	±4 ⁴	Counts
15	TUE value at 8 MHz ^{13, 14} (with calibration)	TUE8	—	±4 ^{4,6}	Counts
16	TUE value at 16 MHz ^{13, 14} (with calibration)	TUE16	—	±8	Counts
17	Variable gain amplifier accuracy (gain=1) ¹⁵ INL, 8 MHz ADC INL, 16 MHz ADC DNL, 8 MHz ADC DNL, 16 MHz ADC	GAINVGA1	-4 -8 -3 ¹⁶ -3 ¹⁶	4 8 3 ¹⁶ 3 ¹⁶	Counts ¹⁷
18	Variable gain amplifier accuracy (gain=2) ¹⁵ INL, 8 MHz ADC INL, 16 MHz ADC DNL, 8 MHz ADC DNL, 16 MHz ADC	GAINVGA2	-5 -8 -3 -3	5 8 3 3	Counts
19	Variable gain amplifier accuracy (gain=4) ¹⁵ INL, 8 MHz ADC INL, 16 MHz ADC DNL, 8 MHz ADC DNL, 16 MHz ADC	GAINVGA4	-7 -8 -4 -4	7 8 4 4	Counts

¹ Stop mode recovery time is the time from the setting of either of the enable bits in the ADC Control Register to the time that the ADC is ready to perform conversions. Delay from power up to full accuracy = 8 ms.

² At V_{RH} – V_{RL} = 5.12 V, one count = 1.25 mV without using pregain.

³ INL and DNL are tested from V_{RL} + 50 LSB to V_{RH} – 50 LSB.

⁴ New design target. Actual specification will change following characterization. Margin for manufacturing has not been fully included.

⁵ At V_{RH} – V_{RL} = 5.12 V, one LSB = 1.25 mV.

⁶ The value is valid at 8 MHz, it is ±8 counts at 16 MHz.

⁷ Below disruptive current conditions, the channel being stressed has conversion values of \$3FF for analog inputs greater than V_{RH} and \$000 for values less than V_{RL}. Other channels are not affected by non-disruptive conditions.

⁸ Exceeding limit may cause conversion error on stressed channels and on unstressed channels. Transitions within the limit do not affect device reliability or cause permanent damage.

⁹ Input must be current limited to the value specified. To determine the value of the required current-limiting resistor, calculate resistance values using V_{POSCLAMP} = V_{DDA} + 0.5 V and V_{NEGCLAMP} = -0.3 V, then use the larger of the calculated values.

¹⁰ Condition applies to two adjacent pins at injection limits.

¹¹ Performance expected with production silicon.

¹² All channels have same 10 kΩ < R_s < 100 kΩ Channel under test has R_s = 10 kΩ, I_{INJ}=I_{INJMAX}, I_{INJMIN}.

¹³ The TUE specification is always less than the sum of the INL, DNL, offset, and gain errors due to cancelling errors.

¹⁴ TUE does not apply to differential conversions.

Electrical Characteristics

¹⁵ Variable gain is controlled by setting the PRE_GAIN bits in the ADC_ACR1-8 registers to select a gain factor of $\times 1$, $\times 2$, or $\times 4$. Settings are for differential input only. Tested at $\times 1$ gain. Values for other settings are guaranteed by as indicated.

¹⁶ Guaranteed 10-bit mono tonicity.

¹⁷ At $V_{RH} - V_{RL} = 5.12$ V, one LSB = 1.25 mV.

4.10 C90 Flash Memory Electrical Characteristics

Table 24. Flash Program and Erase Specifications (Pending Si characterization)

Spec	Characteristic	Symbol	Typ ¹	Initial Max ²	Lifetime Max ³	Unit
1	Double Word (64 bits) Program Time ⁴	$t_{dwprogram}$	38	—	500	μs
2	Page (128 bits) Program Time ⁴	$t_{pprogram}$	45	160	500	μs
3	16 KB Block Pre-program and Erase Time	$t_{16kpperase}$	270	1000	5000	ms
4	48 KB Block Pre-program and Erase Time	$t_{48kpperase}$	625	1500	5000	ms
5	64 KB Block Pre-program and Erase Time	$t_{64kpperase}$	800	1800	5000	ms
6	128 KB Block Pre-program and Erase Time	$t_{128kpperase}$	1500	2600	7500	ms
7	256 KB Block Pre-program and Erase Time	$t_{256kpperase}$	3000	5200	15000	ms

¹ Typical program and erase times represent the median performance and assume nominal supply values and operation at 25 °C. These values are characterized, but not tested.

² Initial Max program and erase times provide guidance for time-out limits used in the factory and apply for < 100 program/erase cycles, nominal supply values and operation at 25 °C. These values are verified at production test.

³ Lifetime Max program and erase times apply across the voltage, temperature, and cycling range of product life. These values are characterized, but not tested.

⁴ Program times are actual hardware programming times and do not include software overhead.

Table 25. Flash EEPROM Module Life

Spec	Characteristic	Symbol	Min	Typical ¹	Unit
1	Number of Program/Erase cycles per block for 16 KB and 64 KB blocks over the operating temperature range (T_J)	P/E	100,000	—	cycles
2	Number of Program/Erase cycles per block for 128 KB and 256 KB blocks over the operating temperature range (T_J)	P/E	1,000	100,000	cycles
3	Minimum Data Retention at 25 °C ambient temperature ² Blocks with 0–1,000 P/E cycles Blocks with 1,001–10,000 P/E cycles Blocks with 10,001–100,000 P/E cycles	Retention	20 10 1 – 5	—	years

¹ Typical endurance is evaluated at 25 °C. Product qualification is performed to the minimum specification. For additional information on the Freescale definition of Typical Endurance, please refer to Engineering Bulletin EB619, *Typical Endurance for Nonvolatile Memory*.

² Ambient temperature averaged over duration of application, not to exceed product operating temperature range.

Table 26. BIUCR1/BIUCR3 Settings

Spec	Maximum Frequency (MHz)		APC = RWSC	WWSC	DPFEN ¹	IPFEN ¹	PFLIM ²	BFEN ³
	Core f _{sys}	Platform f _{platf}						
1	180 MHz	90 MHz	0b010	0b01	0b0 0b1	0b0 0b1	0b00 0b01 0b1x	0b0 0b1
	Default setting after reset:		0b111	0b11	0b00	0b00	0b00	0b0

¹ For maximum flash performance, set to 0b1.

² For maximum flash performance, set to 0b10.

³ For maximum flash performance, set to 0b1.

4.11 AC Specifications

4.11.1 Clocking Modes

There are two main modes of operating frequency settings:

- Double 2:1 (Core:Platform) Mode—the core is running at the system frequency setting while the platform and eTPU are running at half the core frequency (system frequency divided by 2).
- eTPU Mode—the core and eTPU are running at the system frequency setting while the platform is running at half the core frequency (system frequency divided by 2).

Table 27 shows the operating frequencies of various blocks depending on the device's clocking mode configuration settings.

Table 27. MPC5676R Block Operating Frequency^{1, 2}

Spec	Blocks	Symbol	Double Mode Freq (MHz)	eTPU Mode Freq (MHz)
1	Cores	f _{sys} (t _{cycsys} = 1/f _{sys})	f _{sys} = 180	f _{sys} = 180
2	Platform	f _{platf} (t _{cyc} = 1/f _{platf})	f _{sys} / 2	f _{sys} / 2
3	eTPU	f _{eTPU}	f _{sys} / 2	f _{sys}
4	EBI	f _{ebi}	f _{sys} / 4	f _{sys} / 4

¹ The values in the table are specified at V_{DD} = 1.02 V to 1.32 V, V_{DDE} = 3.0 V to 3.6 V, V_{DDEH} = 4.5 V to 5.5 V, V_{DD33} and V_{DDSYN} = 3.0 V to 3.6 V, T_A = T_L to T_H.

² Up to the maximum frequency rating of the device (refer to Table 1). The f_{sys} speed is the nominal maximum frequency.

Electrical Characteristics

4.11.2 Pad AC Specifications

Table 28. Pad AC Specifications ($V_{DDEH} = 5.0$ V, $V_{DDE} = 3.3$ V)¹

Spec	Pad	SRC/DSC	Out Delay ^{2,4} $L \rightarrow H/H \rightarrow L$ (ns)	Rise/Fall ^{3,4} (ns)	Load Drive (pF)
1	Medium ⁵	00	152/165	70/74	50
2			205/220	96/96	200
3		01	28/34	12/15	50
4			52/59	28/31	200
5		11	12/12	5.3/5.9	50
6			32/32	22/22	200
7	Fast ⁶	00	2.5	1.2	10
8		01			20
9		10			30
10		11			50
11	Fast with Slew Rate	00	40/40	16/16	50
12			50/50	21/21	200
13		01	13/13	5/5	50
14			19/19	8/8	200
15		10	8/8	2.4/2.4	50
16			12/12	5/5	200
17		11	5/5	1.1/1/1	50
18			8/8	2.6	200
19	Pull Up/Down (3.6 V max)	—	—	7500	50
20	Pull Up/Down (5.25 V max)	—	6000	5000/5000	50

¹ These are worst case values that are estimated from simulation and not tested. The values in the table are simulated at $V_{DD} = 1.02$ V to 1.32 V, $V_{DDE} = 3.0$ V to 3.6 V, $V_{DDEH} = 4.75$ V to 5.25 V, V_{DD33} and $V_{DDSYN} = 3.0$ V to 3.6 V, $T_A = T_L$ to T_H .

² This parameter is supplied for reference and is not guaranteed by design and not tested.

³ This parameter is guaranteed by characterization before qualification rather than 100% tested.

⁴ Delay and rise/fall are measured to 20% or 80% of the respective signal.

⁵ Out delay is shown in [Figure 7](#). Add a maximum of one system clock to the output delay for delay with respect to system clock.

⁶ Out delay is shown in [Figure 7](#). Add a maximum of one system clock to the output delay for delay with respect to system clock.

Table 29. Derated Pad AC Specifications ($V_{DDEH} = 3.3$ V)¹

Spec	Pad	SRC/DSC	Out Delay ^{2,3} $L \rightarrow H/H \rightarrow L$ (ns)	Rise/Fall ^{4,3} (ns)	Load Drive (pF)
1	Medium ⁵	00	200/210	86/86	50
2			270/285	120/120	200
3		01	37/45	15.5/19	50
4			69/82	38/43	200
5		11	18/17	7.6/8.5	50
6			46/49	30/34	200

- 1 These are worst case values that are estimated from simulation and not tested. The values in the table are simulated at $V_{DD} = 1.08\text{ V}$ to 1.32 V , $V_{DDE} = 3.0\text{ V}$ to 3.6 V , $V_{DDEH} = 3.0\text{ V}$ to 3.6 V , V_{DD33} and $V_{DDSYN} = 3.0\text{ V}$ to 3.6 V , $T_A = T_L$ to T_H .
- 2 This parameter is supplied for reference and is not guaranteed by design and not tested.
- 3 Delay and rise/fall are measured to 20% or 80% of the respective signal.
- 4 This parameter is guaranteed by characterization before qualification rather than 100% tested.
- 5 Out delay is shown in [Figure 7](#). Add a maximum of one system clock to the output delay for delay with respect to system clock.

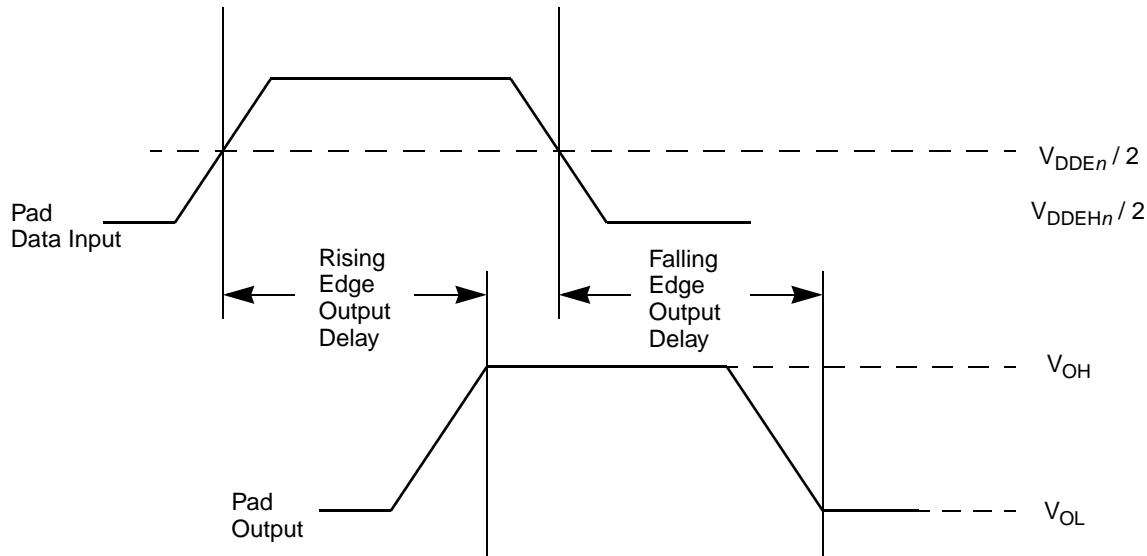


Figure 7. Pad Output Delay

4.12 AC Timing

4.12.1 Generic Timing Diagrams

The generic timing diagrams in [Figure 8](#) and [Figure 9](#) apply to all I/O pins with pad types F and MH. See [Table 38](#) for the pad type for each pin.

Electrical Characteristics

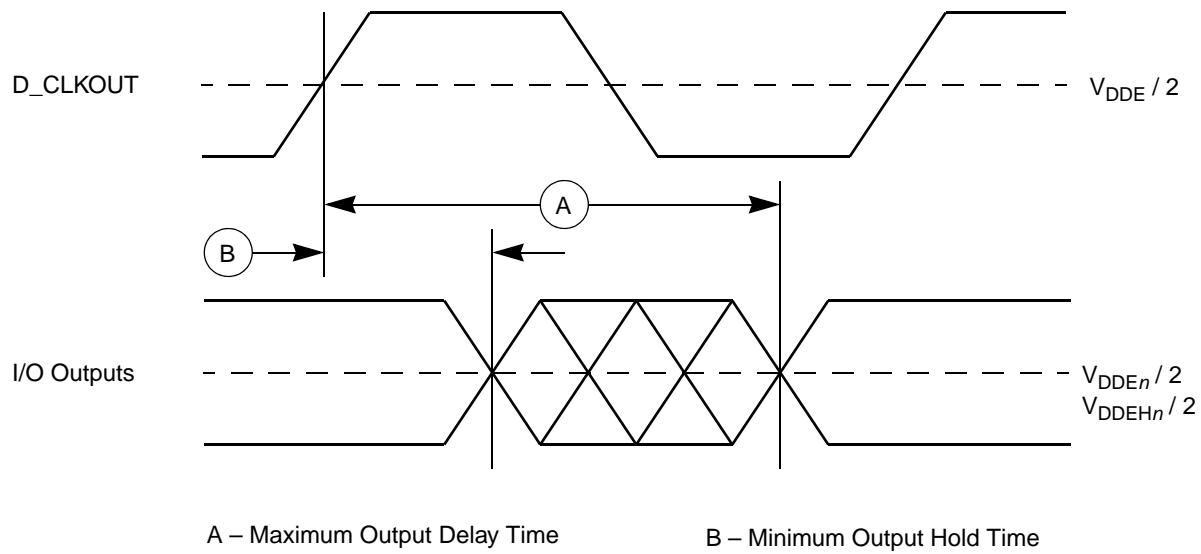


Figure 8. Generic Output Delay/Hold Timing

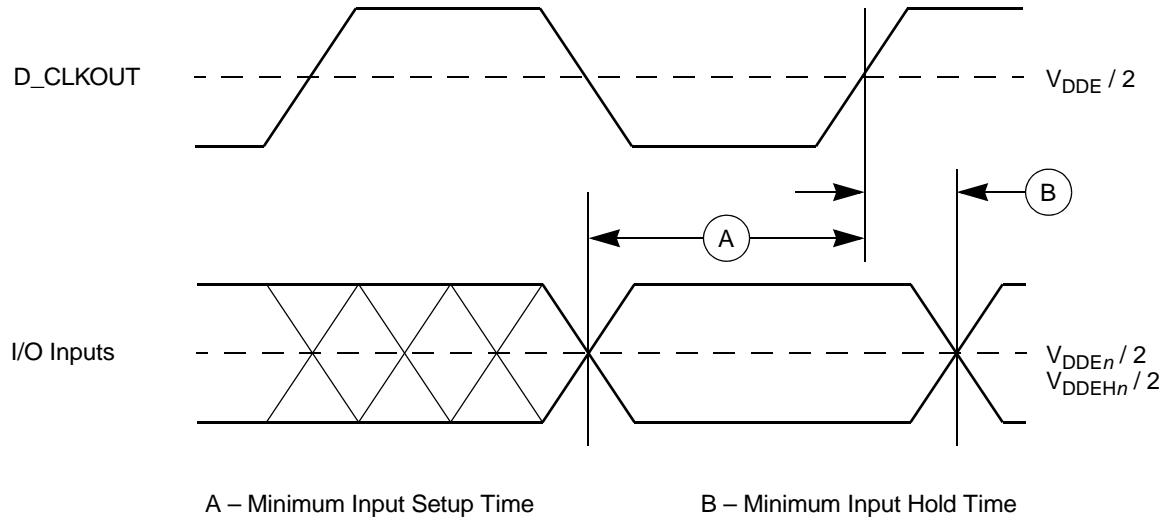


Figure 9. Generic Input Setup/Hold Timing

4.12.2 Reset and Configuration Pin Timing

Table 30. Reset and Configuration Pin Timing¹

Spec	Characteristic	Symbol	Min	Max	Unit
1	RESET Pulse Width	t_{RPW}	10	—	t_{cyc}^2
2	RESET Glitch Detect Pulse Width	t_{GPW}	2	—	t_{cyc}^2
3	PLLCFG, BOOTCFG, WKPCFG Setup Time to RSTOUT Valid	t_{RCSU}	10	—	t_{cyc}^2
4	PLLCFG, BOOTCFG, WKPCFG Hold Time to RSTOUT Valid	t_{RCH}	0	—	t_{cyc}^2

¹ Reset timing specified at: $V_{DDEH} = 3.0\text{ V}$ to 5.25 V , $V_{DD} = 1.08\text{ V}$ to 1.32 V , $T_A = T_L$ to T_H .

² See Notes on t_{cyc} on Table 27.

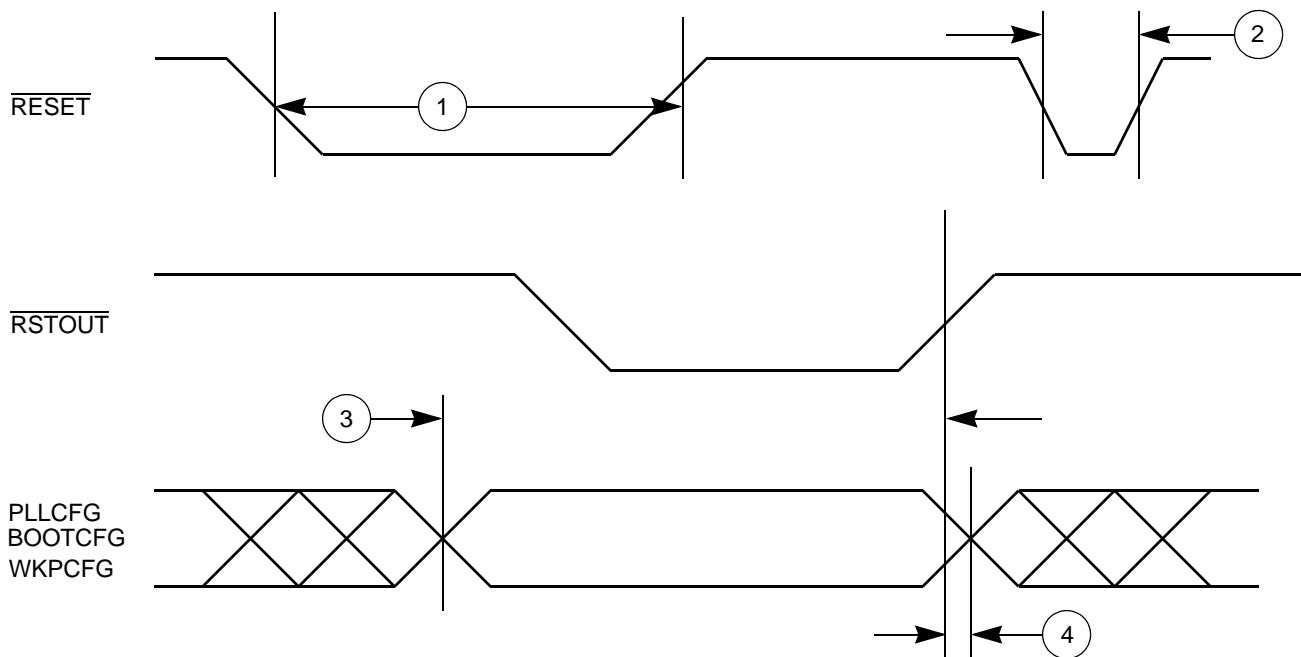


Figure 10. Reset and Configuration Pin Timing

4.12.3 IEEE 1149.1 Interface Timing

Table 31. JTAG Pin AC Electrical Characteristics¹

Spec	Characteristic	Symbol	Min	Max	Unit
1	TCK Cycle Time	t_{JCYC}	100	—	ns
2	TCK Clock Pulse Width (Measured at $V_{DDE} / 2$)	t_{JDC}	40	60	ns
3	TCK Rise and Fall Times (40%–70%)	$t_{TCKRISE}$	—	3	ns
4	TMS, TDI Data Setup Time	t_{TMSS}, t_{TDIS}	5	—	ns
5	TMS, TDI Data Hold Time	t_{TMSH}, t_{TDIH}	25	—	ns
6	TCK Low to TDO Data Valid	t_{TDOV}	—	10	ns
7	TCK Low to TDO Data Invalid	t_{TDOI}	0	—	ns
8	TCK Low to TDO High Impedance	t_{TDOHZ}	—	20	ns
9	JCOMP Assertion Time	t_{JCMPPW}	100	—	ns
10	JCOMP Setup Time to TCK Low	t_{JCMPS}	40	—	ns
11	TCK Falling Edge to Output Valid	t_{BSDV}	—	50	ns

Electrical Characteristics

Table 31. JTAG Pin AC Electrical Characteristics¹ (continued)

Spec	Characteristic	Symbol	Min	Max	Unit
12	TCK Falling Edge to Output Valid out of High Impedance	t_{BSDVZ}	—	50	ns
13	TCK Falling Edge to Output High Impedance	t_{BSDHZ}	—	50	ns
14	Boundary Scan Input Valid to TCK Rising Edge	t_{BSDST}	50	—	ns
15	TCK Rising Edge to Boundary Scan Input Invalid	t_{BSDHT}	50	—	ns

¹ JTAG timing specified at $V_{DD} = 1.08\text{ V}$ to 1.32 V , $V_{DDE} = 3.0\text{ V}$ to 3.6 V , V_{DD33} and $V_{DDSYN} = 3.0\text{ V}$ to 3.6 V , $T_A = T_L$ to T_H , and $C_L = 30\text{ pF}$ with DSC = 0b10, SRC = 0b00. These specifications apply to JTAG boundary scan only. See [Table 32](#) for functional specifications.

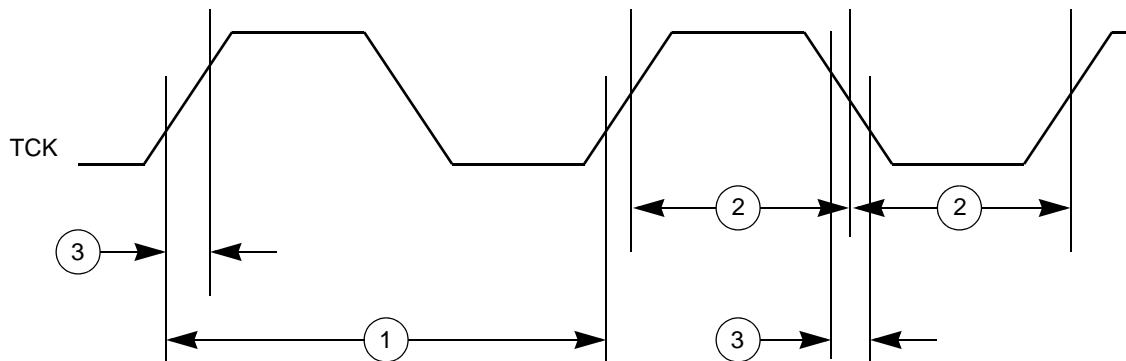


Figure 11. JTAG Test Clock Input Timing

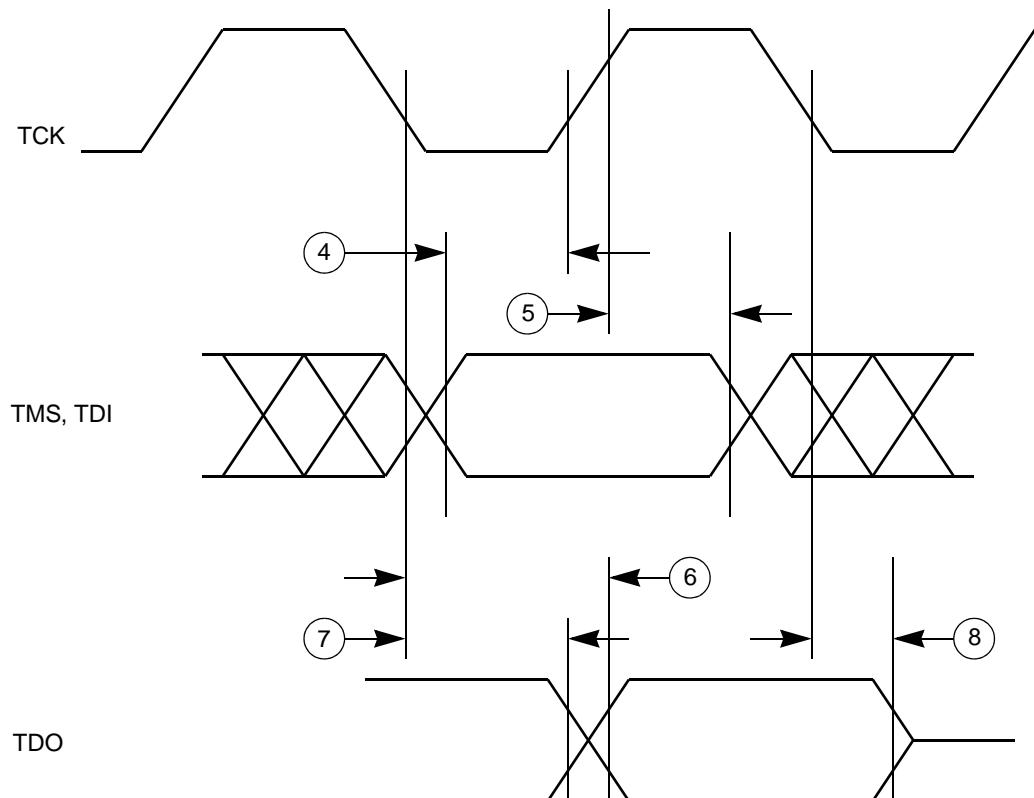


Figure 12. JTAG Test Access Port Timing

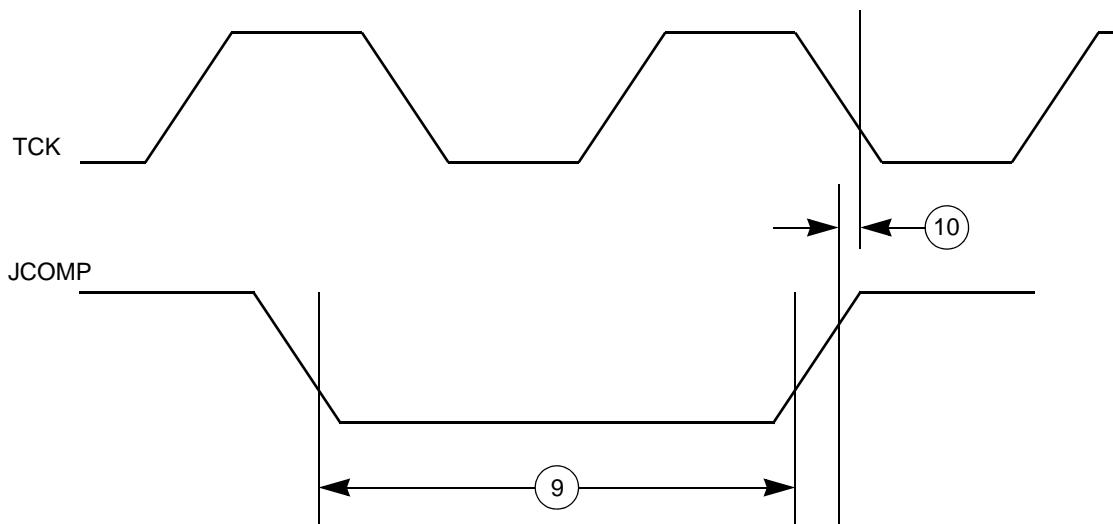


Figure 13. JTAG JCOMP Timing

Electrical Characteristics

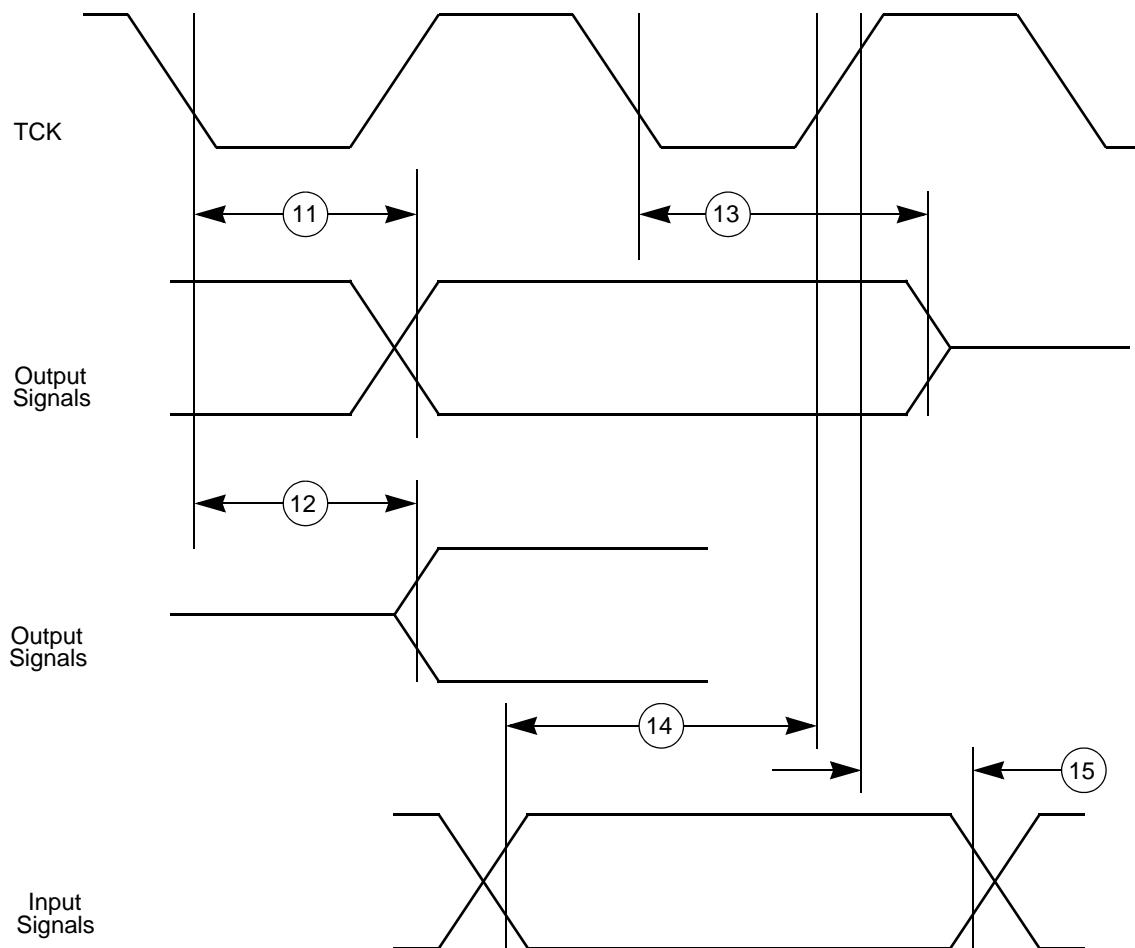


Figure 14. JTAG Boundary Scan Timing

4.12.4 Nexus Timing

Table 32. Nexus Debug Port Timing¹

Spec	Characteristic	Symbol	Min	Max	Unit
1	MCKO Cycle Time	t_{MCYC}	2^2	8	t_{CYC}
2	MCKO Duty Cycle	t_{MDC}	40	60	%
3	MCKO Low to MDO Data Valid ³	t_{MDOV}	-0.1	0.2	t_{MCYC}
4	MCKO Low to MSEO Data Valid ³	t_{MSEOV}	-0.1	0.2	t_{MCYC}
5	MCKO Low to EVTO Data Valid ³	t_{EVTOV}	-0.1	0.2	t_{MCYC}
6	\overline{EVTI} Pulse Width	$t_{EVТИPW}$	4.0	—	t_{TCYC}
7	\overline{EVTO} Pulse Width	t_{EVTOPW}	1	—	t_{MCYC}
8	TCK Cycle Time	t_{TCYC}	4^4	—	t_{CYC}
9	TCK Duty Cycle	t_{TDC}	40	60	%
10	TDI, TMS Data Setup Time	t_{NTDIS}, t_{NTMSS}	8	—	ns

Table 32. Nexus Debug Port Timing¹ (continued)

Spec	Characteristic	Symbol	Min	Max	Unit
11	TDI, TMS Data Hold Time	t_{NTDIH}, t_{NTMSH}	5	—	ns
12	TCK Low to TDO Data Valid	t_{NTDOV}	0	10	ns
13	\overline{RDY} Valid to MCKO ⁵	—	—	—	—
14	TDO hold time after TCLK low	t_{NTDOH}	1	—	ns

¹ All Nexus timing relative to MCKO is measured from 50% of MCKO and 50% of the respective signal. Nexus timing specified at $V_{DD} = 1.08$ V to 1.32 V, $V_{DDE} = 3.0$ V to 3.6 V, V_{DD33} and $V_{DDSYN} = 3.0$ V to 3.6 V, $T_A = T_L$ to T_H , and $C_L = 30$ pF with DSC = 0b10.

² The Nexus AUX port runs up to 82 MHz (pending characterization). Set NPC_PCR[MCKO_DIV] to correct division depending on the system frequency, not to exceed maximum Nexus AUX port frequency.

³ MDO, \overline{MSEO} , and \overline{EVTO} data is held valid until next MCKO low cycle.

⁴ Lower frequency is required to be fully compliant to standard.

⁵ The \overline{RDY} pin timing is asynchronous to MCKO. The timing is guaranteed by design to function correctly.

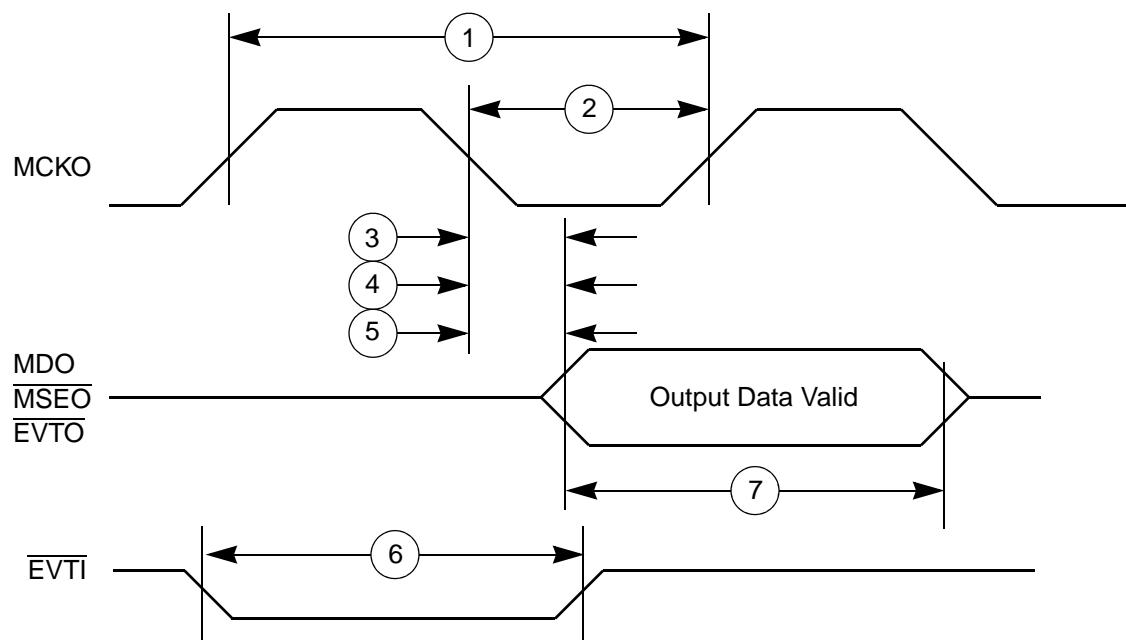


Figure 15. Nexus Timings

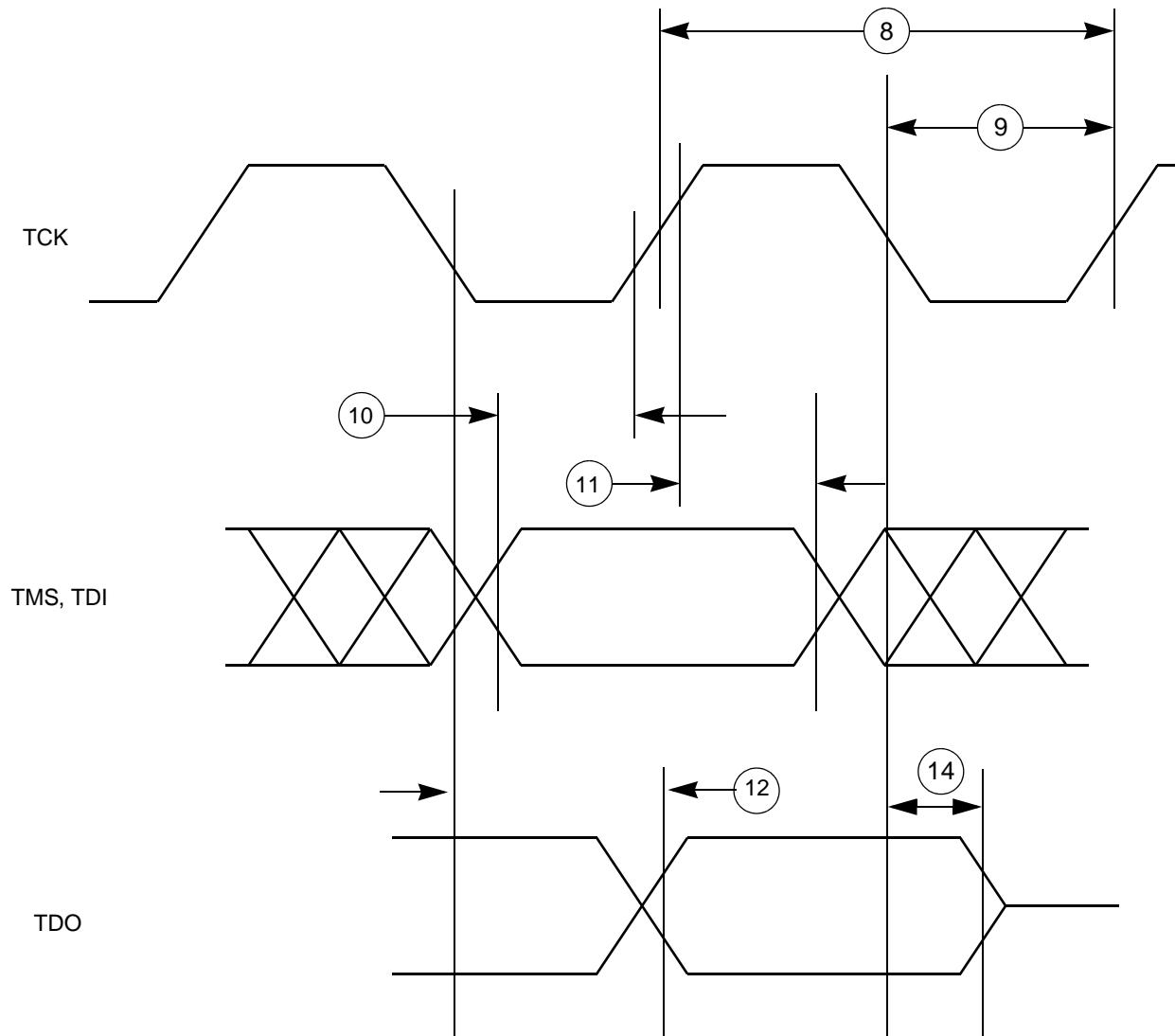


Figure 16. Nexus TCK, TDI, TMS, TDO Timing

4.12.5 External Bus Interface (EBI) Timing

Table 33. Bus Operation Timing¹

Spec	Characteristic	Symbol	66 MHz (Ext. Bus Freq) ^{2 3}		Unit	Notes
			Min	Max		
1	D_CLKOUT Period	t_C	15.2	—	ns	Signals are measured at 50% V_{DDE} .

Table 33. Bus Operation Timing¹ (continued)

Spec	Characteristic	Symbol	66 MHz (Ext. Bus Freq) ^{2 3}		Unit	Notes
			Min	Max		
2	D_CLKOUT Duty Cycle	t _{CDC}	45%	55%	t _C	
3	D_CLKOUT Rise Time	t _{CRT}	—	— ⁴	ns	
4	D_CLKOUT Fall Time	t _{CFT}	—	— ⁴	ns	
5	D_CLKOUT Posedge to Output Signal Invalid or High Z (Hold Time) D_ADD[9:30] D_BDIP D_CS[0:3] D_DAT[0:15] D_OE D_RD_WR D_TA D_TS D_WE[0:3]/D_BE[0:3]	t _{COH}	1.0/1.5	—	ns	Hold time selectable via SIU_ECCR[EBTS] bit: EBTS = 0: 1.0 ns EBTS = 1: 1.5 ns
6	D_CLKOUT Posedge to Output Signal Valid (Output Delay) D_ADD[9:30] D_BDIP D_CS[0:3] D_DAT[0:15] D_OE D_RD_WR D_TA D_TS D_WE[0:3]/D_BE[0:3]	t _{COV}	—	8.5/9.0	ns	Output valid time selectable via SIU_ECCR[EBTS] bit: EBTS = 0: 8.5 ns EBTS = 1: 9.0 ns
7	Input Signal Valid to D_CLKOUT Posedge (Setup Time) D_ADD[9:30] D_DAT[0:15] D_RD_WR D_TA D_TS	t _{CIS}	5.0/4.5	—	ns	Input setup time selectable via SIU_ECCR[EBTS] bit: EBTS = 0; 5.0ns EBTS = 1; 4.5ns
8	D_CLKOUT Posedge to Input Signal Invalid (Hold Time) D_ADD[9:30] D_DAT[0:15] D_RD_WR D_TA D_TS	t _{CIH}	1.0	—	ns	
9	D_ALE Pulse Width	t _{APW}	6.5	—	ns	The timing is for Asynchronous external memory system.
10	D_ALE Negated to Address Invalid	t _{AAI}	2.0/1.0 ⁵	—	ns	The timing is for Asynchronous external memory system. ALE is measured at 50% of VDDE.

Electrical Characteristics

- 1 EBI timing specified at $V_{DD} = 1.08\text{ V}$ to 1.32 V , $V_{DDE} = 3.0\text{ V}$ to 3.6 V , V_{DD33} and $V_{DDSYN} = 3.0\text{ V}$ to 3.6 V , $T_A = T_L$ to T_H , and $C_L = 30\text{ pF}$ with DSC = 0b10.
- 2 Speed is the nominal maximum frequency. Max speed is the maximum speed allowed including frequency modulation (FM).
- 3 Depending on the internal bus speed, set the SIU_ECCR[EBDF] bits correctly not to exceed maximum external bus frequency. The maximum external bus frequency is 66 MHz.
- 4 Refer to Fast pad timing in [Table 28](#) and [Table 29](#).
- 5 ALE hold time spec is temperature dependant. 1.0ns spec applies for temperature range -40 to 0 C. 2.0ns spec applies to temperatures > 0 C. This spec has no dependency on SIU_ECCR[EBTS] bit.

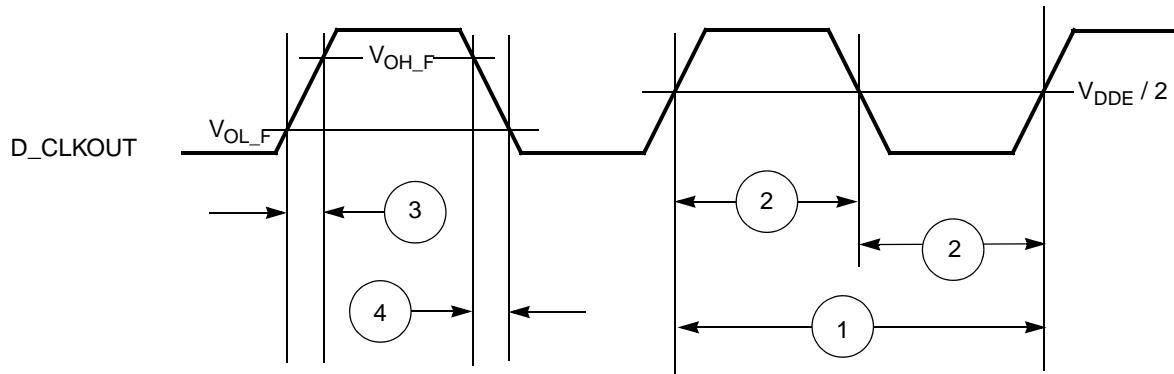
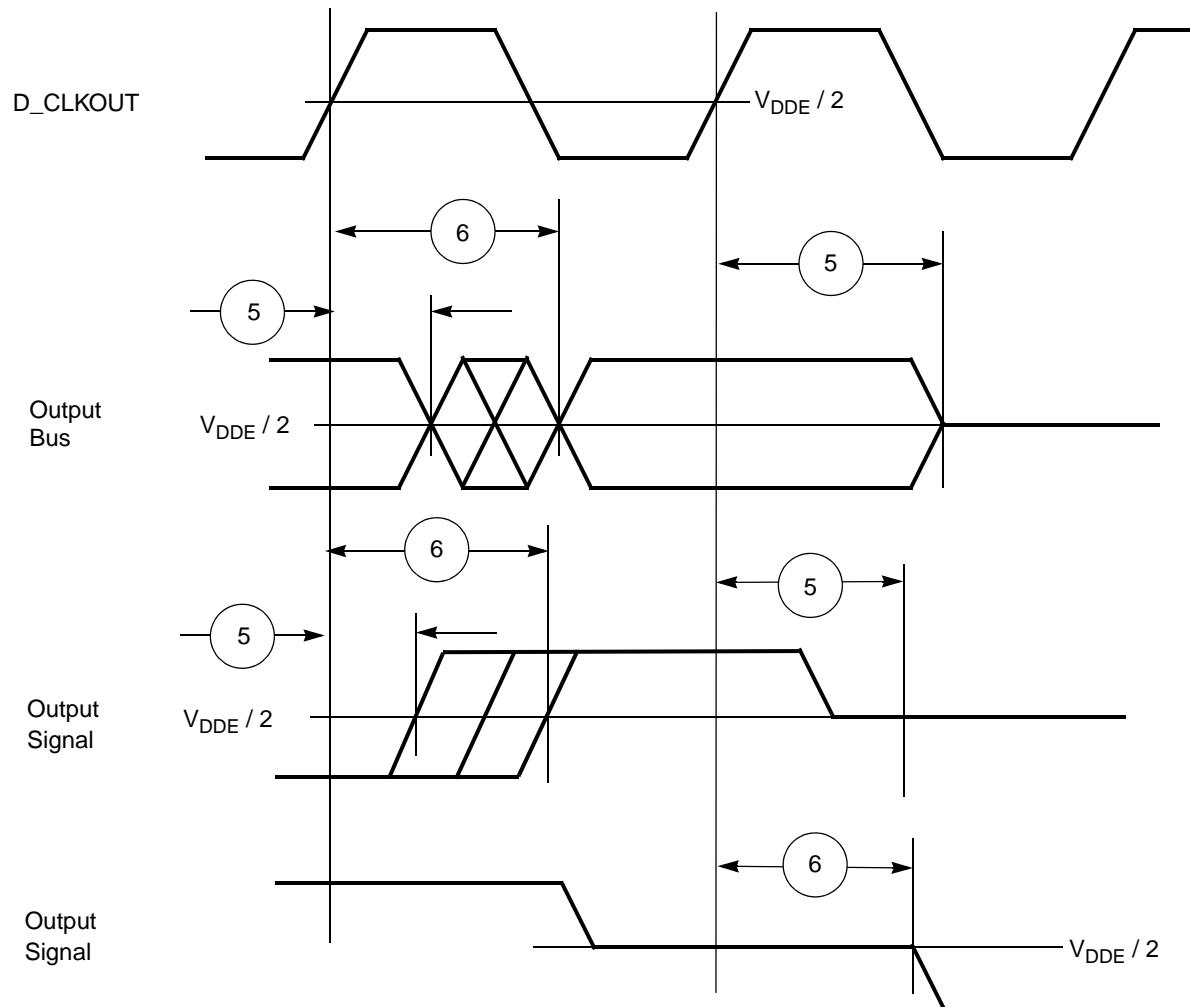


Figure 17. D_CLKOUT Timing

**Figure 18. Synchronous Output Timing**

Electrical Characteristics

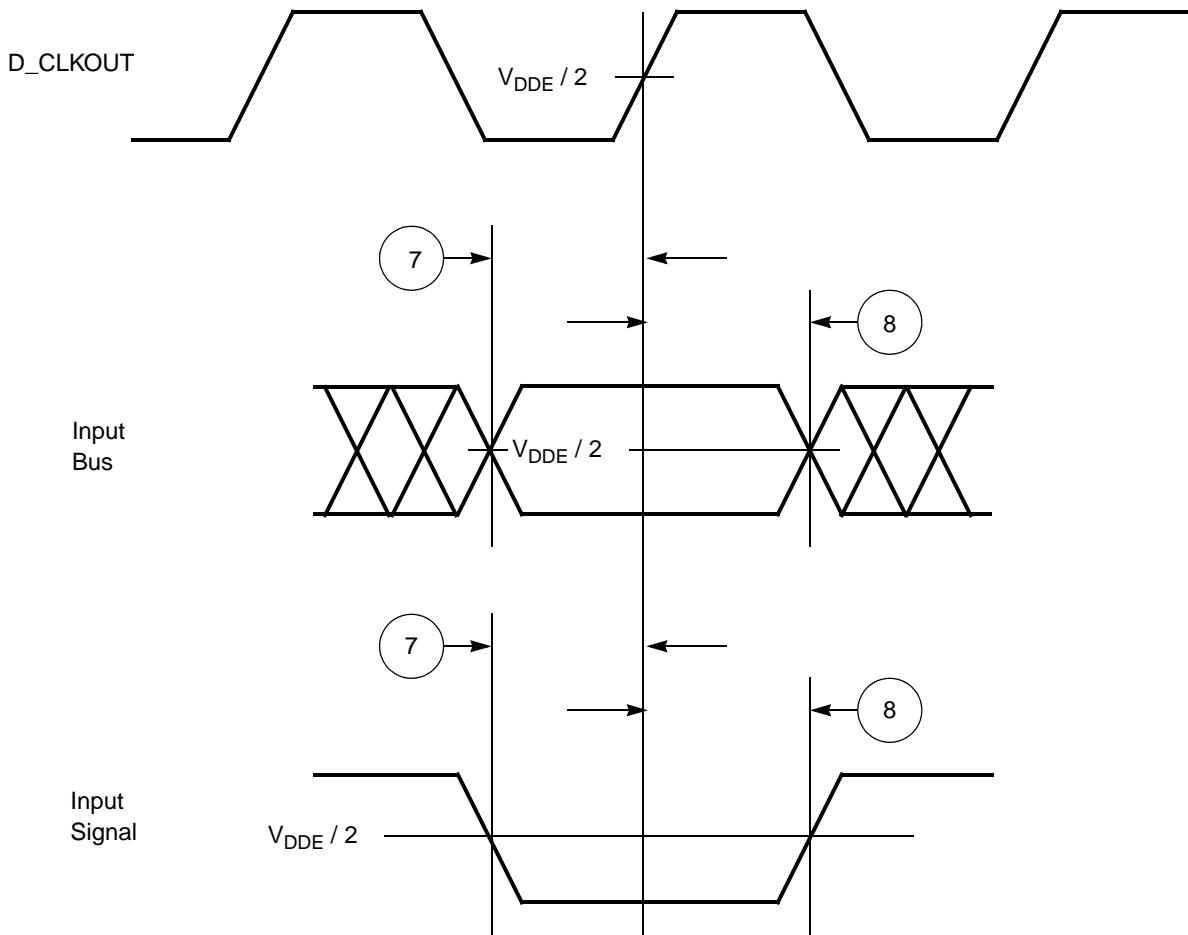


Figure 19. Synchronous Input Timing

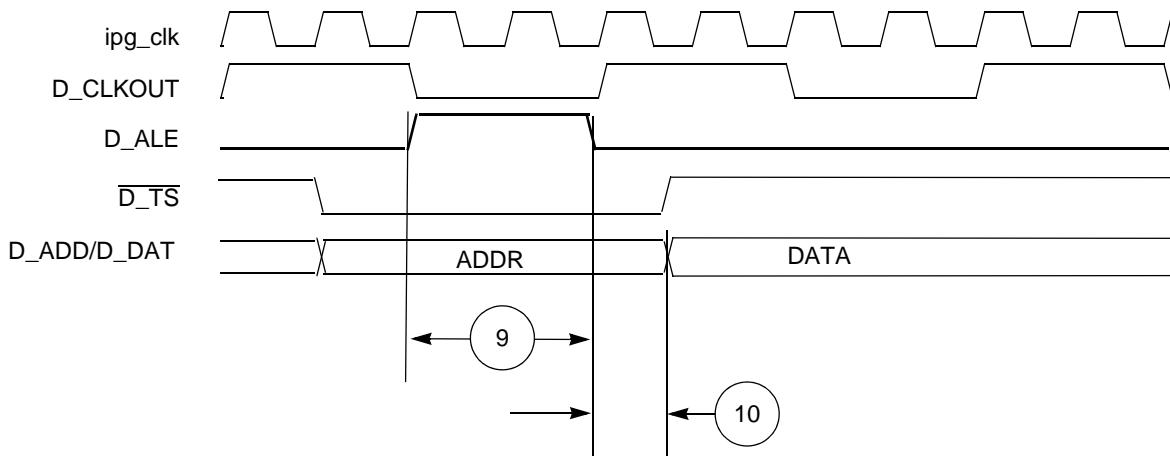


Figure 20. ALE Signal Timing

4.12.6 External Interrupt Timing (IRQ Pin)

Table 34. External Interrupt Timing¹

Spec	Characteristic	Symbol	Min	Max	Unit
1	IRQ Pulse Width Low	t_{IPWL}	3	—	t_{cyc}^2
2	IRQ Pulse Width High	t_{IPWH}	3	—	t_{cyc}^2
3	IRQ Edge to Edge Time ³	t_{ICYC}	6	—	t_{cyc}^2

¹ IRQ timing specified at $V_{DD} = 1.08\text{ V}$ to 1.32 V , $V_{DDEH} = 3.0\text{ V}$ to 5.5 V , V_{DD33} and $V_{DDSYN} = 3.0\text{ V}$ to 3.6 V , $T_A = T_L$ to T_H .

² See Notes on t_{cyc} Table 27.

³ Applies when IRQ pins are configured for rising edge or falling edge events, but not both.

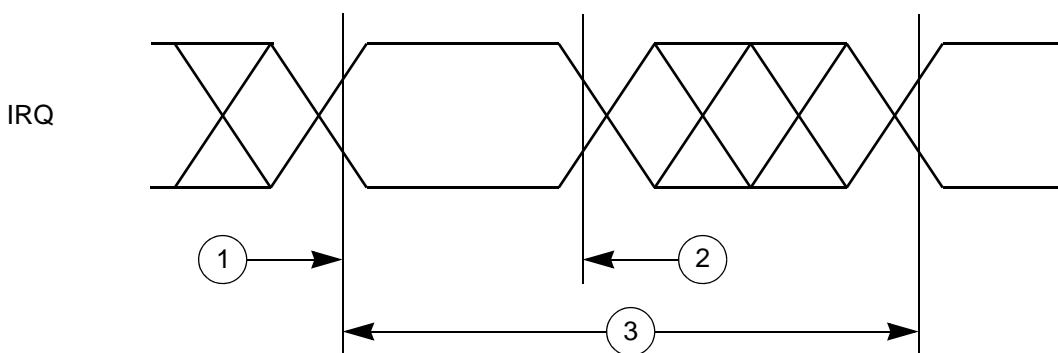


Figure 21. External Interrupt Timing

4.12.7 eTPU Timing

Table 35. eTPU Timing¹

Spec	Characteristic	Symbol	Min	Max	Unit
1	eTPU Input Channel Pulse Width	t_{ICPW}	4	—	t_{cyc}^2
2	eTPU Output Channel Pulse Width	t_{OCPW}	1 ³	—	t_{cyc}^2

¹ eTPU timing specified at $V_{DD} = 1.08\text{ V}$ to 1.32 V , $V_{DDEH} = 3.0\text{ V}$ to 5.5 V , V_{DD33} and $V_{DDSYN} = 3.0\text{ V}$ to 3.6 V , $T_A = T_L$ to T_H , and $C_L = 200\text{ pF}$ with SRC = 0b00.

² See Notes on t_{cyc} Table 27.

³ This specification does not include the rise and fall times. When calculating the minimum eTPU pulse width, include the rise and fall times defined in the slew rate control fields (SRC) of the pad configuration registers (PCR).

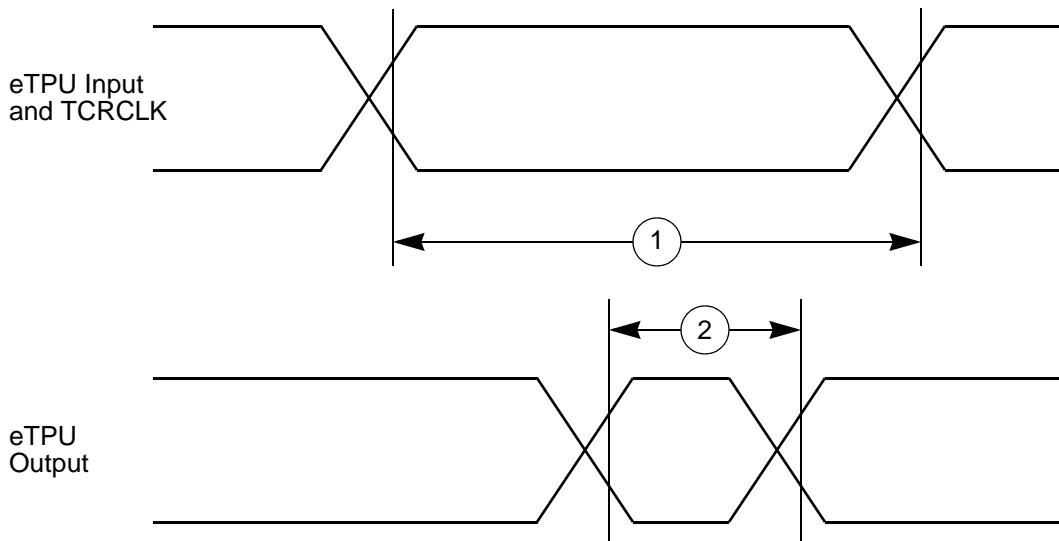


Figure 22. eTPU Timing

4.12.8 eMIOS Timing

Table 36. eMIOS Timing¹

Spec	Characteristic	Symbol	Min	Max	Unit
1	eMIOS Input Pulse Width	t_{MIPW}	4	—	t_{cyc}^2
2	eMIOS Output Pulse Width	t_{MOPW}	1 ³	—	t_{cyc}^2

¹ eMIOS timing specified at $V_{DD} = 1.08$ V to 1.32 V, $V_{DDEH} = 3.0$ V to 5.5 V, V_{DD33} and $V_{DDSYN} = 3.0$ V to 3.6 V, $T_A = T_L$ to T_H , and $C_L = 50$ pF with SRC = 0b00.

² See Notes on t_{cyc} on Table 27.

³ This specification does not include the rise and fall times. When calculating the minimum eMIOS pulse width, include the rise and fall times defined in the slew rate control fields (SRC) of the pad configuration registers (PCR).

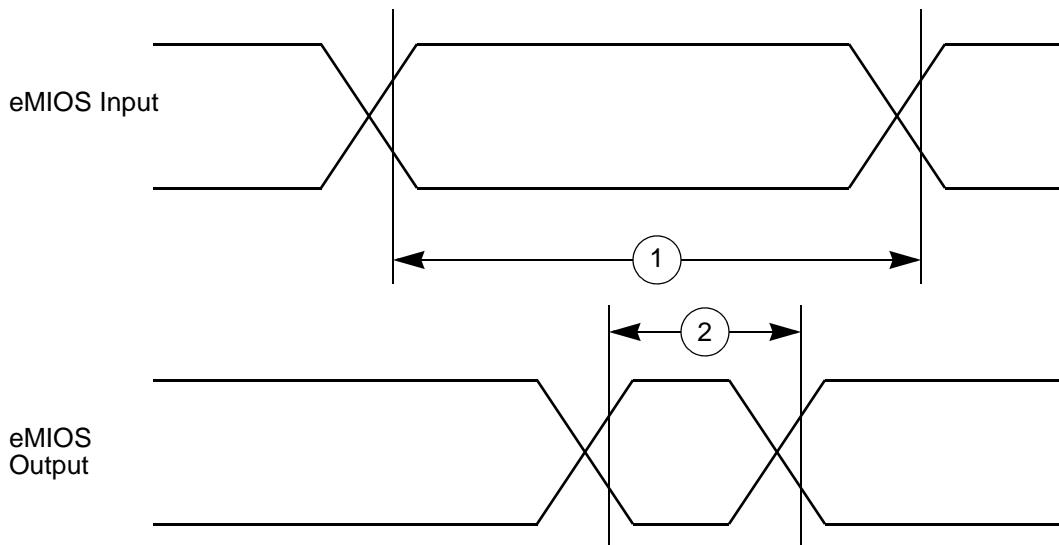


Figure 23. eMOS Timing

4.12.9 DSPI Timing

Table 37. DSPI Timing^{1,2}

Spec	Characteristic	Symbol	Peripheral Bus Freq: 92 MHz		Unit
			Min	Max	
1	DSPI Cycle Time ^{3, 4} Master (MTFE = 0) Slave (MTFE = 0) Master (MTFE = 1) Slave (MTFE = 1)	t_{SCK}	23.8	1800	ns
2	PCS to SCK Delay ⁵	t_{CSC}	12	—	ns
3	After SCK Delay ⁶	t_{ASC}	12	—	ns
4	SCK Duty Cycle	t_{SDC}	$0.4 * t_{SCK}$	$0.6 * t_{SCK}$	ns
5	Slave Access Time (SS active to SOUT valid)	t_A	—	25	ns
6	Slave SOUT Disable Time (SS inactive to SOUT High-Z or invalid)	t_{DIS}	—	25	ns
7	PCSx to PCSS time	t_{PCSC}	4	—	ns
8	PCSS to PCSx time	t_{PASC}	5	—	ns

Electrical Characteristics

Table 37. DSPI Timing^{1,2} (continued)

Spec	Characteristic	Symbol	Peripheral Bus Freq: 92 MHz		Unit
			Min	Max	
9	Data Setup Time for Inputs Master (MTFE = 0) Slave Master (MTFE = 1, CPHA = 0) ⁷ Master (MTFE = 1, CPHA = 1)	t _{SUI}	27 10 7 27	— — — —	ns ns ns ns
10	Data Hold Time for Inputs Master (MTFE = 0) Slave Master (MTFE = 1, CPHA = 0) ⁷ Master (MTFE = 1, CPHA = 1)	t _{HI}	-3 7 12 -3	— — — —	ns ns ns ns
11	Data Valid (after SCK edge) Master (MTFE = 0) Slave Master (MTFE = 1, CPHA = 0) Master (MTFE = 1, CPHA = 1) Master (LVDS)	t _{SUO}	— — — — —	10 30 20 10 5	ns ns ns ns ns
12	Data Hold Time for Outputs Master (MTFE = 0) Slave Master (MTFE = 1, CPHA = 0) Master (MTFE = 1, CPHA = 1) Master (LVDS)	t _{HO}	-6 2.5 3 -7 -5	— — — — —	ns ns ns ns ns

¹ DSPI timing specified at V_{DD} = 1.08 V to 1.32 V, V_{DDEH} = 3.0 V to 5.5 V, V_{DD33} and V_{DDSYN} = 3.0 V to 3.6 V, and T_A = T_L to T_H

² Speed is the nominal maximum frequency of platform clock (f_{platf}). Max speed is the maximum speed allowed including frequency modulation (FM).

³ The minimum DSPI Cycle Time restricts the baud rate selection for given system clock rate. These numbers are calculated based on two devices communicating over a DSPI link.

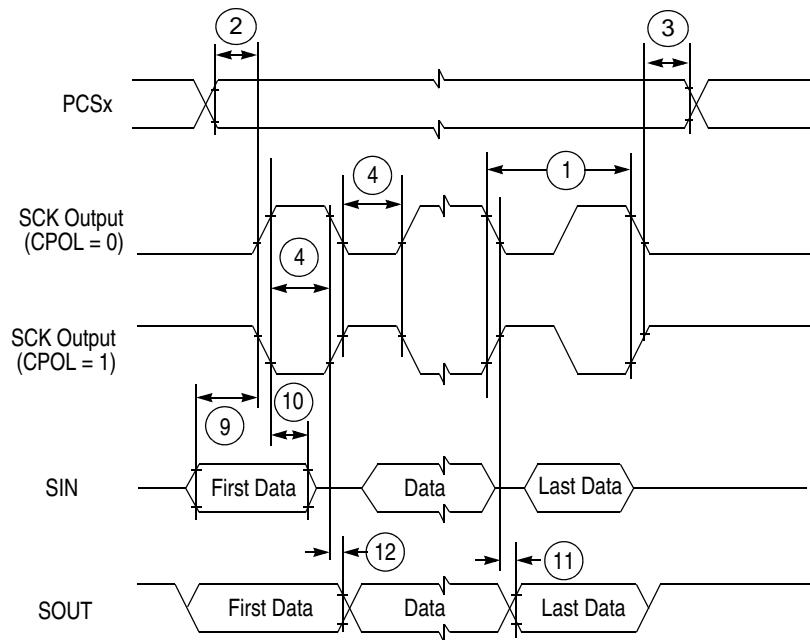
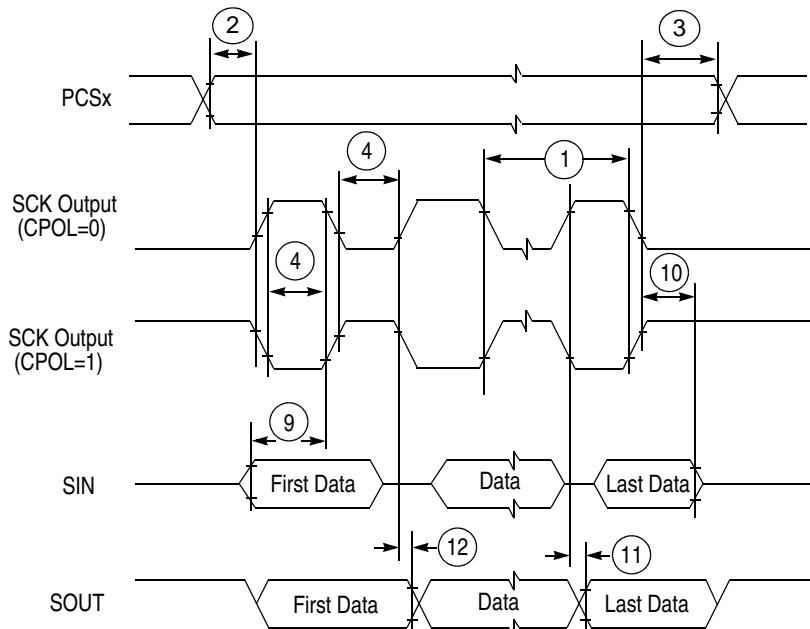
⁴ The actual minimum SCK cycle time is limited by pad performance.

⁵ The maximum value is programmable in DSPI_CTARn[PSSCK] and DSPI_CTARn[CSSCK].

⁶ The maximum value is programmable in DSPI_CTARn[PASC] and DSPI_CTARn[ASC].

⁷ This number is calculated assuming the SMPL_PT bit-field in DSPI_MCR is set to 0b10.

The DSPI in this device can be configured to serialize data to an external device that implements the Microsecond Bus protocol. DSPI pins support 5 V logic levels or Low Voltage Differential Signalling (LVDS) for data and clock signals to improve high speed operation.

**Figure 24. DSPI Classic SPI Timing — Master, CPHA = 0****Figure 25. DSPI Classic SPI Timing — Master, CPHA = 1**

Electrical Characteristics

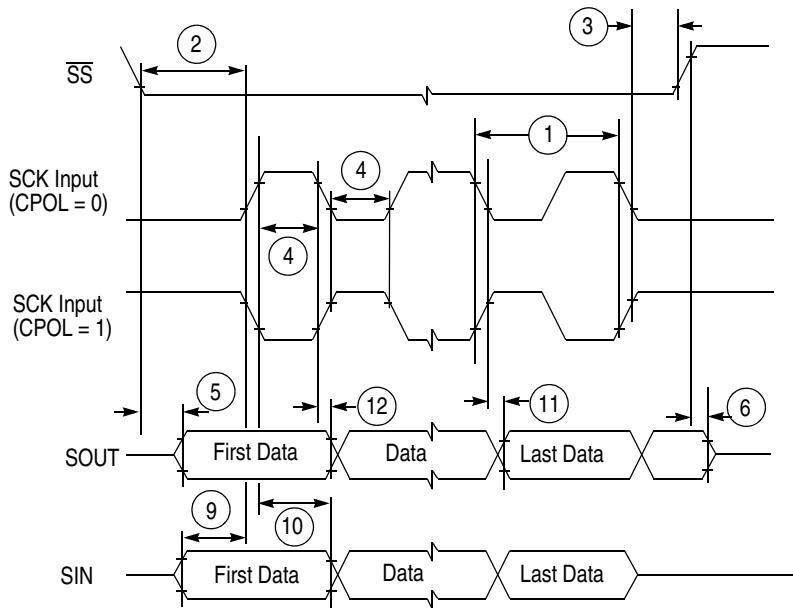


Figure 26. DSPI Classic SPI Timing — Slave, CPHA = 0

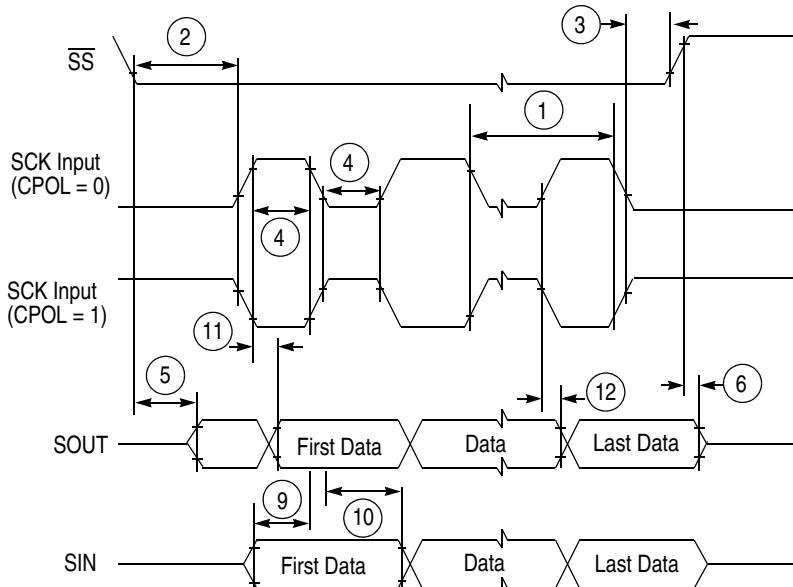


Figure 27. DSPI Classic SPI Timing — Slave, CPHA = 1

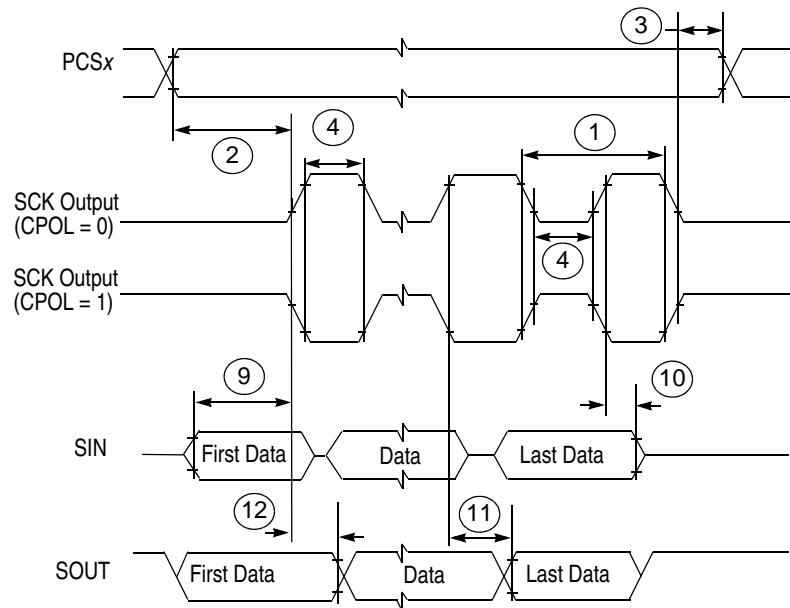


Figure 28. DSPI Modified Transfer Format Timing — Master, CPHA = 0

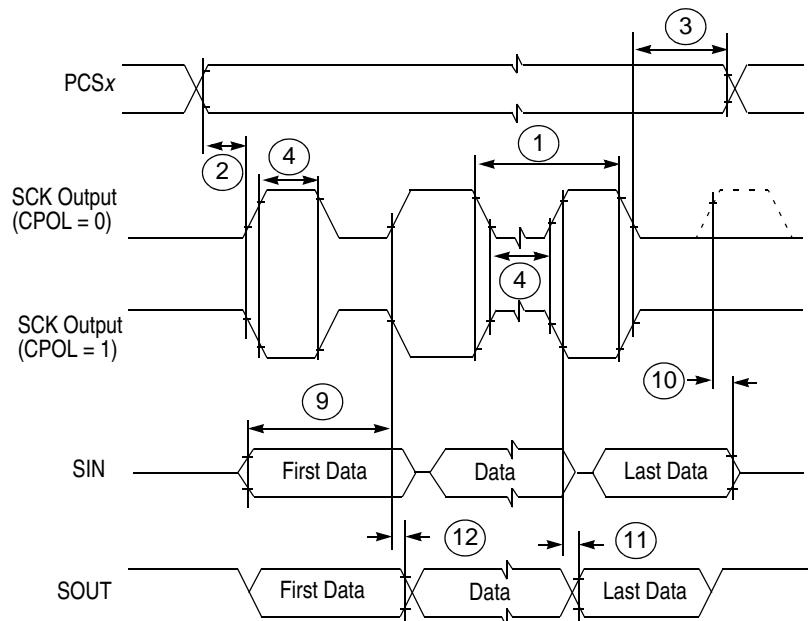


Figure 29. DSPI Modified Transfer Format Timing — Master, CPHA = 1

Electrical Characteristics

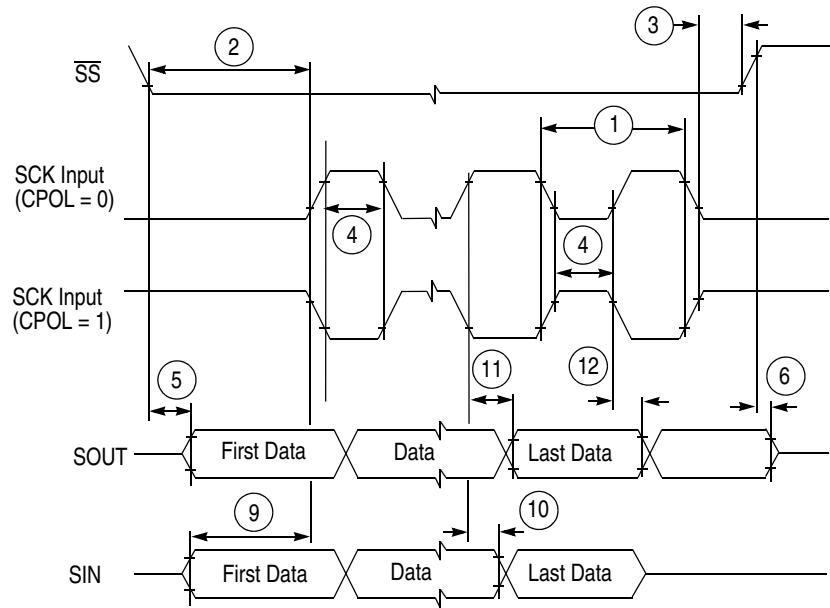


Figure 30. DSPI Modified Transfer Format Timing — Slave, CPHA = 0

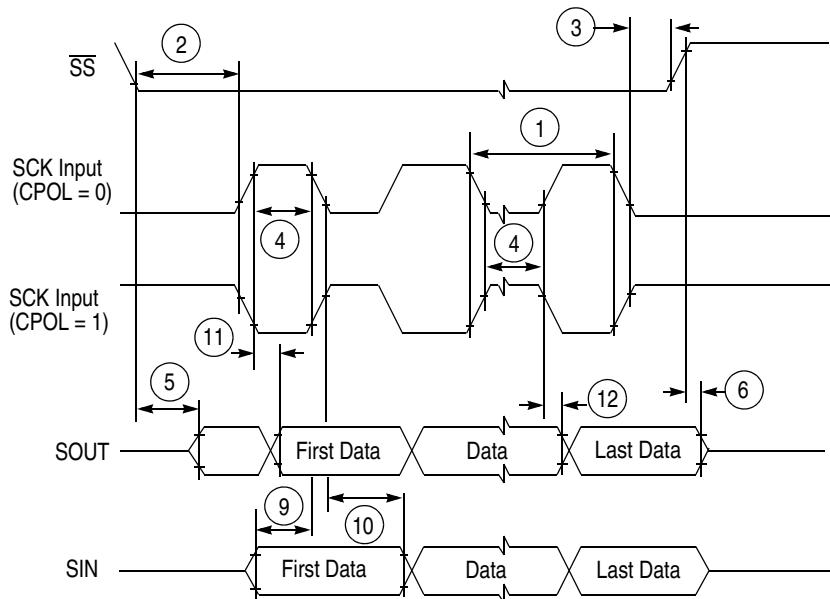


Figure 31. DSPI Modified Transfer Format Timing — Slave, CPHA = 1

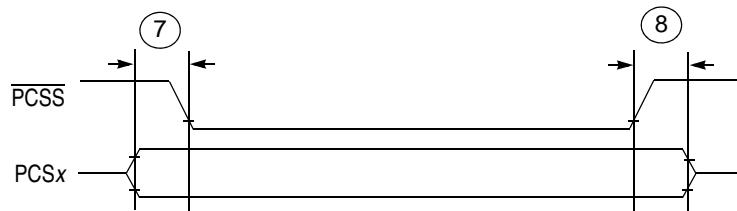


Figure 32. DSPI PCS Strobe ($\overline{\text{PCSS}}$) Timing

5 Package Information

5.1 416-Pin Package

The package drawings of the 416-pin TEPBGA package are shown in [Figure 33](#) and [Figure 34](#).

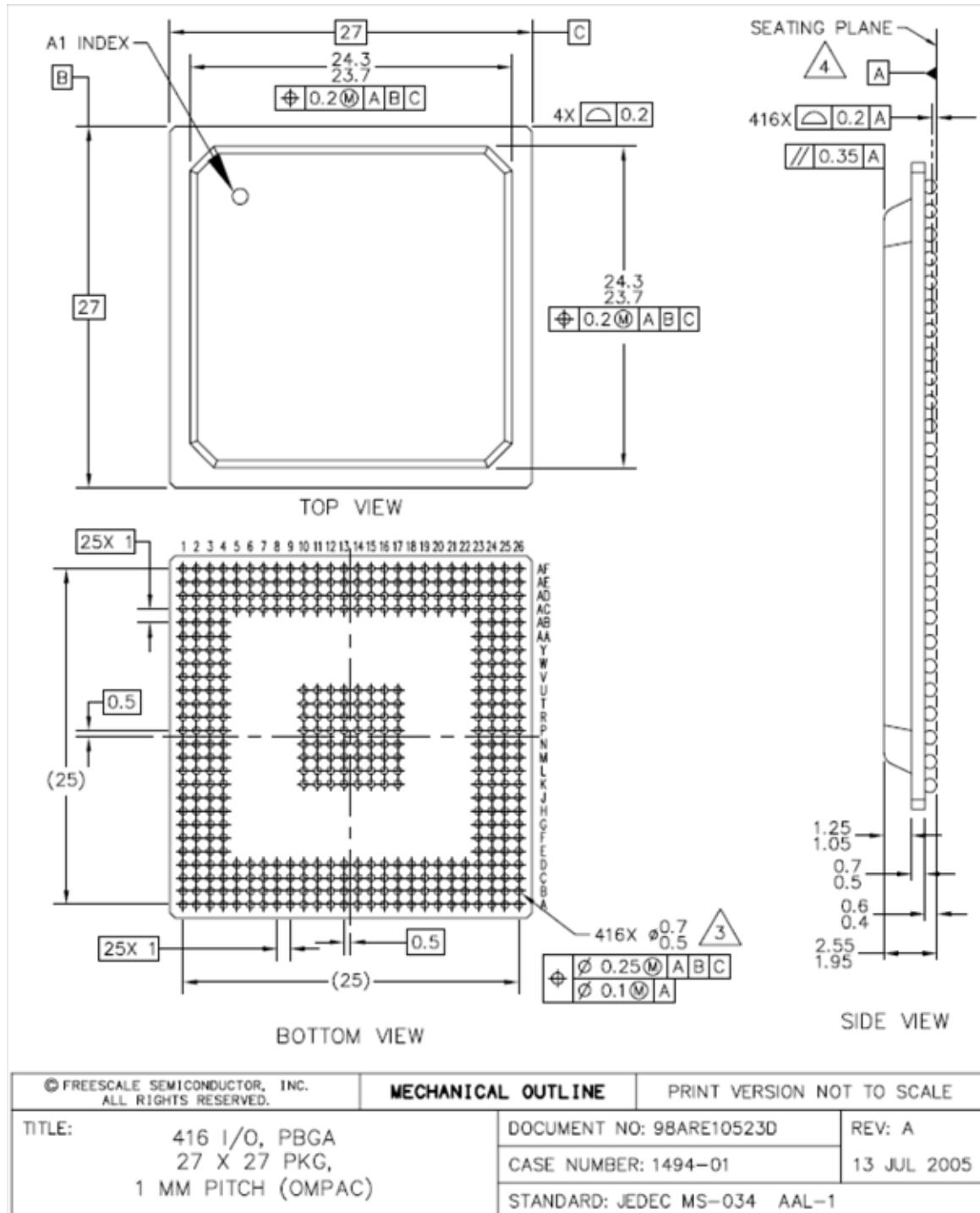


Figure 33. 416 TEPBGA Package (1 of 2)

NOTES:

1. ALL DIMENSIONS IN MILLIMETERS.

2. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.



3. MAXIMUM SOLDER BALL DIAMETER MEASURED PARALLEL TO DATUM A.



4. DATUM A, THE SEATING PLANE, IS DETERMINED BY THE SPHERICAL CROWNS OF THE SOLDER BALLS.

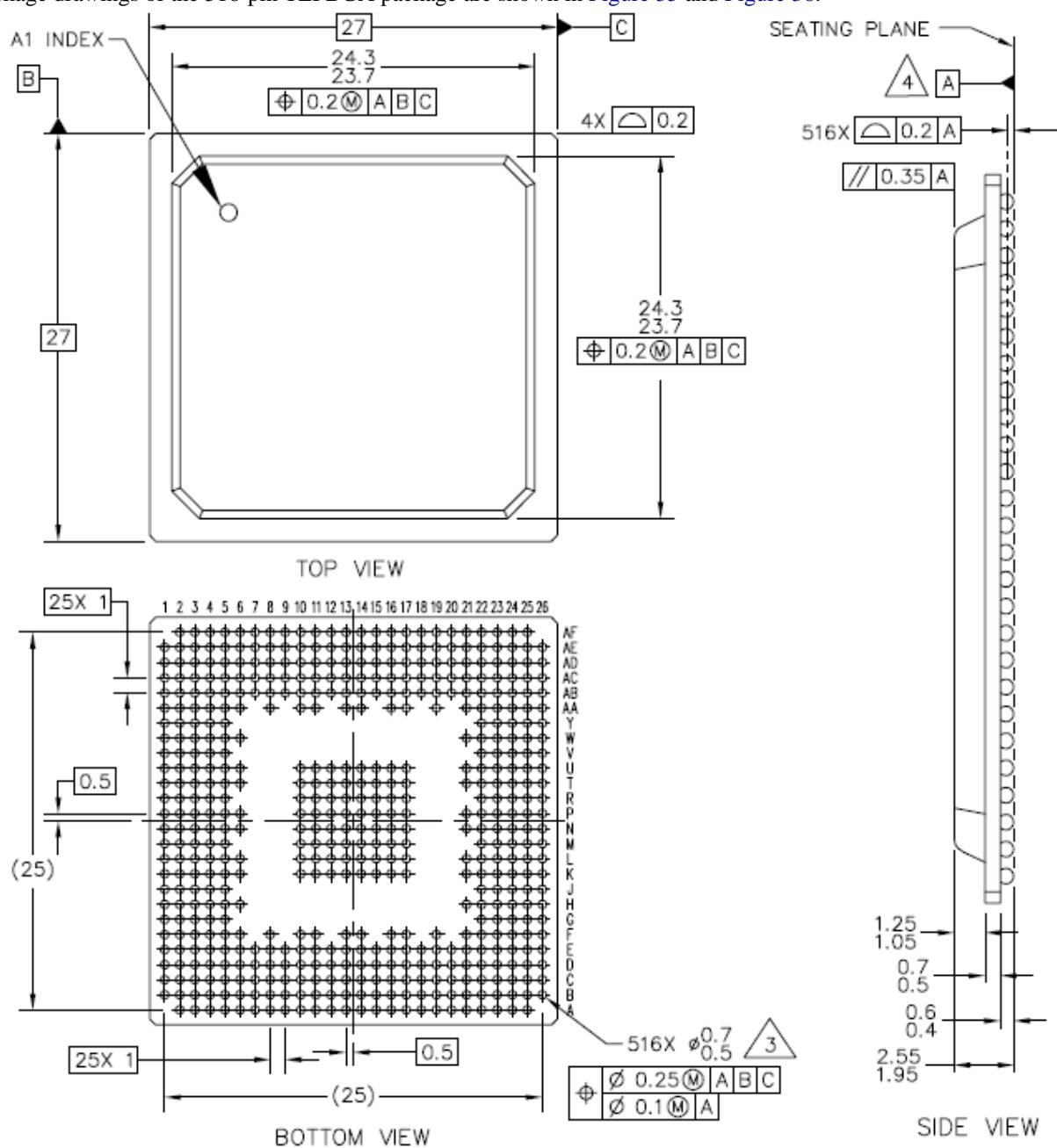
© FREESCALE SEMICONDUCTOR, INC. ALL RIGHTS RESERVED.	MECHANICAL OUTLINE	PRINT VERSION NOT TO SCALE
TITLE: 416 I/O, PBGA 27 X 27 PKG, 1 MM PITCH (OMPAC)	DOCUMENT NO: 98ARE10523D CASE NUMBER: 1494-01 STANDARD: JEDEC MS-034 AAL-1	REV: A 13 JUL 2005

Figure 34. 416 TEPBGA Package (2 of 2)

Package Information

5.2 516-Pin Package

The package drawings of the 516-pin TEPBGA package are shown in [Figure 35](#) and [Figure 36](#).



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TITLE:	516 I/O, PBGA 27 X 27 PKG, 1 MM PITCH (OMPAC)	DOCUMENT NO: 98ARS10503D	REV: B	
		CASE NUMBER: 1164A-01		09 AUG 2005
		STANDARD: JEDEC MS-034 AAL-1		

Figure 35. 516 TEPBGA Package (1 of 2)

NOTES:

1. ALL DIMENSIONS IN MILLIMETERS.
2. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.
3. MAXIMUM SOLDER BALL DIAMETER MEASURED PARALLEL TO DATUM A.
4. DATUM A, THE SEATING PLANE, IS DETERMINED BY THE SPHERICAL CROWNS OF THE SOLDER BALLS.
5. PACKAGE CODES: 5193 & 5198.

© FREESCALE SEMICONDUCTOR, INC. ALL RIGHTS RESERVED.	MECHANICAL OUTLINE	PRINT VERSION NOT TO SCALE	
TITLE: 516 I/O, PBGA 27 X 27 PKG, 1 MM PITCH (OMPAC)	DOCUMENT NO: 98ARS10503D	REV: B	
	CASE NUMBER: 1164A-01	09 AUG 2005	
	STANDARD: JEDEC MS-034 AAL-1		

Figure 36. 516 TEPBGA Package (2 of 2)

6 Product Documentation

This data sheet is labeled as a particular type: Product Preview, Advance Information, or Technical Data. Definitions of these types are available at: <http://www.freescale.com>.

The following documents are required for a complete description of the device and are necessary to design properly with the parts:

- *MPC5676R RM Microprocessor Reference Manual* (document number MPC5676RRM)

Appendix A Signal Properties and Muxing

The following table shows the signals properties for each pin on the MPC5676R. For each port pin that has an associated SIU_PCRn register to control its pin properties, the supported functions column lists the functions associated with the programming of the SIU_PCRn[PA] bit in the order: Primary function (P), Function 2 (F2), Function 3 (F3), and GPIO (G). See Figure 37.

Table 2. Signal Properties and Muxing Summary							
	GPIO/PCR ¹	Signal Name ²	P/F/G	Function ³	Function Summary	I/O	Pad Type
Primary Functions are listed First	113	TCRCLKA_IRQ7_GPIO113	P	TCRCLKA	eTPU A TCR clock	I	5V M
			A1	IRQ7	External interrupt request	I	
			A2	—	—	—	
			G	GPIO113	GPIO	I/O	
Function not implemented on this device							

Figure 37. Supported Functions Example

Table 38. Signal Properties and Muxing Summary

	Signal Name ²	P/A/G ³	Function ⁴	Function Summary	Direction	Pad Type ⁵	Voltage ⁶	State during RESET ⁷	State after RESET ⁸	Package Location
eTPU_A										
3	TCRCLKA_IRQ7_GPIO113	P	TCRCLKA	eTPU A TCR clock	I	MH	V _{DDEH1}	—/Up	—/Up	L1 K
		A1	IRQ7	External interrupt request	I					
		A2	—	—	—					
		G	GPIO113	GPIO	I/O					
4	ETPUA0_ETPUA12_GPIO114	P	ETPUA0	eTPU A channel	I/O	MH	V _{DDEH1}	—/WKPCFG	—/WKPCFG	L2 L
		A1	ETPUA12	eTPU A channel (output only)	O					
		A2	—	—	—					
		G	GPIO114	GPIO	I/O					
5	ETPUA1_ETPUA13_GPIO115	P	ETPUA1	eTPU A channel	I/O	MH	V _{DDEH1}	—/WKPCFG	—/WKPCFG	L3 J
		A1	ETPUA13	eTPU A channel (output only)	O					
		A2	—	—	—					
		G	GPIO115	GPIO	I/O					

Table 38. Signal Properties and Muxing Summary (continued)

GPIO/PCR ¹	Signal Name ²	P/A/G ³	Function ⁴	Function Summary	Direction	Pad Type ⁵	Voltage ⁶	State during RESET ⁷	State after RESET ⁸	Package Location	
										416	516
116	ETPUA2_ETPUA14_GPIO116	P	ETPUA2	eTPU A channel	I/O	MH	V _{DDEH1}	—/WKPCFG	—/WKPCFG	L4	J2
		A1	ETPUA14	eTPU A channel (output only)	O						
		A2	—	—	—						
		G	GPIO116	GPIO	I/O						
117	ETPUA3_ETPUA15_GPIO117	P	ETPUA3	eTPU A channel	I/O	MH	V _{DDEH1}	—/WKPCFG	—/WKPCFG	K1	H4
		A1	ETPUA15	eTPU A channel (output only)	O						
		A2	—	—	—						
		G	GPIO117	GPIO	I/O						
118	ETPUA4_ETPUA16_GPIO118	P	ETPUA4	eTPU A channel	I/O	MH	V _{DDEH1}	—/WKPCFG	—/WKPCFG	K2	J4
		A1	ETPUA16	eTPU A channel (output only)	O						
		A2	—	—	—						
		G	GPIO118	GPIO	I/O						
119	ETPUA5_ETPUA17_GPIO119	P	ETPUA5	eTPU A channel	I/O	MH	V _{DDEH1}	—/WKPCFG	—/WKPCFG	K3	H1
		A1	ETPUA17	eTPU A channel (output only)	O						
		A2	—	—	—						
		G	GPIO119	GPIO	I/O						
120	ETPUA6_ETPUA18_GPIO120	P	ETPUA6	eTPU A channel	I/O	MH	V _{DDEH1}	—/WKPCFG	—/WKPCFG	K4	K5
		A1	ETPUA18	eTPU A channel (output only)	O						
		A2	—	—	—						
		G	GPIO120	GPIO	I/O						
121	ETPUA7_ETPUA19_GPIO121	P	ETPUA7	eTPU A channel	I/O	MH	V _{DDEH1}	—/WKPCFG	—/WKPCFG	J1	H2
		A1	ETPUA19	eTPU A channel (output only)	O						
		A2	—	—	—						
		G	GPIO121	GPIO	I/O						

Table 38. Signal Properties and Muxing Summary (continued)

GPIO/PCR ¹	Signal Name ²	P/A/G ³	Function ⁴	Function Summary	Direction	Pad Type ⁵	Voltage ⁶	State during RESET ⁷	State after RESET ⁸	Package Location	
										416	516
122	ETPUA8_ETPUA20_GPIO122	P	ETPUA8	eTPU A channel	I/O	MH	V _{DDEH1}	—/WKPCFG	—/WKPCFG	J2	H3
		A1	ETPUA20	eTPU A channel (output only)	O						
		A2	—	—	—						
		G	GPIO122	GPIO	I/O						
123	ETPUA9_ETPUA21_GPIO123	P	ETPUA9	eTPU A channel	I/O	MH	V _{DDEH1}	—/WKPCFG	—/WKPCFG	J3	J3
		A1	ETPUA21	eTPU A channel (output only)	O						
		A2	—	—	—						
		G	GPIO123	GPIO	I/O						
124	ETPUA10_ETPUA22_GPIO124	P	ETPUA10	eTPU A channel	I/O	MH	V _{DDEH1}	—/WKPCFG	—/WKPCFG	J4	K6
		A1	ETPUA22	eTPU A channel (output only)	O						
		A2	—	—	—						
		G	GPIO124	GPIO	I/O						
125	ETPUA11_ETPUA23_GPIO125	P	ETPUA11	eTPU A channel	I/O	MH	V _{DDEH1}	—/WKPCFG	—/WKPCFG	H1	G1
		A1	ETPUA23	eTPU A channel (output only)	O						
		A2	—	—	—						
		G	GPIO125	GPIO	I/O						
126	ETPUA12_PCSB1_GPIO126	P	ETPUA12	eTPU A channel	I/O	MH	V _{DDEH1}	—/WKPCFG	—/WKPCFG	H2	J5
		A1	PCSB1	DSPI B peripheral chip select	O						
		A2	—	—	—						
		G	GPIO126	GPIO	I/O						
127	ETPUA13_PCSB3_GPIO127	P	ETPUA13	eTPU A channel	I/O	MH	V _{DDEH1}	—/WKPCFG	—/WKPCFG	H4	G2
		A1	PCSB3	DSPI B peripheral chip select	O						
		A2	—	—	—						
		G	GPIO127	GPIO	I/O						

Table 38. Signal Properties and Muxing Summary (continued)

GPIO/PCR ¹	Signal Name ²	P/A/G ³	Function ⁴	Function Summary	Direction	Pad Type ⁵	Voltage ⁶	State during RESET ⁷	State after RESET ⁸	Package Location	
										416	516
128	ETPUA14_PCSB4_GPIO128	P	ETPUA14	eTPU A channel	I/O	MH	V _{DDEH1}	—/WKPCFG	—/WKPCFG	H3	H5
		A1	PCSB4	DSPI B peripheral chip select	O						
		A2	—	—	—						
		G	GPIO128	GPIO	I/O						
129	ETPUA15_PCSB5_GPIO129	P	ETPUA15	eTPU A channel	I/O	MH	V _{DDEH1}	—/WKPCFG	—/WKPCFG	G1	G3
		A1	PCSB5	DSPI B peripheral chip select	O						
		A2	—	—	—						
		G	GPIO129	GPIO	I/O						
130	ETPUA16_PCSD1_GPIO130	P	ETPUA16	eTPU A channel	I/O	MH	V _{DDEH1}	—/WKPCFG	—/WKPCFG	G2	H6
		A1	PCSD1	DSPI D peripheral chip select	O						
		A2	—	—	—						
		G	GPIO130	GPIO	I/O						
131	ETPUA17_PCSD2_GPIO131	P	ETPUA17	eTPU A channel	I/O	MH	V _{DDEH1}	—/WKPCFG	—/WKPCFG	G3	G4
		A1	PCSD2	DSPI D peripheral chip select	O						
		A2	—	—	—						
		G	GPIO131	GPIO	I/O						
132	ETPUA18_PCSD3_GPIO132	P	ETPUA18	eTPU A channel	I/O	MH	V _{DDEH1}	—/WKPCFG	—/WKPCFG	G4	G5
		A1	PCSD3	DSPI D peripheral chip select	O						
		A2	—	—	—						
		G	GPIO132	GPIO	I/O						
133	ETPUA19_PCSD4_GPIO133	P	ETPUA19	eTPU A channel	I/O	MH	V _{DDEH1}	—/WKPCFG	—/WKPCFG	F1	F1
		A1	PCSD4	DSPI D peripheral chip select	O						
		A2	—	—	—						
		G	GPIO133	GPIO	I/O						

Table 38. Signal Properties and Muxing Summary (continued)

GPIO/PCR ¹	Signal Name ²	P/A/G ³	Function ⁴	Function Summary	Direction	Pad Type ⁵	Voltage ⁶	State during RESET ⁷	State after RESET ⁸	Package Location	
										416	516
134	ETPUA20_IRQ8_GPIO134	P	ETPUA20	eTPU A channel	I/O	MH	V _{DDEH1}	—/WKPCFG	—/WKPCFG	F2	F2
		A1	IRQ8	External interrupt request	I						
		A2	—	—	—						
		G	GPIO134	GPIO	I/O						
135	ETPUA21_IRQ9_GPIO135	P	ETPUA21	eTPU A channel	I/O	MH	V _{DDEH1}	—/WKPCFG	—/WKPCFG	F3	F3
		A1	IRQ9	External interrupt request	I						
		A2	—	—	—						
		G	GPIO135	GPIO	I/O						
136	ETPUA22_IRQ10_GPIO136	P	ETPUA22	eTPU A channel	I/O	MH	V _{DDEH1}	—/WKPCFG	—/WKPCFG	F4	F4
		A1	IRQ10	External interrupt request	I						
		A2	—	—	—						
		G	GPIO136	GPIO	I/O						
137	ETPUA23_IRQ11_GPIO137	P	ETPUA23	eTPU A channel	I/O	MH	V _{DDEH1}	—/WKPCFG	—/WKPCFG	E1	E1
		A1	IRQ11	External interrupt request	I						
		A2	—	—	—						
		G	GPIO137	GPIO	I/O						
138	ETPUA24_IRQ12_GPIO138	P	ETPUA24	eTPU A channel	I/O	MH	V _{DDEH1}	—/WKPCFG	—/WKPCFG	E2	E2
		A1	IRQ12	External interrupt request	I						
		A2	—	—	—						
		G	GPIO138	GPIO	I/O						
139	ETPUA25_IRQ13_GPIO139	P	ETPUA25	eTPU A channel	I/O	MH	V _{DDEH1}	—/WKPCFG	—/WKPCFG	E3	E3
		A1	IRQ13	External interrupt request	I						
		A2	—	—	—						
		G	GPIO139	GPIO	I/O						

Table 38. Signal Properties and Muxing Summary (continued)

GPIO/PCR ¹	Signal Name ²	P/A/G ³	Function ⁴	Function Summary	Direction	Pad Type ⁵	Voltage ⁶	State during RESET ⁷	State after RESET ⁸	Package Location	
										416	516
140	ETPUA26_IRQ14_GPIO140	P	ETPUA26	eTPU A channel	I/O	MH	V _{DDEH1}	—/WKPCFG	—/WKPCFG	E4	E4
		A1	IRQ14	External interrupt request	I						
		A2	—	—	—						
		G	GPIO140	GPIO	I/O						
141	ETPUA27_IRQ15_GPIO141	P	ETPUA27	eTPU A channel	I/O	MH	V _{DDEH1}	—/WKPCFG	—/WKPCFG	D1	D1
		A1	IRQ15	External interrupt request	I						
		A2	—	—	—						
		G	GPIO141	GPIO	I/O						
142	ETPUA28_PCSC1_GPIO142	P	ETPUA28	eTPU A channel	I/O	MH	V _{DDEH1}	—/WKPCFG	—/WKPCFG	D2	D2
		A1	PCSC1	DSPI C peripheral chip select	O						
		A2	—	—	—						
		G	GPIO142	GPIO	I/O						
143	ETPUA29_PCSC2_GPIO143	P	ETPUA29	eTPU A channel	I/O	MH	V _{DDEH1}	—/WKPCFG	—/WKPCFG	D3	D3
		A1	PCSC2	DSPI C peripheral chip select	O						
		A2	—	—	—						
		G	GPIO143	GPIO	I/O						
144	ETPUA30_PCSC3_GPIO144	P	ETPUA30	eTPU A channel	I/O	MH	V _{DDEH1}	—/WKPCFG	—/WKPCFG	C1	C1
		A1	PCSC3	DSPI C peripheral chip select	O						
		A2	—	—	—						
		G	GPIO144	GPIO	I/O						
145	ETPUA31_PCSC4_GPIO145	P	ETPUA31	eTPU A channel	I/O	MH	V _{DDEH1}	—/WKPCFG	—/WKPCFG	C2	C2
		A1	PCSC4	DSPI C peripheral chip select	O						
		A2	—	—	—						
		G	GPIO145	GPIO	I/O						

eTPU_B

Table 38. Signal Properties and Muxing Summary (continued)

GPIO/PCR ¹	Signal Name ²	P/A/G ³	Function ⁴	Function Summary	Direction	Pad Type ⁵	Voltage ⁶	State during RESET ⁷	State after RESET ⁸	Package Location	
										416	516
146	TCRCLKB IRQ6_GPIO146	P	TCRCLKB	eTPU B TCR clock	I	MH	V _{DDEH6}	—/Up	—/Up	T23	V25
		A1	IRQ6	External interrupt request	I						
		A2	—	—	—						
		G	GPIO146	GPIO	I/O						
147	ETPUB0_ETPUB16_GPIO147	P	ETPUB0	eTPU B channel	I/O	MH	V _{DDEH6}	—/WKPCFG	—/WKPCFG	T24	V26
		A1	ETPUB16	eTPU B channel (output only)	O						
		A2	—	—	—						
		G	GPIO147	GPIO	I/O						
148	ETPUB1_ETPUB17_GPIO148	P	ETPUB1	eTPU B channel	I/O	MH	V _{DDEH6}	—/WKPCFG	—/WKPCFG	T25	U22
		A1	ETPUB17	eTPU B channel (output only)	O						
		A2	—	—	—						
		G	GPIO148	GPIO	I/O						
149	ETPUB2_ETPUB18_GPIO149	P	ETPUB2	eTPU B channel	I/O	MH	V _{DDEH6}	—/WKPCFG	—/WKPCFG	T26	U23
		A1	ETPUB18	eTPU B channel (output only)	O						
		A2	—	—	—						
		G	GPIO149	GPIO	I/O						
150	ETPUB3_ETPUB19_GPIO150	P	ETPUB3	eTPU B channel	I/O	MH	V _{DDEH6}	—/WKPCFG	—/WKPCFG	R23	T22
		A1	ETPUB19	eTPU B channel (output only)	O						
		A2	—	—	—						
		G	GPIO150	GPIO	I/O						
151	ETPUB4_ETPUB20_GPIO151	P	ETPUB4	eTPU B channel	I/O	MH	V _{DDEH6}	—/WKPCFG	—/WKPCFG	R24	U24
		A1	ETPUB20	eTPU B channel (output only)	O						
		A2	—	—	—						
		G	GPIO151	GPIO	I/O						

Table 38. Signal Properties and Muxing Summary (continued)

GPIO/PCR ¹	Signal Name ²	P/A/G ³	Function ⁴	Function Summary	Direction	Pad Type ⁵	Voltage ⁶	State during RESET ⁷	State after RESET ⁸	Package Location	
										416	516
152	ETPUB5_ETPUB21_GPIO152	P	ETPUB5	eTPU B channel	I/O	MH	V _{DDEH6}	—/WKPCFG	—/WKPCFG	R25	U25
		A1	ETPUB21	eTPU B channel (output only)	O						
		A2	—	—	—						
		G	GPIO152	GPIO	I/O						
153	ETPUB6_ETPUB22_GPIO153	P	ETPUB6	eTPU B channel	I/O	MH	V _{DDEH6}	—/WKPCFG	—/WKPCFG	R26	U26
		A1	ETPUB22	eTPU B channel (output only)	O						
		A2	—	—	—						
		G	GPIO153	GPIO	I/O						
154	ETPUB7_ETPUB23_GPIO154	P	ETPUB7	eTPU B channel	I/O	MH	V _{DDEH6}	—/WKPCFG	—/WKPCFG	P23	T23
		A1	ETPUB23	eTPU B channel (output only)	O						
		A2	—	—	—						
		G	GPIO154	GPIO	I/O						
155	ETPUB8_ETPUB24_GPIO155	P	ETPUB8	eTPU B channel	I/O	MH	V _{DDEH6}	—/WKPCFG	—/WKPCFG	P24	T24
		A1	ETPUB24	eTPU B channel (output only)	O						
		A2	—	—	—						
		G	GPIO155	GPIO	I/O						
156	ETPUB9_ETPUB25_GPIO156	P	ETPUB9	eTPU B channel	I/O	MH	V _{DDEH6}	—/WKPCFG	—/WKPCFG	P25	R22
		A1	ETPUB25	eTPU B channel (output only)	O						
		A2	—	—	—						
		G	GPIO156	GPIO	I/O						
157	ETPUB10_ETPUB26_GPIO157	P	ETPUB10	eTPU B channel	I/O	MH	V _{DDEH6}	—/WKPCFG	—/WKPCFG	P26	T25
		A1	ETPUB26	eTPU B channel (output only)	O						
		A2	—	—	—						
		G	GPIO157	GPIO	I/O						

Table 38. Signal Properties and Muxing Summary (continued)

GPIO/PCR ¹	Signal Name ²	P/A/G ³	Function ⁴	Function Summary	Direction	Pad Type ⁵	Voltage ⁶	State during RESET ⁷	State after RESET ⁸	Package Location	
										416	516
158	ETPUB11_ETPUB27_GPIO158	P	ETPUB11	eTPU B channel	I/O	MH	V _{DDEH6}	—/WKPCFG	—/WKPCFG	N24	T26
		A1	ETPUB27	eTPU B channel (output only)	O						
		A2	—	—	—						
		G	GPIO158	GPIO	I/O						
159	ETPUB12_ETPUB28_GPIO159	P	ETPUB12	eTPU B channel	I/O	MH	V _{DDEH6}	—/WKPCFG	—/WKPCFG	N25	R23
		A1	ETPUB28	eTPU B channel (output only)	O						
		A2	—	—	—						
		G	GPIO159	GPIO	I/O						
160	ETPUB13_ETPUB29_GPIO160	P	ETPUB13	eTPU B channel	I/O	MH	V _{DDEH6}	—/WKPCFG	—/WKPCFG	N26	P22
		A1	ETPUB29	eTPU B channel (output only)	O						
		A2	—	—	—						
		G	GPIO160	GPIO	I/O						
161	ETPUB14_ETPUB30_GPIO161	P	ETPUB14	eTPU B channel	I/O	MH	V _{DDEH6}	—/WKPCFG	—/WKPCFG	M25	R24
		A1	ETPUB30	eTPU B channel (output only)	O						
		A2	—	—	—						
		G	GPIO161	GPIO	I/O						
162	ETPUB15_ETPUB31_GPIO162	P	ETPUB15	eTPU B channel	I/O	MH	V _{DDEH6}	—/WKPCFG	—/WKPCFG	M24	R25
		A1	ETPUB31	eTPU B channel (output only)	O						
		A2	—	—	—						
		G	GPIO162	GPIO	I/O						
163	ETPUB16_PCSA1_GPIO163	P	ETPUB16	eTPU B channel	I/O	MH	V _{DDEH6}	—/WKPCFG	—/WKPCFG	U26	V24
		A1	PCSA1	DSPI A peripheral chip select	O						
		A2	—	—	—						
		G	GPIO163	GPIO	I/O						

Table 38. Signal Properties and Muxing Summary (continued)

Table 38. Signal Properties and Muxing Summary (continued)

GPIO/PCR ¹	Signal Name ²	P/A/G ³	Function ⁴	Function Summary	Direction	Pad Type ⁵	Voltage ⁶	State during RESET ⁷	State after RESET ⁸	Package Location	
										416	516
170	ETPUB23_GPIO170	P	ETPUB23	eTPU B channel	I/O	MH	V _{DDEH6}	—/WKPCFG	—/WKPCFG	W26	U21
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO170	GPIO	I/O						
171	ETPUB24_GPIO171	P	ETPUB24	eTPU B channel	I/O	MH	V _{DDEH6}	—/WKPCFG	—/WKPCFG	W25	Y25
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO171	GPIO	I/O						
172	ETPUB25_GPIO172	P	ETPUB25	eTPU B channel	I/O	MH	V _{DDEH6}	—/WKPCFG	—/WKPCFG	W24	W21
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO172	GPIO	I/O						
173	ETPUB26_GPIO173	P	ETPUB26	eTPU B channel	I/O	MH	V _{DDEH6}	—/WKPCFG	—/WKPCFG	V23	Y23
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO173	GPIO	I/O						
174	ETPUB27_GPIO174	P	ETPUB27	eTPU B channel	I/O	MH	V _{DDEH6}	—/WKPCFG	—/WKPCFG	Y25	Y24
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO174	GPIO	I/O						
175	ETPUB28_GPIO175	P	ETPUB28	eTPU B channel	I/O	MH	V _{DDEH6}	—/WKPCFG	—/WKPCFG	Y24	AA24
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO175	GPIO	I/O						

Table 38. Signal Properties and Muxing Summary (continued)

Table 38. Signal Properties and Muxing Summary (continued)

GPIO/PCR ¹	Signal Name ²	P/A/G ³	Function ⁴	Function Summary	Direction	Pad Type ⁵	Voltage ⁶	State during RESET ⁷	State after RESET ⁸	Package Location	
										416	516
443	ETPUC2_GPIO443	P	ETPUC2	eTPU C channel	I/O	MH	V _{DDEH7}	—/WKPCFG	—/WKPCFG	D25	D25
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO443	GPIO	I/O						
444	ETPUC3_GPIO444	P	ETPUC3	eTPU C channel	I/O	MH	V _{DDEH7}	—/WKPCFG	—/WKPCFG	D26	D26
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO444	GPIO	I/O						
445	ETPUC4_PCSE1_GPIO445	P	ETPUC4	eTPU C channel	I/O	MH	V _{DDEH7}	—/WKPCFG	—/WKPCFG	E24	E24
		A1		DSPI E peripheral chip select							
		A2	—	—	—						
		G	GPIO445	GPIO	I/O						
446	ETPUC5_PCSE2_GPIO446	P	ETPUC5	eTPU C channel	I/O	MH	V _{DDEH7}	—/WKPCFG	—/WKPCFG	E25	E25
		A1		DSPI E peripheral chip select							
		A2	—	—	—						
		G	GPIO446	GPIO	I/O						
447	ETPUC6_PCSE3_GPIO447	P	ETPUC6	eTPU C channel	I/O	MH	V _{DDEH7}	—/WKPCFG	—/WKPCFG	E26	E26
		A1		DSPI E peripheral chip select							
		A2	—	—	—						
		G	GPIO447	GPIO	I/O						
448	ETPUC7_PCSE4_GPIO448	P	ETPUC7	eTPU C channel	I/O	MH	V _{DDEH7}	—/WKPCFG	—/WKPCFG	F23	F23
		A1		DSPI E peripheral chip select							
		A2	—	—	—						
		G	GPIO448	GPIO	I/O						

Table 38. Signal Properties and Muxing Summary (continued)

Table 38. Signal Properties and Muxing Summary (continued)

GPIO/PCR ¹	Signal Name ²	P/A/G ³	Function ⁴	Function Summary	Direction	Pad Type ⁵	Voltage ⁶	State during RESET ⁷	State after RESET ⁸	Package Location	
										416	516
455	ETPUC14_4_IRQ5_GPIO455	P	ETPUC14	eTPU C channel	I/O	MH	V _{DDEH7}	—/WKPCFG	—/WKPCFG	G26	G25
		A1	IRQ5	External interrupt request	—						
		A2	—	—	—						
		G	GPIO455	GPIO	I/O						
456	ETPUC15_GPIO456	P	ETPUC15	eTPU C channel	I/O	MH	V _{DDEH7}	—/WKPCFG	—/WKPCFG	H23	G26
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO456	GPIO	I/O						
457	ETPUC16_FR_A_TX_GPIO457	P	ETPUC16	eTPU C channel	I/O	MH	V _{DDEH7}	—/WKPCFG	—/WKPCFG	H24	H22
		A1	FR_A_TX	FlexRay A transfer	O						
		A2	—	—	—						
		G	GPIO457	GPIO	I/O						
458	ETPUC17_FR_A_RX_GPIO458	P	ETPUC17	eTPU C channel	I/O	MH	V _{DDEH7}	—/WKPCFG	—/WKPCFG	H25	H23
		A1	FR_A_RX	FlexRay A receive	I						
		A2	—	—	—						
		G	GPIO458	GPIO	I/O						
459	ETPUC18_FR_A_TX_EN_GPIO459	P	ETPUC18	eTPU C channel	I/O	MH	V _{DDEH7}	—/WKPCFG	—/WKPCFG	H26	H24
		A1	FR_A_TX_EN	FlexRay A transfer enable	O						
		A2	—	—	—						
		G	GPIO459	GPIO	I/O						
460	ETPUC19_TXDA_GPIO460	P	ETPUC19	eTPU C channel	I/O	MH	V _{DDEH7}	—/WKPCFG	—/WKPCFG	J23	H21
		A1	TXDA	eSCI A transmit	O						
		A2	—	—	—						
		G	GPIO460	GPIO	I/O						

Table 38. Signal Properties and Muxing Summary (continued)

Table 38. Signal Properties and Muxing Summary (continued)

GPIO/PCR ¹	Signal Name ²	P/A/G ³	Function ⁴	Function Summary	Direction	Pad Type ⁵	Voltage ⁶	State during RESET ⁷	State after RESET ⁸	Package Location	
										416	516
467	ETPUC26_PCSD2_GPIO467	P	ETPUC26	eTPU C channel	I/O	MH	V _{DDEH7}	—/WKPCFG	—/WKPCFG	K26	J25
		A1	PCSD2	DSPI D peripheral chip select	O						
		A2	—	—	—						
		G	GPIO467	GPIO	I/O						
468	ETPUC27_PCSD1_GPIO468	P	ETPUC27	eTPU C channel	I/O	MH	V _{DDEH7}	—/WKPCFG	—/WKPCFG	L23	J26
		A1	PCSD1	DSPI D peripheral chip select	O						
		A2	—	—	—						
		G	GPIO468	GPIO	I/O						
469	ETPUC28_PCSD0_GPIO469	P	ETPUC28	eTPU C channel	I/O	MH	V _{DDEH7}	—/WKPCFG	—/WKPCFG	L24	K22
		A1	PCSD0	DSPI D peripheral chip select	O						
		A2	—	—	—						
		G	GPIO469	GPIO	I/O						
470	ETPUC29_SCKD_GPIO470	P	ETPUC29	eTPU C channel	I/O	MH	V _{DDEH7}	—/WKPCFG	—/WKPCFG	L25	K23
		A1	SCKD	DSPI D clock	I/O						
		A2	—	—	—						
		G	GPIO470	GPIO	I/O						
471	ETPUC30_SOUTD_GPIO471	P	ETPUC30	eTPU C channel	I/O	MH	V _{DDEH7}	—/WKPCFG	—/WKPCFG	L26	K24
		A1	SOUTD	DSPI D data output	O						
		A2	—	—	—						
		G	GPIO471	GPIO	I/O						
472	ETPUC31_SIND_GPIO472	P	ETPUC31	eTPU C channel	I/O	MH	V _{DDEH7}	—/WKPCFG	—/WKPCFG	M23	K25
		A1	SIND	DSPI D data input	I						
		A2	—	—	—						
		G	GPIO472	GPIO	I/O						
eMIOS											

Table 38. Signal Properties and Muxing Summary (continued)

Table 38. Signal Properties and Muxing Summary (continued)

GPIO/PCR ¹	Signal Name ²	P/A/G ³	Function ⁴	Function Summary	Direction	Pad Type ⁵	Voltage ⁶	State during RESET ⁷	State after RESET ⁸	Package Location	
										416	516
185	EMIOS6_ETPUA6_GPIO185	P	EMIOS6	eMIOS channel	I/O	MH	V _{DDEH4}	—/WKPCFG	—/WKPCFG	AE12	AE14
		A1	ETPUA6	eTPU A channel	O						
		A2	—	—	—						
		G	GPIO185	GPIO	I/O						
186	EMIOS7_ETPUA7_GPIO186	P	EMIOS7	eMIOS channel	I/O	MH	V _{DDEH4}	—/WKPCFG	—/WKPCFG	AF12	AD14
		A1	ETPUA7	eTPU A channel	O						
		A2	—	—	—						
		G	GPIO186	GPIO	I/O						
187	EMIOS8_ETPUA8_GPIO187	P	EMIOS8	eMIOS channel	I/O	MH	V _{DDEH4}	—/WKPCFG	—/WKPCFG	AC13	AC14
		A1	ETPUA8	eTPU A channel	O						
		A2	—	—	—						
		G	GPIO187	GPIO	I/O						
188	EMIOS9_ETPUA9_GPIO188	P	EMIOS9	eMIOS channel	I/O	MH	V _{DDEH4}	—/WKPCFG	—/WKPCFG	AD13	AF15
		A1	ETPUA9	eTPU A channel	O						
		A2	—	—	—						
		G	GPIO188	GPIO	I/O						
189	EMIOS10_SCKD_GPIO189	P	EMIOS10	eMIOS channel	I/O	MH	V _{DDEH4}	—/WKPCFG	—/WKPCFG	AE13	AE15
		A1	SCKD	DSPI D clock	O						
		A2	—	—	—						
		G	GPIO189	GPIO	I/O						
190	EMIOS11_SIND_GPIO190	P	EMIOS11	eMIOS channel	I/O	MH	V _{DDEH4}	—/WKPCFG	—/WKPCFG	AF13	AB14
		A1	SIND	DSPI D data input	I						
		A2	—	—	—						
		G	GPIO190	GPIO	I/O						

Table 38. Signal Properties and Muxing Summary (continued)

Table 38. Signal Properties and Muxing Summary (continued)

GPIO/PCR ¹	Signal Name ²	P/A/G ³	Function ⁴	Function Summary	Direction	Pad Type ⁵	Voltage ⁶	State during RESET ⁷	State after RESET ⁸	Package Location	
										416	516
197	EMIOS18_ETPUB2_GPIO197	P	EMIOS18	eMIOS channel	I/O	MH	V _{DDEH4}	—/WKPCFG	—/WKPCFG	AC15	AD17
		A1	ETPUB2	eTPU B channel	O						
		A2	FR_DBG[1]	FlexRay debug	O						
		G	GPIO197	GPIO	I/O						
198	EMIOS19_ETPUB3_GPIO198	P	EMIOS19	eMIOS channel	I/O	MH	V _{DDEH4}	—/WKPCFG	—/WKPCFG	AD15	AB16
		A1	ETPUB3	eTPU B channel	O						
		A2	FR_DBG[0]	FlexRay debug	O						
		G	GPIO198	GPIO	I/O						
199	EMIOS20_ETPUB4_GPIO199	P	EMIOS20	eMIOS channel	I/O	MH	V _{DDEH4}	—/WKPCFG	—/WKPCFG	AF16	AF16
		A1	ETPUB4	eTPU B channel	O						
		A2	—	—	—						
		G	GPIO199	GPIO	I/O						
200	EMIOS21_ETPUB5_GPIO200	P	EMIOS21	eMIOS channel	I/O	MH	V _{DDEH4}	—/WKPCFG	—/WKPCFG	AE16	AE17
		A1	ETPUB5	eTPU B channel	O						
		A2	—	—	—						
		G	GPIO200	GPIO	I/O						
201	EMIOS22_ETPUB6_GPIO201	P	EMIOS22	eMIOS channel	I/O	MH	V _{DDEH4}	—/WKPCFG	—/WKPCFG	AC16	AC16
		A1	ETPUB6	eTPU B channel	O						
		A2	—	—	—						
		G	GPIO201	GPIO	I/O						
202	EMIOS23_ETPUB7_GPIO202	P	EMIOS23	eMIOS channel	I/O	MH	V _{DDEH4}	—/WKPCFG	—/WKPCFG	AD16	AA16
		A1	ETPUB7	eTPU B channel	O						
		A2	—	—	—						
		G	GPIO202	GPIO	I/O						

Table 38. Signal Properties and Muxing Summary (continued)

Table 38. Signal Properties and Muxing Summary (continued)

GPIO/PCR ¹	Signal Name ²	P/A/G ³	Function ⁴	Function Summary	Direction	Pad Type ⁵	Voltage ⁶	State during RESET ⁷	State after RESET ⁸	Package Location	
										416	516
436	EMIOS30_PCSC2_GPIO436	P	EMIOS30	eMIOS channel	I/O	MH	V _{DDEH4}	—/WKPCFG	—/WKPCFG	AD18	AF19
		A1	PCSC2	DSPI C peripheral chip select	O						
		A2	—	—	—						
		G	GPIO436	GPIO	I/O						
437	EMIOS31_PCSC5_GPIO437	P	EMIOS31	eMIOS channel	I/O	MH	V _{DDEH4}	—/WKPCFG	—/WKPCFG	AC18	AA17
		A1	PCSC5	DSPI C peripheral chip select	O						
		A2	—	—	—						
		G	GPIO437	GPIO	I/O						
eQADC											
—	ANA0	P	ANA0 ⁹	eQADC A shared analog input	I	AE/up-down	V _{DDA_A1}	ANA0	ANA0	A4	A4
—	ANA1	P	ANA1 ⁹	eQADC A shared analog input	I	AE/up-down	V _{DDA_A1}	ANA1	ANA1	B5	B5
—	ANA2	P	ANA2 ⁹	eQADC A shared analog input	I	AE/up-down	V _{DDA_A1}	ANA2	ANA2	C5	C5
—	ANA3	P	ANA3 ⁹	eQADC A shared analog input	I	AE/up-down	V _{DDA_A1}	ANA3	ANA3	D6	D6
—	ANA4	P	ANA4 ⁹	eQADC A shared analog input	I	AE/up-down	V _{DDA_A1}	ANA4	ANA4	A5	A5
—	ANA5	P	ANA5 ⁹	eQADC A shared analog input	I	AE/up-down	V _{DDA_A1}	ANA5	ANA5	B6	B6
—	ANA6	P	ANA6 ⁹	eQADC A shared analog input	I	AE/up-down	V _{DDA_A1}	ANA6	ANA6	C6	C6
—	ANA7	P	ANA7 ⁹	eQADC A shared analog input	I	AE/up-down	V _{DDA_A1}	ANA7	ANA7	D7	C7
—	ANA8	P	ANA8	eQADC A analog input	I	AE	V _{DDA_A1}	ANA8	ANA8	A6	D7
—	ANA9	P	ANA9	eQADC A analog input	I	AE	V _{DDA_A1}	ANA9	ANA9	C7	A6
—	ANA10	P	ANA10	eQADC A analog input	I	AE	V _{DDA_A1}	ANA10	ANA10	B7	B7
—	ANA11	P	ANA11	eQADC A analog input	I	AE	V _{DDA_A1}	ANA11	ANA11	A7	A7

Table 38. Signal Properties and Muxing Summary (continued)

GPIO/PCR ¹	Signal Name ²	P/A/G ³	Function ⁴	Function Summary	Direction	Pad Type ⁵	Voltage ⁶	State during RESET ⁷	State after RESET ⁸	Package Location	
										416	516
—	ANA12	P	ANA12	eQADC A analog input	I	AE	V _{DDA_A1}	ANA12	ANA12	D8	D8
—	ANA13	P	ANA13	eQADC A analog input	I	AE	V _{DDA_A1}	ANA13	ANA13	C8	C8
—	ANA14	P	ANA14	eQADC A analog input	I	AE	V _{DDA_A1}	ANA14	ANA14	B8	B8
—	ANA15	P	ANA15	eQADC A analog input	I	AE	V _{DDA_A1}	ANA15	ANA15	A8	A8
—	ANA16	P	ANA16	eQADC A analog input	I	AE	V _{DDA_A1}	ANA16	ANA16	D9	D9
—	ANA17	P	ANA17	eQADC A analog input	I	AE	V _{DDA_A1}	ANA17	ANA17	C9	C9
—	ANA18	P	ANA18	eQADC A analog input	I	AE	V _{DDA_A1}	ANA18	ANA18	D10	D10
—	ANA19	P	ANA19	eQADC A analog input	I	AE	V _{DDA_A1}	ANA19	ANA19	C10	C10
—	ANA20	P	ANA20	eQADC A analog input	I	AE	V _{DDA_A1}	ANA20	ANA20	D11	D11
—	ANA21	P	ANA21	eQADC A analog input	I	AE	V _{DDA_A1}	ANA21	ANA21	C11	C11
—	ANA22	P	ANA22	eQADC A analog input	I	AE	V _{DDA_A1}	ANA22	ANA22	D12	C12
—	ANA23	P	ANA23	eQADC A analog input	I	AE	V _{DDA_A1}	ANA23	ANA23	C12	D12
—	AN24	P	AN24	eQADC analog input	I	AE	V _{DDA_A0}	AN24	AN24	B12	B12
—	AN25	P	AN25	eQADC analog input	I	AE	V _{DDA_A0}	AN25	AN25	D13	C13
—	AN26	P	AN26	eQADC analog input	I	AE	V _{DDA_A0}	AN26	AN26	C13	D13
—	AN27	P	AN27	eQADC analog input	I	AE	V _{DDA_A0}	AN27	AN27	B13	B13
—	AN28	P	AN28	eQADC analog input	I	AE	V _{DDA_A0}	AN28	AN28	A13	A13
—	AN29	P	AN29	eQADC analog input	I	AE	V _{DDA_A0}	AN29	AN29	B14	A14
—	AN30	P	AN30	eQADC analog input	I	AE	V _{DDA_B1}	AN30	AN30	C14	B14
—	AN31	P	AN31	eQADC analog input	I	AE	V _{DDA_B1}	AN31	AN31	D14	C14
—	AN32	P	AN32	eQADC analog input	I	AE	V _{DDA_B1}	AN32	AN32	A14	B15
—	AN33	P	AN33	eQADC analog input	I	AE	V _{DDA_B0}	AN33	AN33	B15	D14
—	AN34	P	AN34	eQADC analog input	I	AE	V _{DDA_B0}	AN34	AN34	C15	C15
—	AN35	P	AN35	eQADC analog input	I	AE	V _{DDA_B0}	AN35	AN35	D15	D15
—	AN36	P	AN36	eQADC analog input	I	AE	V _{DDA_B1}	AN36	AN36	A15	A15
—	AN37	P	AN37	eQADC analog input	I	AE	V _{DDA_B0}	AN37	AN37	C16	C17
—	AN38	P	AN38	eQADC analog input	I	AE	V _{DDA_B0}	AN38	AN38	C17	D16

Table 38. Signal Properties and Muxing Summary (continued)

GPIO/PCR ¹	Signal Name ²	P/A/G ³	Function ⁴	Function Summary	Direction	Pad Type ⁵	Voltage ⁶	State during RESET ⁷	State after RESET ⁸	Package Location	
										416	516
—	AN39	P	AN39	eQADC analog input	I	AE	V _{DDA_B0}	AN39	AN39	D16	C16
—	ANB0	P	ANB0	eQADC B shared analog input	I	AE/up-down	V _{DDA_B0}	ANB0	ANB0	C18	C18
—	ANB1	P	ANB1	eQADC B shared analog input	I	AE/up-down	V _{DDA_B0}	ANB1	ANB1	D17	D17
—	ANB2	P	ANB2	eQADC B shared analog input	I	AE/up-down	V _{DDA_B0}	ANB2	ANB2	D18	D18
—	ANB3	P	ANB3	eQADC B shared analog input	I	AE/up-down	V _{DDA_B0}	ANB3	ANB3	D19	D19
—	ANB4	P	ANB4	eQADC B shared analog input	I	AE/up-down	V _{DDA_B0}	ANB4	ANB4	C19	B19
—	ANB5	P	ANB5	eQADC B shared analog input	I	AE/up-down	V _{DDA_B0}	ANB5	ANB5	C20	A20
—	ANB6	P	ANB6	eQADC B shared analog input	I	AE/up-down	V _{DDA_B0}	ANB6	ANB6	B19	C20
—	ANB7	P	ANB7	eQADC B shared analog input	I	AE/up-down	V _{DDA_B0}	ANB7	ANB7	A20	C19
—	ANB8	P	ANB8	eQADC B analog input	I	AE	V _{DDA_B0}	ANB8	ANB8	B20	B20
—	ANB9	P	ANB9	eQADC B analog input	I	AE	V _{DDA_B0}	ANB9	ANB9	D20	A21
—	ANB10	P	ANB10	eQADC B analog input	I	AE	V _{DDA_B0}	ANB10	ANB10	B21	B21
—	ANB11	P	ANB11	eQADC B analog input	I	AE	V _{DDA_B0}	ANB11	ANB11	A21	C21
—	ANB12	P	ANB12	eQADC B analog input	I	AE	V _{DDA_B0}	ANB12	ANB12	C21	A22
—	ANB13	P	ANB13	eQADC B analog input	I	AE	V _{DDA_B0}	ANB13	ANB13	D21	B22
—	ANB14	P	ANB14	eQADC B analog input	I	AE	V _{DDA_B0}	ANB14	ANB14	A22	D20
—	ANB15	P	ANB15	eQADC B analog input	I	AE	V _{DDA_B0}	ANB15	ANB15	B22	C22
—	ANB16	P	ANB16	eQADC B analog input	I	AE	V _{DDA_B0}	ANB16	ANB16	C22	D21
—	ANB17	P	ANB17	eQADC B analog input	I	AE	V _{DDA_B0}	ANB17	ANB17	A23	D22
—	ANB18	P	ANB18	eQADC B analog input	I	AE	V _{DDA_B0}	ANB18	ANB18	B23	A23
—	ANB19	P	ANB19	eQADC B analog input	I	AE	V _{DDA_B0}	ANB19	ANB19	C23	B23
—	ANB20	P	ANB20	eQADC B analog input	I	AE	V _{DDA_B0}	ANB20	ANB20	D22	C23

Table 38. Signal Properties and Muxing Summary (continued)

Table 38. Signal Properties and Muxing Summary (continued)

GPIO/PCR ¹	Signal Name ²	P/A/G ³	Function ⁴	Function Summary	Direction	Pad Type ⁵	Voltage ⁶	State during RESET ⁷	State after RESET ⁸	Package Location	
										416	516
250	FR_A_TX_EN_GPIO250	P	FR_A_TX_EN	FlexRay A transfer enable	O	FS	V _{DDE2}	—/Up (/-/ for Rev.1 of the device)	—/Up (/-/ for Rev.1 of the device)	AF3	AF3
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO250	GPIO	I/O						
251	FR_B_TX_GPIO251	P	FR_B_TX	FlexRay B transfer	O	FS	V _{DDE2}	—/Up (/-/ for Rev.1 of the device)	—/Up (/-/ for Rev.1 of the device)	AD5	AD5
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO251	GPIO	I/O						
252	FR_B_RX_GPIO252	P	FR_B_RX	FlexRay B receive	I	FS	V _{DDE2}	—/Up (/-/ for Rev.1 of the device)	—/Up (/-/ for Rev.1 of the device)	AE4	AE4
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO252	GPIO	I/O						
253	FR_B_TX_EN_GPIO253	P	FR_B_TX_EN	FlexRay B transfer enable	O	FS	V _{DDE2}	—/Up (/-/ for Rev.1 of the device)	—/Up (/-/ for Rev.1 of the device)	AF4	AF4
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO253	GPIO	I/O						
FlexCAN											
83	CNTXA_TXDA_GPIO83	P	CNTXA	FlexCAN A transmit	O	MH	V _{DDEH4}	—/Up	—/Up	AF19	AE19
		A1	TXDA	eSCI A transmit	O						
		A2	—	—	—						
		G	GPIO83	GPIO	I/O						
84	CNRXA_RXDA_GPIO84	P	CNRXA	FlexCAN A receive	I	MH	V _{DDEH4}	—/Up	—/Up	AE19	AD19
		A1	RXDA	eSCI A receive	I						
		A2	—	—	—						
		G	GPIO84	GPIO	I/O						

Table 38. Signal Properties and Muxing Summary (continued)

Table 38. Signal Properties and Muxing Summary (continued)

GPIO/PCR ¹	Signal Name ²	P/A/G ³	Function ⁴	Function Summary	Direction	Pad Type ⁵	Voltage ⁶	State during RESET ⁷	State after RESET ⁸	Package Location	
										416	516
89	TXDA_GPIO89	P	TXDA	eSCI A transmit	O	MH	V _{DDEH1}	—/Up	—/Up	M2	K2
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO89	GPIO	I/O						
90	RXDA_GPIO90	P	RXDA	eSCI A receive	I	MH	V _{DDEH1}	—/Up	—/Up	M3	K3
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO90	GPIO	I						
91	TXDB_PCSO1_GPIO91	P	TXDB	eSCI B transmit	O	MH	V _{DDEH1}	—/Up	—/Up	P1	K1
		A1	PCSD1	DSPI D peripheral chip select	O						
		A2	—	—	—						
		G	GPIO91	GPIO	I/O						
92	RXDB_PCSO5_GPIO92	P	RXDB	eSCI B receive	I	MH	V _{DDEH1}	—/Up	—/Up	N1	L5
		A1	PCSD5	DSPI D peripheral chip select	O						
		A2	—	—	—						
		G	GPIO92	GPIO	I/O						
244	TXDC_ETRIG0_GPIO244	P	TXDC	eSCI C transmit	O	MH	V _{DDEH4}	—/Up	—/Up	AF23	AF23
		A1	ETRIG0	eQADC trigger input	I						
		A2	—	—	—						
		G	GPIO244	GPIO	I/O						
245	RXDC_GPIO245	P	RXDC	eSCI C receive	I	MH	V _{DDEH5}	—/Up	—/Up	AD22	AD22
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO245	GPIO	I/O						

Table 38. Signal Properties and Muxing Summary (continued)

Table 38. Signal Properties and Muxing Summary (continued)

GPIO/PCR ¹	Signal Name ²	P/A/G ³	Function ⁴	Function Summary	Direction	Pad Type ⁵	Voltage ⁶	State during RESET ⁷	State after RESET ⁸	Package Location	
										416	516
99	PCSA3_SINE_GPIO99	P	PCSA3	DSPI A peripheral chip select	O	MH	V _{DDEH3}	—/Up	—/Up	AE7	AD7
		A1		DSPI E data input							
		A2	—	—	—						
		G	GPIO99	GPIO	I/O						
100	PCSA4_SCKE_GPIO100	P	PCSA4	DSPI A peripheral chip select	O	MH	V _{DDEH3}	—/Up	—/Up	AE5	AE5
		A1		DSPI E clock							
		A2	—	—	—						
		G	GPIO100	GPIO	I/O						
101	PCSA5_ETRIG1_GPIO101	P	PCSA5	DSPI A peripheral chip select	O	MH	V _{DDEH3}	—/Up	—/Up	AD6	AA8
		A1	ETRIG1	eQADC trigger input	I						
		A2	—	—	—						
		G	GPIO101	GPIO	I/O						
102	SCKB_GPIO102	P	SCKB	DSPI B clock	I/O	MH	V _{DDEH3}	—/Up	—/Up	AE8	AC8
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO102	GPIO	I/O						
103	SINB_GPIO103	P	SINB	DSPI B data input	I	MH	V _{DDEH3}	—/Up	—/Up	AE9	AB9
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO103	GPIO	I/O						
104	SOUTB_GPIO104	P	SOUTB	DSPI B data output	O	MH	V _{DDEH3}	—/Up	—/Up	AF9	AA10
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO104	GPIO	I/O						

Table 38. Signal Properties and Muxing Summary (continued)

Table 38. Signal Properties and Muxing Summary (continued)

GPIO/PCR ¹	Signal Name ²	P/A/G ³	Function ⁴	Function Summary	Direction	Pad Type ⁵	Voltage ⁶	State during RESET ⁷	State after RESET ⁸	Package Location	
										416	516
235	SCKC_SCK_C_LVDSP_GPIO235	P	SCKC	DSPI C clock	I/O	MH+ LVDS	V _{DDEH4}	—/Up	—/Up	AD21	AD21
		A1	SCK_C_LVDSP	LVDS+ downstream signal positive output clock	O						
		A2	—	—	—						
		G	GPIO235	GPIO	I/O						
236	SINC_SCK_C_LVDSM_GPIO236	P	SINC	DSPI C data input	I	MH+ LVDS	V _{DDEH4}	—/Up	—/Up	AE22	AE22
		A1	SCK_C_LVDSM	LVDS– downstream signal negative output clock	O						
		A2	—	—	—						
		G	GPIO236	GPIO	I/O						
237	SOUTC_SOUT_C_LVDSP_GPIO237	P	SOUTC	DSPI C data output	O	MH+ LVDS	V _{DDEH4}	—/Up	—/Up	AF21	AF21
		A1	SOUT_C_LVDSP	LVDS+ downstream signal positive output data	O						
		A2	—	—	—						
		G	GPIO237	GPIO	I/O						
238	PCSC0_SOUT_C_LVDSM_GPIO238	P	PCSC0	DSPI C peripheral chip select	I/O	MH+ LVDS	V _{DDEH4}	—/Up	—/Up	AE21	AE21
		A1	SOUT_C_LVDSM	LVDS– downstream signal negative output data	O						
		A2	—	—	—						
		G	GPIO238	GPIO	I/O						
239	PCSC1_GPIO239	P	PCSC1	DSPI C peripheral chip select	O	MH	V _{DDEH4}	—/Up	—/Up	AC22	AC22
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO239	GPIO	I/O						
240	PCSC2_GPIO240	P	PCSC2	DSPI C peripheral chip select	O	MH	V _{DDEH5}	—/Up	—/Up	AE23	AE23
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO240	GPIO	I/O						

Table 38. Signal Properties and Muxing Summary (continued)

GPIO/PCR ¹	Signal Name ²	P/A/G ³	Function ⁴	Function Summary	Direction	Pad Type ⁵	Voltage ⁶	State during RESET ⁷	State after RESET ⁸	Package Location	
										416	516
241	PCSC3_GPIO241	P	PCSC3	DSPI C peripheral chip select	O	MH	V _{DDEH5}	—/Up	—/Up	AD23	AD23
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO241	GPIO	I/O						
242	PCSC4_GPIO242	P	PCSC4	DSPI C peripheral chip select	O	MH	V _{DDEH5}	—/Up	—/Up	AF24	AF24
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO242	GPIO	I/O						
243	PCSC5_GPIO243	P	PCSC5	DSPI C peripheral chip select	O	MH	V _{DDEH5}	—/Up	—/Up	AE24	AE24
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO243	GPIO	I/O						
EBI											
256	D_CS0_GPIO256	P	D_CS0	EBI chip select 0	O	F	V _{DDE9}	—/Up	—/Up	—	AD9
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO256	GPIO	I/O						
257	D_CS2_D_ADD_DAT31_GPIO257	P	D_CS2	EBI chip select 2	O	F	V _{DDE8}	—/Up	—/Up	—	U1
		A1	D_ADD_DAT31	Address and data in mux mode.	I/O						
		A2	—	—	—						
		G	GPIO257	GPIO	I/O						
258	D_CS3_D_TEA_GPIO258	P	D_CS3	EBI chip select 3	O	F	V _{DDE8}	—/Up	—/Up	—	T6
		A1	D_TEA	EBI transfer error acknowledge	I/O						
		A2	—	—	—						
		G	GPIO258	GPIO	I/O						

Table 38. Signal Properties and Muxing Summary (continued)

GPIO/PCR ¹	Signal Name ²	P/A/G ³	Function ⁴	Function Summary	Direction	Pad Type ⁵	Voltage ⁶	State during RESET ⁷	State after RESET ⁸	Package Location	
										416	516
259	D_ADD12_GPIO259	P	D_ADD12	EBI address bus	O	F	V _{DDE8}	—/Up	—/Up	—	R1
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO259	GPIO	I/O						
260	D_ADD13_GPIO260	P	D_ADD13	EBI address bus	O	F	V _{DDE8}	—/Up	—/Up	—	R2
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO260	GPIO	I/O						
261	D_ADD14_GPIO261	P	D_ADD14	EBI address bus	O	F	V _{DDE8}	—/Up	—/Up	—	R3
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO261	GPIO	I/O						
262	D_ADD15_GPIO262	P	D_ADD15	EBI address bus	O	F	V _{DDE8}	—/Up	—/Up	—	R4
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO262	GPIO	I/O						
263	D_ADD16_D_ADD_DAT16_GPIO263	P	D_ADD16	EBI address bus	O	F	V _{DDE8}	—/Up	—/Up	—	R5
		A1	D_ADD_DAT16	Address and data in mux mode.	I/O						
		A2	—	—	—						
		G	GPIO263	GPIO	I/O						
264	D_ADD17_D_ADD_DAT17_GPIO264	P	D_ADD17	EBI address bus	O	F	V _{DDE8}	—/Up	—/Up	—	T5
		A1	D_ADD_DAT17	Address and data in mux mode.	I/O						
		A2	—	—	—						
		G	GPIO264	GPIO	I/O						

Table 38. Signal Properties and Muxing Summary (continued)

Table 38. Signal Properties and Muxing Summary (continued)

GPIO/PCR ¹	Signal Name ²	P/A/G ³	Function ⁴	Function Summary	Direction	Pad Type ⁵	Voltage ⁶	State during RESET ⁷	State after RESET ⁸	Package Location	
										416	516
271	D_ADD24_D_ADD_DAT24_GPIO271	P	D_ADD24	EBI address bus	O	F	V _{DDE9}	—/Up	—/Up	—	AF10
		A1	D_ADD_DAT24	Address and data in mux mode.	I/O						
		A2	—	—	—						
		G	GPIO271	GPIO	I/O						
272	D_ADD25_D_ADD_DAT25_GPIO272	P	D_ADD25	EBI address bus	O	F	V _{DDE9}	—/Up	—/Up	—	AD11
		A1	D_ADD_DAT25	Address and data in mux mode.	I/O						
		A2	—	—	—						
		G	GPIO272	GPIO	I/O						
273	D_ADD26_D_ADD_DAT26_GPIO273	P	D_ADD26	EBI address bus	O	F	V _{DDE9}	—/Up	—/Up	—	AE11
		A1	D_ADD_DAT26	Address and data in mux mode.	I/O						
		A2	—	—	—						
		G	GPIO273	GPIO	I/O						
274	D_ADD27_D_ADD_DAT27_GPIO274	P	D_ADD27	EBI address bus	O	F	V _{DDE9}	—/Up	—/Up	—	AF11
		A1	D_ADD_DAT27	Address and data in mux mode.	I/O						
		A2	—	—	—						
		G	GPIO274	GPIO	I/O						
275	D_ADD28_D_ADD_DAT28_GPIO275	P	D_ADD28	EBI address bus	O	F	V _{DDE9}	—/Up	—/Up	—	AD12
		A1	D_ADD_DAT28	Address and data in mux mode.	I/O						
		A2	—	—	—						
		G	GPIO275	GPIO	I/O						
276	D_ADD29_D_ADD_DAT29_GPIO276	P	D_ADD29	EBI address bus	O	F	V _{DDE9}	—/Up	—/Up	—	AB12
		A1	D_ADD_DAT29	Address and data in mux mode.	I/O						
		A2	—	—	—						
		G	GPIO276	GPIO	I/O						

Table 38. Signal Properties and Muxing Summary (continued)

Table 38. Signal Properties and Muxing Summary (continued)

GPIO/PCR ¹	Signal Name ²	P/A/G ³	Function ⁴	Function Summary	Direction	Pad Type ⁵	Voltage ⁶	State during RESET ⁷	State after RESET ⁸	Package Location	
										416	516
282	D_ADD_DAT4_GPIO282	P	D_ADD_DAT4	EBI data only in non-mux mode. Address and data in mux mode.	I/O	F	V _{DDE10}	—/Up	—/Up	—	N26
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO282	GPIO	I/O						
283	D_ADD_DAT5_GPIO283	P	D_ADD_DAT5	EBI data only in non-mux mode. Address and data in mux mode.	I/O	F	V _{DDE10}	—/Up	—/Up	—	M25
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO283	GPIO	I/O						
284	D_ADD_DAT6_GPIO284	P	D_ADD_DAT6	EBI data only in non-mux mode. Address and data in mux mode.	I/O	F	V _{DDE10}	—/Up	—/Up	—	N22
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO284	GPIO	I/O						
285	D_ADD_DAT7_GPIO285	P	D_ADD_DAT7	EBI data only in non-mux mode. Address and data in mux mode.	I/O	F	V _{DDE10}	—/Up	—/Up	—	M24
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO285	GPIO	I/O						
286	D_ADD_DAT8_GPIO286	P	D_ADD_DAT8	EBI data only in non-mux mode. Address and data in mux mode.	I/O	F	V _{DDE10}	—/Up	—/Up	—	M23
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO286	GPIO	I/O						

Table 38. Signal Properties and Muxing Summary (continued)

Table 38. Signal Properties and Muxing Summary (continued)

GPIO/PCR ¹	Signal Name ²	P/A/G ³	Function ⁴	Function Summary	Direction	Pad Type ⁵	Voltage ⁶	State during RESET ⁷	State after RESET ⁸	Package Location	
										416	516
292	D_ADD_DAT14_GPIO292	P	D_ADD_DAT14	EBI data only in non-mux mode. Address and data in mux mode.	I/O	F	V _{DDE10}	—/Up	—/Up	—	L22
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO292	GPIO	I/O						
293	D_ADD_DAT15_GPIO293	P	D_ADD_DAT15	EBI data only in non-mux mode. Address and data in mux mode.	I/O	F	V _{DDE10}	—/Up	—/Up	—	K26
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO293	GPIO	I/O						
294	D_RD_WR_GPIO294	P	D_RD_WR	EBI read/write	O	F	V _{DDE10}	—/Up	—/Up	—	R26
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO294	GPIO	I/O						
295	D_WE0_GPIO295	P	D_WE0	EBI write enable	O	F	V _{DDE8}	—/Up	—/Up	—	N1
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO295	GPIO	I/O						
296	D_WE1_GPIO296	P	D_WE1	EBI write enable	O	F	V _{DDE8}	—/Up	—/Up	—	P5
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO296	GPIO	I/O						
297	D_OE_GPIO297	P	D_OE	EBI output enable	O	F	V _{DDE10}	—/Up	—/Up	—	P23
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO297	GPIO	I/O						

Table 38. Signal Properties and Muxing Summary (continued)

Table 38. Signal Properties and Muxing Summary (continued)

GPIO/PCR ¹	Signal Name ²	P/A/G ³	Function ⁴	Function Summary	Direction	Pad Type ⁵	Voltage ⁶	State during RESET ⁷	State after RESET ⁸	Package Location	
										416	516
304	D_WE3_GPIO304	P	D_WE3	EBI write enable	O	F	V _{DDE8}	—/Up	—/Up	—	N3
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO304	GPIO	I/O						
305	D_ADD9_GPIO305	P	D_ADD9	EBI address bus	O	F	V _{DDE8}	—/Up	—/Up	—	P1
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO305	GPIO	I/O						
306	D_ADD10_GPIO306	P	D_ADD10	EBI address bus	O	F	V _{DDE8}	—/Up	—/Up	—	P2
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO306	GPIO	I/O						
307	D_ADD11_GPIO307	P	D_ADD11	EBI address bus	O	F	V _{DDE8}	—/Up	—/Up	—	P3
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO307	GPIO	I/O						
Reset and Clocks											
—	RESET	P	RESET	External reset input	I	MH	V _{DDEH1}	RESET/Up	RESET/Up	R2	N5
230	RSTOUT	P	RSTOUT	External reset output	O	MH	V _{DDEH1}	RSTOUT/Low	RSTOUT/High	A3	A3
211	BOOTCFG0_IRQ2_GPIO211	P	BOOTCFG0	Boot configuration	I	MH	V _{DDEH1}	BOOTCFG/Down	—/Down	—	L4
		A1	IRQ2	—	I						
		A2	—	—	—						
		G	GPIO211	GPIO	I/O						

Table 38. Signal Properties and Muxing Summary (continued)

GPIO/PCR ¹	Signal Name ²	P/A/G ³	Function ⁴	Function Summary	Direction	Pad Type ⁵	Voltage ⁶	State during RESET ⁷	State after RESET ⁸	Package Location	
										416	516
212	BOOTCFG1_IRQ3_GPIO212	P	BOOTCFG1	Boot configuration	I	MH	V _{DDEH1}	BOOTCFG/Down	—/Down	N2	L3
		A1	IRQ3	External interrupt request	I						
		A2	—	—	—						
		G	GPIO212	GPIO	I/O						
213	WKPCFG_NMI_GPIO213 ¹⁰	P	WKPCFG	Weak pull configuration input	I	MH	V _{DDEH1}	WKPCFG/Up	—/Up	N3	M5
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO213	GPIO	I						
208	PLLCFG0_IRQ4_GPIO208	P	PLLCFG0	FMPPLL mode configuration input	I	MH	V _{DDEH1}	PLLCFG/Up	—/Up	R3	M3
		A1	IRQ4	External interrupt request	I						
		A2	—	—	—						
		G	GPIO208	GPIO	I/O						
209	PLLCFG1_IRQ5_GPIO209	P	PLLCFG1	FMPPLL mode configuration input	I	MH	V _{DDEH1}	PLLCFG/Up	—/Up	P2	L1
		A1	IRQ5	External interrupt request	I						
		A2	SOUTD	DSPI D data output	O						
		G	GPIO209	GPIO	I/O						
—	PLLCFG2	P	PLLCFG2	FMPPLL mode configuration input	I	MH	V _{DDEH1}	PLLCFG/Down	—/Down	P3	L2
—	XTAL	P	XTAL	Crystal oscillator output	O	AE	V _{DD33}	XTAL	XTAL	AC26	AC26
—	EXTAL	P	EXTAL	Crystal oscillator input	I	AE	V _{DD33}	EXTAL	EXTAL	AB26	AB26
229	D_CLKOUT	P	D_CLKOUT	EBI system clock output	O	F	V _{DDE9}	CLKOUT/Enabled	CLKOUT/Enabled	—	AF12
214	ENGCLK	P	ENGCLK	EBI engineering clock output Note: EXTCLK (External clock input) selected through SIU register)	O	F	V _{DDE2}	ENGCLK/Enabled	ENGCLK/Enabled	AD1	AD1
JTAG and Nexus (see footnote ¹¹ about resets)											
—	EVTI	— ¹²	EVTI	Nexus event in	I	F	V _{DDE2}	—/Up	EVTI/Up	T4	V1

Table 38. Signal Properties and Muxing Summary (continued)

GPIO/PCR ¹	Signal Name ²	P/A/G ³	Function ⁴	Function Summary	Direction	Pad Type ⁵	Voltage ⁶	State during RESET ⁷	State after RESET ⁸	Package Location	
										416	516
227	EVTO (the BAM uses this pin to select if auto baud rate is on or off)	- ¹²	EVTO	Nexus event out	O	F	V _{DDE2}	ABS/Up	EVTO/HI	U1	V2
219	MCKO	- ¹²	MCKO	Nexus message clock out	O	F	V _{DDE2}	O/Low	Disabled ¹³	T2	U4
220	MDO0_GPIO220	- ¹²	MDO0 ¹⁴	Nexus message data out	O	F	V _{DDE2}	See Note ¹⁵	See Note ¹⁵	U3	V3
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO220	GPIO	I/O						
221	MDO1_GPIO221	- ¹²	MDO1 ¹⁴	Nexus message data out	O	F	V _{DDE2}	O/Low	—/Down	U4	W6
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO221	GPIO	I/O						
222	MDO2_GPIO222	- ¹²	MDO2 ¹⁴	Nexus message data out	O	F	V _{DDE2}	O/Low	—/Down	V1	V4
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO222	GPIO	I/O						
223	MDO3_GPIO223	- ¹²	MDO3 ¹⁴	Nexus message data out	O	F	V _{DDE2}	O/Low	—/Down	V2	V5
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO223	GPIO	I/O						
75	MDO4_GPIO75	- ¹²	MDO4 ¹⁴	Nexus message data out	O	F	V _{DDE2}	O/Low	—/Down	V3	W1
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO75	GPIO	I/O						

Table 38. Signal Properties and Muxing Summary (continued)

Table 38. Signal Properties and Muxing Summary (continued)

GPIO/PCR ¹	Signal Name ²	P/A/G ³	Function ⁴	Function Summary	Direction	Pad Type ⁵	Voltage ⁶	State during RESET ⁷	State after RESET ⁸	Package Location	
										416	516
82	MDO11_GPIO82	- ¹²	MDO11 ¹⁴	Nexus message data out	O	F	V _{DDE2}	O/Low	—/Down	Y3	Y4
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO82	GPIO	I/O						
231	MDO12_GPIO231	- ¹²	MDO12 ¹⁴	Nexus message data out	O	F	V _{DDE2}	O/Low	—/Down	AA1	Y5
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO231	GPIO	I/O						
232	MDO13_GPIO232	- ¹²	MDO13 ¹⁴	Nexus message data out	O	F	V _{DDE2}	O/Low	—/Down	AA2	AA1
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO232	GPIO	I/O						
233	MDO14_GPIO233	- ¹²	MDO14 ¹⁴	Nexus message data out	O	F	V _{DDE2}	O/Low	—/Down	AA3	AA2
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO233	GPIO	I/O						
234	MDO15_GPIO234	- ¹²	MDO15 ¹⁴	Nexus message data out	O	F	V _{DDE2}	O/Low	—/Down	Y4	AA3
		A1	—	—	—						
		A2	—	—	—						
		G	GPIO234	GPIO	I/O						
224	MSEO0	- ¹²	MSEO0 ¹⁴	Nexus message start/end out	O	F	V _{DDE2}	O/Low	MSEO/HI	U2	U6
225	MSEO1	- ¹²	MSEO1 ¹⁴	Nexus message start/end out	O	F	V _{DDE2}	O/Low	MSEO/HI	T3	U5
226	RDY	- ¹²	RDY	Nexus ready output	O	F	V _{DDE2}	O/Low	RDY/HI	R4	U3
—	TCK	- ¹²	TCK	JTAG test clock input	I	F	V _{DDE2}	TCK/Down	TCK/Down	AB2	AB2
—	TDI	- ¹²	TDI	JTAG test data input	I	F	V _{DDE2}	TDI/Up	TDI/Up	AC2	AC2
228	TDO	- ¹²	TDO	JTAG test data output	O	F	V _{DDE2}	TDO/Up	TDO/Up	AB1	AB1
—	TMS	- ¹²	TMS	JTAG test mode select input	I	F	V _{DDE2}	TMS/Up	TMS/Up	AB3	AB3

Table 38. Signal Properties and Muxing Summary (continued)

GPIO/PCR ¹	Signal Name ²	P/A/G ³	Function ⁴	Function Summary	Direction	Pad Type ⁵	Voltage ⁶	State during RESET ⁷	State after RESET ⁸	Package Location	
										416	516
—	JCOMP	- ¹²	JCOMP	JTAG TAP controller enable	I	F	V _{DDE2}	JCOMP/Down	JCOMP/Down	R1	U2
—	TEST	—	TEST	Test mode select (not for customer use)	I	F	V _{DDEH1}	TEST/Down	TEST/Down	B4	B4
—	VDDSYN	—	VDDSYN	Clock synthesizer power input	I/O	VDDE	V _{DDSYN}	VDDSYN	VDDSYN	AD26	AD26
—	VSSYN	—	VSSYN	Clock synthesizer ground input	I	VSSE	V _{DDSYN}	VSSYN	VSSYN	AA26	AA26
—	VSTBY	—	VSTBY	SRAM standby power input	I	VHV	V _{DDEH1}	VSTBY	VSTBY	M4	M4
—	REGSEL	—	REGSEL	Selects regulator mode (Linear/Switch mode)	I	AE	V _{DDREG}	REGSEL	REGSEL	W23	W23
—	REGCTL	—	REGCTL	Regulator controller output to base/gate of power transistor	O	AE	V _{DDREG}	REGCTL	REGCTL	Y26	Y26
—	VSSFL	—	VSSFL	Tie to V _{SS}	I	VSS	V _{DDREG}	VSSFL	VSSFL	AB25	AB25
—	VDDREG	—	VDDREG	Source voltage for on-chip regulators and Low voltage detect circuits	I	VDDINT	V _{DDREG}	VDDREG	VDDREG	AA25	AA25

¹ The GPIO number is the same as the corresponding pad configuration register (SIU_PCRn) number in pins that have GPIO functionality. For pins that do not have GPIO functionality, this number is the PCR number.

² The primary signal name is used as the pin label on the BGA map for identification purposes. However, the primary signal function is not available on all devices and is indicated by a dash in the following table columns: Signal Functions, P/F/G, and I/O Type.

³ P/A/G stands for Primary/Alternate/GPIO . This column indicates which function on a pin is Primary, Alternate 1, Alternate 2, (Alternate n) and GPIO.

⁴ Each line in the Function column corresponds to a separate signal function on the pin. For all device I/O pins, the primary, alternate, or GPIO signal functions are designated in the PA field of the SIU_PCRn registers except where explicitly noted.

⁵ MH = High voltage, medium speed

F = Fast speed

FS = Fast speed with slew

AE = Analog with ESD protection circuitry (up/down = pull up and pull down circuits included in the pad)

VHV = Very high voltage

⁶ VDDE (fast I/O) and VDDEH (slow I/O) power supply inputs are grouped into segments. Each segment of VDDEH pins can connect to a separate 3.3–5.0 V (+5%/-10%) power supply input. Each segment of VDDE pins can connect to a separate 1.8–3.3 V ($\pm 10\%$) power supply.

⁷ All pins are sampled after the internal POR is negated. The terminology used in this column is: O – output, I – input, Up – weak pull up enabled, Down – weak pulldown enabled, Low – output driven low, High – output driven high, ABS — Auto Baud Select (during Reset or until JCOMP assertion). A dash on the left side of the slash denotes that both the input and output buffers for the pin are off. A dash on the right side of the slash denotes that there is no weak pull up/down enabled on the pin. The signal name to the left or right of the slash indicates the pin is enabled.

⁸ The Function After Reset of a GPIO function is general purpose input. A dash on the left side of the slash denotes that both the input and output buffers for the pin are off. A dash on the right side of the slash denotes that there is no weak pull up/down enabled on the pin.

- ⁹ During and just after POR negates, internal pull resistors can be enabled, resulting in as much as 4 mA of current draw. The pull resistors are disabled when the system clock propagates through the device.
- ¹⁰ NMI function is selected using the SIU_IREER/SIU_IFEER registers and has priority over any other function on this pin.
- ¹¹ Nexus reset is different than system reset; MDO0-11 are enabled in RPM or FPM trace modes, while MDO12-15 are enabled in FPM trace mode only. MSEO and MCKO are also dependent on trace (RPM or FPM) being enabled.
- ¹² The Nexus pins don't have a "primary" function as they are not configured by the SIU. The pins are selected by asserting JCOMP and configuring the NPC. SIU values have no effect on the function of these pins once enabled.
- ¹³ MCKO is disabled from reset; it can be enabled from the tool (controlled by Nexus NPC_PCR register).
- ¹⁴ Do not connect pin directly to a power supply or ground.
- ¹⁵ While JCOMP is negated, the MDO0 pad is pulled up because of the default values in its SIU PCR. When JCOMP is asserted, the MDO0 pad is enabled as an output and goes low when the system clock is present.

Appendix B Revision History

[Table 39](#) describes the changes made to this document between revisions.

Table 39. Revision History

Revision	Date	Description
Rev 1	5 Aug 2011	Initial customer release
Rev 2	21 Dec 2011	<p>Added information about specs 1a through 1d in the PMC Electrical Specifications table.</p> <p>Updated the footnote reference (changed from ¹³ to ¹⁴) of spec 18 of the PMC Electrical Specifications table.</p> <p>Updated the Operating Current 5.0 V Supplies @ fsys = 180MHz VDDA Max value (changed from 30 to 50).</p> <p>Updated footnote ¹ of the VDD33 Pad Average DC Current table (changed IDDE to IDD33).</p> <p>Updated the pF value of 11 SRC/DSC Fast with Slew Rate (changed from 2.6 to 200) in the Pad AC Specifications (VDDEH = 5.0 V, VDDE = 3.3 V) table.</p> <p>Added a footnote for ANA0-ANA7 (⁹) functions in the “Signal Properties and Muxing Summary” table.</p> <p>Added a footnote for MDO0-MDO15 (¹⁴) and MSE00 functions in the “Signal Properties and Muxing Summary” table.</p> <p>Updated figure numbers 25, 27, 29, and 31: Added specs 1-4.</p> <p>Changed the title of the “PFCPR1 Settings” table to “BIUCR1/BIUCR3”.</p> <p>Added a new row “Load” under “Termination” in the “DSPI LVDS Pad Specification” table.</p> <p>Updated the “Max” and “Typical” values of “Delay, Z to Normal”, “Rise/Fall Time”, and “Data Frequency” in the “DSPI LVDS Pad Specification” table.</p> <p>Changed “V_{DDE}” to “V_{DDEH}” in footnote ¹⁰ of the “DC Electrical Specifications” table.</p> <p>Made the following changes in the “DSPI Timing” table:</p> <ul style="list-style-type: none"> • Update the minimum peripheral bus frequencies for “Data Setup Time for Inputs” and “Data Hold Time for Outputs”. • Updated the maximum peripheral bus frequencies for “Data Valid (after SCK edge)”. • Added “Master (LVDS)” information for “Data Valid (after SCK edge)” and “Data Hold Time for Outputs”. <p>Changed the minimum voltage value of the “I/O Supply Voltage (fast I/O pads)” from “1.62 V” to “3.0 V” in the “DC Electrical Specifications” table.</p> <p>Changed “V_{DDE}” values from “1.62 V to 1.98 V” to “3.0 V to 3.6 V” in footnote ¹ of the “Pad AC Specifications (V_{DDEH} = 5.0 V, V_{DDE} = 3.3 V)” table.</p> <p>Removed voltage ranges “1.62 V–1.98 V” and “2.25 V–2.75 V” from “Fast I/O Weak Pull Up/Down Current” in the “DC Electrical Specifications” table.</p>

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